TECHNICAL MANUAL FOR

DE-211/DE-291 DATA ELECTRONICS

APPROVED BY E.S. Kann

LIST OF EFFECTIVE PAGES

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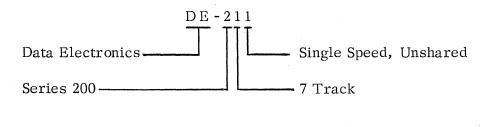
SECTION I GENERAL DESCRIPTION

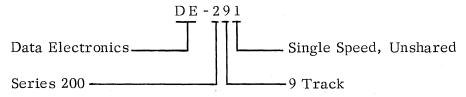
1-1. INTRODUCTION.

1-2. SCOPE.

This technical manual describes the installation, operation, theory of operation and maintenance of the DE-211 and the DE-291 Data Electronics.

1-3. MODEL DESIGNATIONS.





1-4. PURPOSE AND BASIC PRINCIPLES.

1-5. PURPOSE.

The Data Electronics card cage is wired, as shown on the Data Electronics Logic Diagram, to accommodate circuit board assemblies which provide the circuitry required to read, write, and check digital data. Seven-track tapes are bilaterally interchangeable with tapes prepared on IBM 729 tape transports. Nine-track tapes are bilaterally interchangeable with tapes prepared per ASCII specifications.

1-6. BASIC PRINCIPLES.

The card cage is wired to accommodate circuit boards which will read and write on either 7 or 9 tracks. Wiring is also included to accommodate circuit boards which will perform Vertical Parity Check, and Echo and Rate Checks.

Circuit board assemblies included in the card cage are determined by tape speed, bit packing density, number of tracks, error checking options, bidirectional read capability, and special features.

1-7. SPECIAL FEATURES.

The following special features (SF) are documented in Section VIII of this manual.

- SF1: Special Positive Input/Output Levels (Dual Density).
- SF2: Vertical Parity Generate (7 Track).
- SF3: Vertical Parity Generate (9 Track).
- SF4: Longitudinal Parity Check.
- SF5: Longitudinal Check Character Generate.

Addenda, which include special logic diagrams, are prepared to document special features not included in this manual. Table 1-1 is a partial list of addenda.

TABLE 1-1 DATA ELECTRONICS ADDENDA

ADDENDUM	DESCRIPTION	LOGIC
3115501	Special Negative Input/Output Levels (Dual Density with Run/Stop Logic)	3115445
3115502	Tri-Density (Run/Stop Logic)	3115446
3115503	Read Only (Dual Density with Run/Stop Logic)	3115795
3115758	Longitudinal Check Character Generate (Tri-Density)	3115757
3118390	Special Negative Input/Output Levels (Tri-Density with Run/Stop Logic)	3118323

SECTION II INSTALLATION

2-1. INTRODUCTION.

2-2. SCOPE.

This section provides information on unpacking, power requirements, installation and cabling. Input signal requirements and output signal characteristics are also described in this section.

2-3. UNPACKING.

The Data Electronics is installed with the Ampex Tape Transport in the Tape Memory System enclosure. When no enclosure is supplied, the Data Electronics is shipped in custom designed crating. No special unpacking instructions are required. All equipment should be inspected for shipping damage prior to the application of power.

2-4. POWER REQUIREMENTS.

Power for the Data Electronics is supplied by the Ampex Logic Power Supply, which is a separate assembly. The power supply provides three regulated voltage outputs and two unregulated voltage outputs. The power supply requires a maximum input power of 345 watts with all outputs at the full load shown on Table 2-1. If the Ampex Logic Power Supply is not used, provision must be made to supply the voltages listed in Table 2-1 at the required current and regulation.

TABLE 2-1 POWER SUPPLY OUTPUT

REGULATED VOLTAGE	CURRENT	REGULATION
+12V	+4.5 Amp	1%
-12V	-5.0 Amp	1%
- 6V	±1.5 Amp	2%
UNREGULATED VOLTAGE	CURRENT	REGULATION
+24V	+0.1 Amp	10%
-24V	-0.1 Amp	10%

	Ĺ	SELEC
	SG	STRO
	ЕО	EXCL
	EO EO EO EC OD OD	EXCL
	EO	EXCL
	EC	ERRO
	8	OUTP
	8	OUTP
ъ	B	INPUT
Figure 2-1 PCB Locations	B	INPUT
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			-
* Op	₹ READ AMPLIFIER (TRACK 1)	READ DESKEW (TRACK 1)	2
Options	READ AMPLIFIER (TRACKS 2 & 3)	READ DESKEW (TRACK 2)	ω
S	READ AMPLIFIER (TRACKS 4 & 5)	READ DESKEW (TRACK 3)	4
	READ AMPLIFIER (TRACKS 6 & 7)	READ DESKEW (TRACK 4)	5
	READ AMPLIFIER (TRACKS 8 & 9)	READ DESKEW (TRACK 5)	6
	SELECT LOGIC *	READ DESKEW (TRACK 6)	7
	STROBE GENERATOR	READ DESKEW (TRACK 7)	8
	© EXCLUSIVE OR ★	READ DESKEW (TRACK 8)	9
	EXCLUSIVE OR *	READ DESKEW (TRACK 9)	10
	EXCLUSIVE OR *		11
	ERROR CHECK *		12
	OUTPUT DRIVER		13
	8 OUTPUT DRIVER	₩RITE AMPLIFIER (TRACK 1)	14
	₩ INPUT BUFFER	₩RITE AMPLIFIER (TRACK 2)	15
	₩ INPUT BUFFER	WRITE AMPLIFIER (TRACK 3)	16
		WRITE AMPLIFIER (TRACK 4)	17
		WRITE AMPLIFIER (TRACK 5)	18
		▼ WRITE AMPLIFIER (TRACK 6)	19
		WRITE AMPLIFIER (TRACK 7)	20
		WRITE AMPLIFIER (TRACK 8)	21
		₩RITE AMPLIFIER (TRACK 9)	22
			23
		₩RITE POWER GATE	24

9-TRACK
DATA ELECTRONICS
(DE-291)

		· · · · · · · · · · · · · · · · · · ·	
		·	-
RA	READ AMPLIFIER (TRACK 1)	₹ READ DESKEW (TRACK 1)	2
RA	READ AMPLIFIER (TRACKS 2 & 3)	₹ READ DESKEW (TRACK 2)	ငှာ
RA	READ AMPLIFIER (TRACKS 4 & 5)	9	4
RA	READ AMPLIFIER (TRACKS 6 & 7)	Ŭ	Ċ
		공 READ DESKEW (TRACK 5)	6
SL	SELECT LOGIC *	READ DESKEW (TRACK 6)	7
SG	STROBE GENERATOR	READ DESKEW (TRACK 7)	œ
EO	EXCLUSIVE OR *		9
EO	EXCLUSIVE OR *		10
			Ξ
EC	ERROR CHECK *		12
OD	OUTPUT DRIVER		13
OD	OUTPUT DRIVER *	WRITE AMPLIFIER (TRACK 1)	14
ІВ	INPUT BUFFER	₩RITE AMPLIFIER (TRACK 2)	15
IB	INPUT BUFFER		16
	(WRITE AMPLIFIER (TRACK 4)	17
11		₩RITE AMPLIFIER (TRACK 5)	8
		₩ RITE AMPLIFIER (TRACK 6)	19
		₩RITE AMPLIFIER (TRACK 7)	20
			21
			22
			23
		₩RITE POWER GATE	24

7-TRACK
DATA ELECTRONICS
(DE-211)

2-5. INSTALLATION.

Typical Outline and Installation drawings are provided in the drawing sections of the Tape Transport technical manuals. Figure 2-1 shows typical printed circuit board (PCB) assembly locations for 7-track and for 9-track Data Electronics. Mnemonic designations, as shown on the Logic Diagram, are provided. Table 2-2 lists the coded designation which appears on the ejector tab of the PCB's and provides the part numbers according to basic tape speeds.

2-6. CABLING.

Cabling diagrams for TM-7211, TM-9211, and TM-11211 Tape Memory Systems are provided in the drawing sections of the tape transport technical manuals. The TM-11211 diagram is also used for TM-12211 systems. Inputs to the system and outputs from the system are connected to the Data Electronics via the connectors on the Input/Output Panel as shown in Tables 2-3 and 2-4, respectively. These inputs and outputs supersede those listed in the Tape Transport manual. Connections from the read heads are as shown in Table 2-5 and connections to the write heads in Table 2-6. Table 2-7 lists connections to the Tape Transport. Table 2-8 lists connections to the Logic Power Supply. Tables 2-3 through 2-8 are located at the end of this section.

2-7. INPUT SIGNAL REQUIREMENTS.

2-8. INPUT SIGNAL VOLTAGE LEVELS.

The following signal voltage levels apply to all input signals (the input impedance is 2300 ± 115 ohms returned to -3.8 volts).

TRUE Level: -12 (+3, -13) volts

FALSE Level: 0.00 ± 1.25 volts

NOTE

When non-standard input levels are provided, special Input Buffer PCBs and wiring changes are required.

2-9. INPUT SIGNAL TIMING.

In the following description of input signal timing, transition times are measured from the 10-percent point to the 90-percent point. Signal duration is measured from the 90-percent point of the leading-edge transition to the 10-percent point of the trailing-edge transition.

TABLE 2-2 PCB PART NUMBERS

CODE	DESCRIPTION	PART NO.
ECC*	Error Check 36/45 ips 75 ips 112.5/120/150 ips	3109872-10 3110558-10 3110031-10
EOA**	Exclusive OR	3107274-10
IBA	Input Buffer	3107258-10
ODA	Output Driver	3107259-10
RAB	Read Amplifier 36/45 ips 75 ips 112.5/120/150 ips	3107266-10 3109991-10 3110273-10 or 3118138-01
RDB***	Read Deskew (Read Fwd) 36/45 ips 75 ips 112.5/120/150 ips	3107269-10 3109475-10 3110004-10
RDC***	Read Deskew (Bidirectional) 36/45 ips 75 ips 112.5/120/150 ips	3109932-10 3109935-10 3109936-10
SGA	Strobe Generator 36/45 ips 75 ips 112.5/120 ips 150 ips	3107057-10 3109994-10 3110003-10 3118218-01
SLB***	Select Logic-B	3111157-10
WAB	Write Amplifier 36/45 ips 75 ips 112.5/120/150 ips	3112363-10 3109572-10 3110002-10
WPD	Write Power Gate	3107268-10

^{*}The Error Check (ECC) PCB is supplied for the Echo and Rate Check option.

^{**}Two Exclusive OR (EOA) PCBs are supplied for the Vertical Parity Check option.

^{***}Read Deskew (RDB) PCBs are replaced by Bidirectional Read Deskew (RDC) PCBs for bidirectional reading. Select Logic (SLB) is supplied for the bidirectional read option.

2-10. Write Data. (See Figure 2-2.) A minimum interval of 1.5 μ sec is required between the 90-percent point of the Write Data leading-edge transition and the 10-percent point of the next Write Strobe leading-edge transition.

A minimum interval of 1.5 μsec is required between the 90-percent point of the Write Strobe trailing-edge transition and the 10-percent of the next Write Data leading-edge transition.

To write a series of ONE's, the Write Data input may be held at the TRUE level for the entire series.

2-11. Write Strobe. (See Figure 2-2.) The Write Strobe leading (and trailing) edge transition time shall not exceed 1.5 µsec.

The Write Strobe TRUE state must coincide with the Write Data TRUE (or FALSE) state for at least 2 $\mu sec.$

2-12. Write Reset. The Write Reset leading (and trailing) edge transition time shall not exceed $1.5~\mu sec.$

The Write Reset signal must remain at the TRUE level for at least 1.5 $\mu sec.$

The Write Reset signal is used to write the longitudinal check character (LCC) at the end of each block of data. The LCC resets the NRZ1 write register.

A minimum interval of $10^6~\mu sec/data$ transfer frequency is required between the 90-percent point of the Write Reset trailing-edge transition and the 10-percent point of the next Write Strobe leading-edge transition.

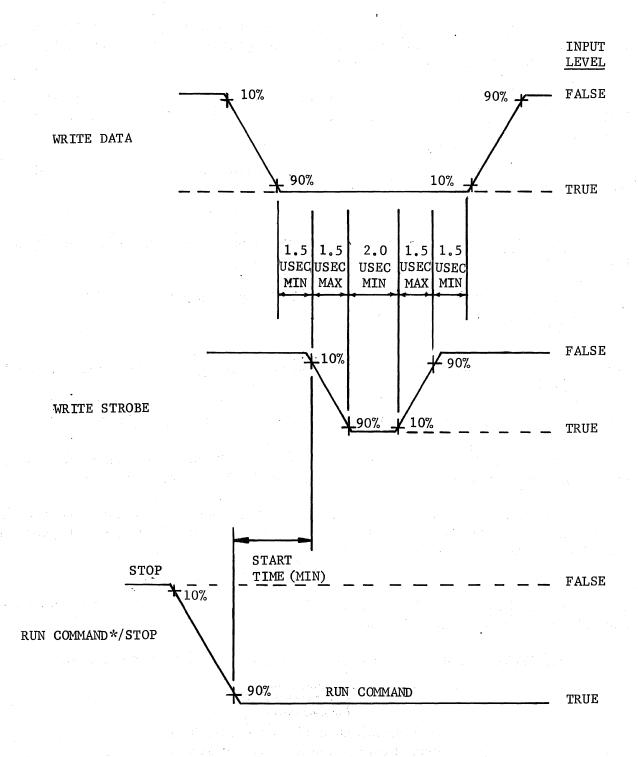
2-13. Write Permit. (See Figure 2-3.) The Write Permit leading (and trailing) edge transition time shall not exceed $5 \mu sec$.

The Write Permit level shall not be changed while the tape is in motion.



Write Permit should be at the FALSE level during Reverse and Rewind operations.

2-14. Read Permit. The Read Permit leading (and trailing) edge transition time shall not exceed $5 \mu \text{sec.}$



^{*}Run Command is Run in Fwd/Rev-Run/Stop logic systems and Forward or Reverse in Fwd/Stop-Rev/Stop logic systems.

Figure 2-2
Timing Requirements for Write Data, Write Strobe, and Run/Stop Inputs

2-15. $\underline{\text{HI/LO Density}}$. The HI/LO Density leading (and trailing) edge transition time shall be 5 µsec maximum. High density is selected by a TRUE level. The high/low density line selects the appropriate timing read circuits.

NOTE

This signal is normally supplied from the tape transport Operator Control Panel.

- 2-16. Odd/Even Parity. The Odd/Even Parity leading (and trailing) edge transition time shall not exceed 5 μ sec. Odd parity is selected by a TRUE level. The Odd/Even Parity line is used to select odd or even Read Vertical Parity check.
- 2-17. Forward/Reverse. The Forward/Reverse leading (and trailing) edge transition time shall not exceed $5\,\mu sec.$ (See Figure 2-3A.) The Forward mode is active when this line is at the TRUE level. Forward/Reverse transitions shall not occur while the tape is in motion.

A minimum interval of 5 μsec is required between a Forward/Reverse transition and the Run/Stop transition.

CAUTION

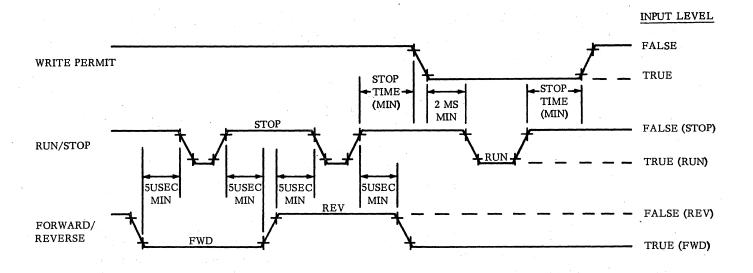
Write Permit should be at the FALSE level when tape is moving in the Reverse direction.

2-18. Run/Stop. The Run/Stop leading (and trailing) edge transition time shall not exceed $5 \mu sec.$ (See Figure 2-3B.) A TRUE level on this line sets the transport in the Run mode.

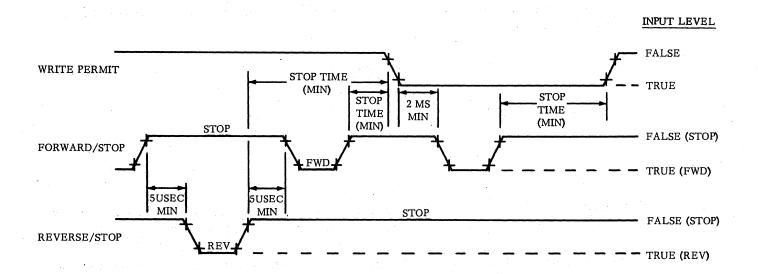
A minimum interval of 5 μsec is required between the Forward/Reverse transition and the Run command.

A minimum interval of 2.0 ms is required between a Write Permit transition and a Run command.

A minimum interval equal to the stop time (to allow tape motion to stop) is required between the 90-percent point of a Stop command transition and a Write Permit transition.



A. Forward/Reverse-Run/Stop Logic



B. Forward/Stop-Reverse/Stop Logic

Figure 2-3
Timing Requirements for Write Permit, Forward/Reverse,
Run/Stop, Forward/Stop, and Reverse/Stop Inputs

2-19. Forward/Stop (Option). The Forward/Stop leading (and trailing) edge transition time shall not exceed $5 \mu sec$. (See Figure 2-3B.) The Forward mode is active when this line is at the TRUE level.

A minimum interval of 2.0 ms is required between a Write Permit transition and a Forward command.

A minimum interval equal to the stop time (to allow tape motion to stop) is required between the 90-percent point of a Stop command transition and a Write Permit transition.

2-20. Reverse/Stop (Option). The Reverse/Stop leading (and trailing) edge transition time shall not exceed 5 μ sec. (See Figure 2-3B.) The Reverse mode is active when this line is at the TRUE level. A minimum interval equal to the stop time (to allow tape motion to stop) is required between the 90-percent point of a stop command transition and a Write Permit transition.

CAUTION

Write Permit should be at the FALSE level when tape is moving in the Reverse direction.

- 2-21. Rewind. The Rewind leading (and trailing) edge transition time shall not exceed 5 μ sec. The Rewind signal shall remain at the TRUE level for at least 5 μ sec. Rewind operation is initiated by the negative-going transition.
- 2-22. Rewind and Lockout. The Rewind and Lockout leading (and trailing) edge transition time shall not exceed $5\,\mu sec$. The Rewind and Lockout signal shall remain at the TRUE level for at least $5\,\mu sec$. Rewind and lockout operation is initiated by the negative-going transition.
- 2-23. OUTPUT SIGNAL CHARACTERISTICS.
- 2-24. OUTPUT SIGNAL VOLTAGE AND CURRENT LEVELS.

TRUE Level: -11.5 (+2.5, -0.5) volts; 5 ma maximum from the load

FALSE Level: 0.00 ± 1.25 volts; 5 ma maximum to the load

NOTE

When non-standard output levels are provided, special Output Driver PCBs and wiring changes are required.

2-25. OUTPUT SIGNAL TIMING.

In the following description of output signal timing, transition times are measured from the 10-percent point to the 90-percent point. Signal duration is measured from the 90-percent point on the leading edge transition to the 10-percent point on the trailing edge transition. Maximum leading edge displacement between Read Data, Read Clock, and Vertical Parity Error outputs is $0.3\,\mu sec$ maximum.

The trailing edge transition times may be affected by the external load circuits.

- 2-26. Read Data. The Read Data leading edge transition time is 0.30 μ sec maximum. The trailing edge transition time is 0.30 μ sec. Signal duration is from 0.9 μ sec minimum to 1.5 μ sec maximum.
- 2-27. Read Clock. The Read Clock leading edge transition time is 0.30 μ sec maximum. The trailing edge transition time is 0.30 μ sec. Signal duration is from 0.9 μ sec minimum to 1.5 μ sec maximum.
- 2-28. Vertical Parity Error (Option). The Vertical Parity Error leading edge transition time is $0.30\,\mu sec$ maximum. The trailing edge transition time is $0.30\,\mu sec$ maximum. Signal duration is from $0.9\,\mu sec$ minimum to $1.5\,\mu sec$ maximum.
- 2-29. Write Check Error (Option). The Write Check Error leading edge transition time is $0.30\,\mu sec$ maximum. The trailing edge transition time is $0.30\,\mu sec$ maximum. Signal duration is from $0.5\,\mu sec$ minimum to $5.3\,\mu sec$ maximum.
- 2-30. Write Enable Status. Three lines are provided to indicate the state of the write permit relay on the Data Electronics Write Power Gate PCBA. When a file-protect condition exists, the write permit relay is deenergized and the Write Enable Status (C) line is connected to the Write Enable Status (NC) line. When a write enable condition exists, the write permit relay is energized and the Write Enable Status (C) line is connected to the Write Enable Status (NO) line.
- 2-31. <u>LP Error (Special Feature)</u>. The LP Error leading edge transition time is $0.30\,\mu sec$ maximum. The trailing edge transition time is $0.3\,\mu sec$ maximum. A TRUE level pulse on the LP Error line indicates that a longitudinal parity error was detected in the last data block read.

2-32. TAPE TRANSPORT STATUS OUTPUTS.

Tape transport status output levels are -11.5 (\pm 2.5, -0.5) volts (5 ma maximum from the load) and 0.00 \pm 1.25 volts (5 ma maximum to the load) for TRUE and FALSE, respectively, unless otherwise indicated. The status outputs are active in the remote mode only.

- 2-33. <u>Beginning-of-Tape (BOT)</u>. A TRUE level on the BOT line indicates that the BOT tab is being sensed by the photosense assembly.
- 2-34. End-of-Tape (EOT). A TRUE level on the EOT line indicates that the EOT tab is being sensed by the photosense assembly.
- 2-35. <u>High/Low Density Status</u>. The High/Low Density Status line acknowledges the density select level. A TRUE level indicates that high density has been selected. A FALSE level indicates that low density has been selected.
- 2-36. Ready. A TRUE level on the Ready line indicates that all tape transport interlocks are closed and the transport is ready for remote operation.
- 2-37. Rewinding. A TRUE level on the Rewinding line indicates that the rewind operation is being performed.
- 2-38. <u>Unit Select</u>. A TRUE level on the Unit Select line indicates that the tape transport has been selected by a TRUE level at the Select input (when a single tape transport is used, the Select line is returned to -12 volts in the Data Electronics, thus providing a TRUE Select level at all times).
- 2-39. Select and Remote Indicator. This line is driven by a line driver returned to ground. The line driver must be terminated with an indicator lamp returned to -12 volts (this is normally done by an indicator lamp in the Operator Control Panel of the Tape Transport). When so terminated, the line driver output is 0.0 ± 1.5 volts when the Unit Select status line is at the TRUE level; the line driver output is 125 ohms returned to ground when the Unit Select status line is at the FALSE level.

TABLE 2-3 SYSTEM INPUT CONNECTIONS (TYPICAL)

INPUT/OUTPUT PANEL CONNECTOR J4 PIN NO.	INPUT SIGNAL	DATA ELECTRONICS CONNECTOR J5 PIN NO.
e 1 f Z d	Fwd/Rev (or Rev/Stop) Odd/Even Parity Rewind Command Rewind and Lockout Read Permit	26 24 28 27 10
Y	Run/Stop (or Fwd/Stop)	25
c	Write Permit	21
X	Write Reset	9
W	Write Strobe	8
C	Write Track 1	1
D E F M N	Write Track 2 Write Track 3 Write Track 4 Write Track 5 Write Track 6	2 3 4 5 6
P	Write Track 7	7
R	Write Track 8	22
S	Write Track 9	23
G	Spare	31
j	Spare	39
k	Spare	40
A	Ground	11
B	Ground	12
H	Ground	13
J	Ground	14
K	Ground	15
L	Ground	16
T	Ground	17
U	Ground	18
V	Ground	19
a	Ground	35
b	Ground	36
g	Ground	29
h	Ground	30
m	Shield Ground	20

TABLE 2-4 SYSTEM OUTPUT CONNECTIONS (TYPICAL)

INPUT/OUTPUT PANEL CONNECTOR J5 PIN NO.	OUTPUT SIGNAL	DATA ELECTRONICS CONNECTOR J4 PIN NO.
W	Beginning-of-Tape	21
X	End-of-Tape	22
e	High/Low Density Status	25
R	Read Clock	8
C	Read Track 1	1
D	Read Track 2	2
E	Read Track 3	3
F	Read Track 4	4
M	Read Track 5	5
N	Read Track 6	6
P	Read Track 7	7
G	Read Track 8	9
d	Read Track 9	10
Z	Ready	24
Y	Rewinding	23
k 1 h c V	Unit Select Select and Remote Indicator Vertical Parity Error* Write Check Error* Write Enable Status (C)	32 33 27 29 38
b a j f A	Write Enable Status (NC) Write Enable Status (NO) Spare (or LP Error**) Spare Ground	40 39 28 26 11
B	Ground	12
H	Ground	13
J	Ground	14
K	Ground	15
L	Ground	16
S	Ground	17
T	Ground	18
U	Ground	19
g	Ground	31
m	Shield Ground	20

^{*}Spare when option is not supplied.
**With Longitudinal Parity Check special feature.

TABLE 2-5
DATA ELECTRONICS TO READ HEAD INTERCONNECTIONS

DATA ELECTRONICS J1 PIN NO.	READ HEAD J1 PIN NO.	SIGNAL DESCRIPTION
2	A	Read Track 1
12	D	Read Track 1
23	H	Read Track 2
33	L	Read Track 2
4	P	Read Track 3
14	T	Read Track 3
25	W	Read Track 4
35	Z	Read Track 4
6	a	Read Track 5
16	X	Read Track 5
27	U	Read Track 6
37	R	Read Track 6
8	M	Read Track 7
18	J	Read Track 7
29	E B	Read Track 8 Read Track 8
21	C	Read Track 9
31	F	Read Track 9
22	c *	Head Ground Shield Ground

^{*}Shield ground terminated at the read head with lug E1, which is attached to chassis ground near the read head.

TABLE 2-6
DATA ELECTRONICS TO WRITE HEAD INTERCONNECTIONS

DATA ELECTRONICS	WRITE HEAD	SIGNAL
J7 PIN NO.	J2 PIN NO.	DESCRIPTION
2	A	Write Track 1
12	D	Write Track 1
22		Shield Ground 1
23	H	Write Track 2
33	L	Write Track 2
13		Shield Ground 2
4	P	Write Track 3
14	T	Write Track 3
24		Shield Ground 3
25	W	Write Track 4
35	Z	Write Track 4
15		Shield Ground 4
6	a	Write Track 5
16	X	Write Track 5
26		Shield Ground 5
27	U	Write Track 6
37	R	Write Track 6
17		Shield Ground 6
8	M	Write Track 7
18	J	Write Track 7
28		Shield Ground 7
29	E	Write Track 8
39	B	Write Track 8
19		Shield Ground 8
21	C	Write Track 9
31	F	Write Track 9
11		Shield Ground 9
20	b	Erase Head Power
30	d	Erase Head Return
40		Shield Ground Erase Head
10	S	Write Power (Head CT)
9	c*	Head Ground
	**	Common Shield

^{*}Head ground also terminated at the write head with lug E1, which is attached to chassis ground near the write head.

^{**}Common shield terminated at the write head with lug E2, which is attached to terminal E2 near the write head.

TABLE 2-7
DATA ELECTRONICS TO TAPE TRANSPORT INTERCONNECTIONS

DATA ELECTRONICS J6 PIN NO.	SIGNAL DESCRIPTION	TM-7/TM-9 J10 PIN NO.	TM-11/TM-12 CONTROL ELECTRONICS J4 PIN NO.
6	Beginning-of-Tape (-) End-of-Tape (-) Forward/Reverse (-/+)* High/Low Density (-/+) High/Low Density Status (-/+)	6	11
8		8	12
1		1	14
7		7	7
19		19	3
10	Ready (-) Rewind and Lockout (-) Rewind Command (-) Rewinding (-) Run/Stop (-/+)**	10	2
4		4	9
3		3	8
9		9	1
2		2	15
5	Select (-) Select and Remote Indicator (+) Unit Select (-) Write Enable Switch/Relay (C) Write Enable Switch/Relay (NC)	5	4
18		18	6
14		14	5
15		15	18
16		16	17
17***	Write Enable Switch/Relay (NO) Ground Ground Ground Shield Ground	17	19
11		11	13
12		12	16
13		13	10
20		20	20

^{*}Reverse/Stop (-/+) when Fwd/Stop-Rev/Stop logic is supplied.

^{**}Forward/Stop(-/+) when Fwd/Stop-Rev/Stop logic is supplied

^{***}Pin 17 of J6 is returned to ground in the Data Electronics

TABLE 2-8
DATA ELECTRONICS TO POWER SUPPLY INTERCONNECTIONS

DATA ELECTRONICS TS1 TERMINAL NO.	LOGIC POWER SUPPLY TS1 TERMINAL NO.	VOLTAGE
1	6	+12 VDC (Regulated)
2	8	Ground
3	. 10	-6 VDC (Regulated)
4	12	Ground
5	2	-12 VDC (Regulated)
6	4	Ground
7	13	+24 VDC (Unregulated)
8	14	Ground
9	15	-24 VDC (Unregulated)
10	16	Ground

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SECTION III OPERATION

3-1. INTRODUCTION.

This section briefly describes the operation of the Data Electronics.

3-2. OPERATING MODES.

The Data Electronics is capable of operating in three different modes: write check, write only, and read only. The operating mode is determined by the level of the Read Permit and Write Permit input signals.

3-3. WRITE CHECK MODE.

In the Write Check Mode, information is read immediately after it is written. To operate in the Write Check Mode, Write Permit and Read Permit inputs must be TRUE.

3-4. WRITE ONLY MODE.

In the Write Only Mode, information is written but reading does not occur. To operate in the Write Only Mode, Write Permit input must be TRUE and Read Permit input must be FALSE.

3-5. READ ONLY MODE.

In the Read Only Mode, information is read, but writing does not occur. To operate in the Read Only Mode, Read Permit input must be TRUE and Write Permit input must be FALSE.

3-6. WRITE SIGNAL CONDITIONING.

Writing of data is accomplished on seven (or nine) tracks. In the following description of write signal conditioning, the operation of only one track is discussed. Each input signal is conditioned by an input buffer.

3-7. WRITE DATA. (See Figure 3-1.)

Data is written when the Write Data input is strobed through an AND gate by the Write Strobe and fed, via an OR gate, to the Write Deskew single-shot delay. Write Head gap-to-gap static skew is compensated for by the single-shot delay. The deskewed Write Data signal is fed to the write register. Write Permit is comprised of the ANDed Write Permit and Run inputs. The write register controls the direction of current flow in the write head.

3-8. WRITE POWER.

When the Write Permit signal is TRUE and a Write Enable Ring is in place, power is supplied to the Write and Erase Heads through the Write Power Gate.

3-9. WRITE RESET.

The Write Reset signal is ANDed with the Set status output of the NRZ Write Register and is then fed to the NRZ Write Register flip-flops via the OR gate and the single-shot delay. The Write Reset line is used to write the Longitudinal Check Character (LCC) at the end of each block of data. The LCC is used to reset the NRZ register, resulting in an even number of flux reversals (ONEs) in each track of the block.

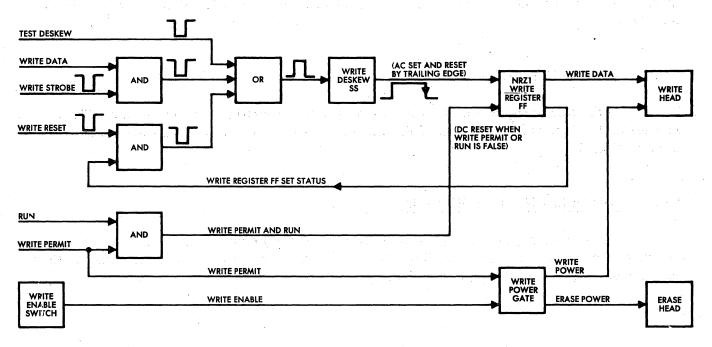


Figure 3-1 Write Signal Conditioning, Block Diagram

3-10. READ SIGNAL CONDITIONING.

Reading of data is accomplished on seven (or nine) tracks. In the following description of read signal conditioning, only one track is discussed.

3-11. READ DATA. (See Figure 3-2.)

The signals from the Read Head are amplified by the Read Amplifier and fed to the peak detector circuit on the Read Deskew PCBA. The peak detector generates positive pulses, corresponding in time to the peaks of the analog Read Head signals. The peak detector clipping level is established as a function of Write Permit.

The Read Data from the peak detector is fed to the Read Deskew single-shot delay. Read head gap-to-gap static skew is compensated for by the single-shot delay. The deskewed Read Data signal is fed to the Read Register. Bi-directional Read Deskew circuits are available as an option.

When a Read Permit signal is present, the Read register assembles the deskewed Read Data signals within each character frame and drives the data output drivers.

3-12. STROBE GENERATION.

The Strobe Generator provides the Strobe signal for the Read Data and Read Parity Error AND gates, and the Read Clock signal to the Read Clock output driver.

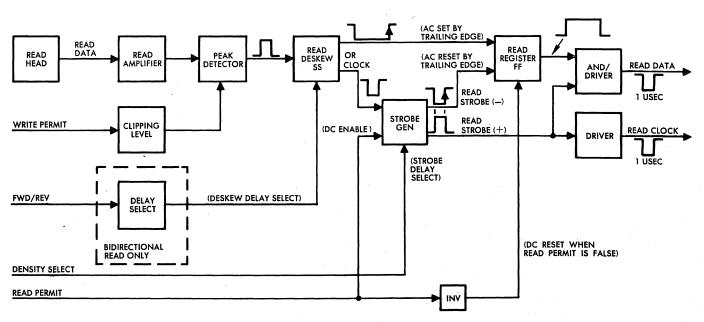


Figure 3-2
Read Signal Conditioning, Block Diagram

3-13. ERROR CHECKING.

3-14. VERTICAL PARITY CHECK.

The vertical parity check circuits generate an Error signal when the parity of the read register does not correspond to the status of the Odd/Even Parity input. In the Read Only Mode, the Error output is provided at the Vertical Parity Error output. In the Write Check Mode, the error indication is provided at the Vertical Parity Error output and at the Write Check Error output

3-15. RATE CHECK.

The rate check circuit generates a Write Check Error output when the time interval between successive characters is below a design threshold.

3-16. ECHO CHECK.

In ORed Clock systems, at least one Write Amplifier flip-flop must change state after each Write Strobe. The echo check circuits generate a Write Check Error output when none of the Write Amplifiers change state after receipt of a Write Strobe.

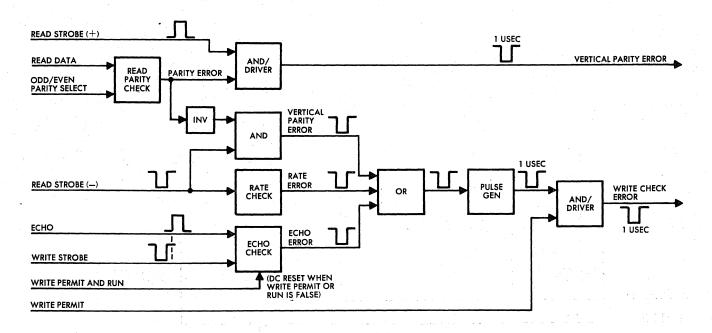


Figure 3-3
Error Check Circuits, Block Diagram

SECTION IV THEORY OF OPERATION

4-1. INTRODUCTION.

This section includes the theory of operation of the data electronics and an introduction to the graphic symbols used in the logic diagrams. The theory of operation description comprises input/output interface, write logical sequence, read logical sequence, and error check functions.

4-2. LOGIC DIAGRAMS.

The data electronics logic diagrams are located at the end of Section VII. Graphic symbols used in the logic diagrams comply with Military Standard MIL-STD-806B, except that squares and rectangles are used interchangeably for special circuits.

- 4-3. Logic Element Identification. Identification of a logic element is accomplished by the graphic symbol and the notations within and adjacent to the symbol. (See Figure 4-1.) The mnemonic (top) designation within the symbol identifies the printed circuit board (PCB) type. The alphanumeric (bottom) designation within the symbol identifies the physical location of the PCB in the data electronics card cage. Dashed lines indicate internal connections on the PCB. Numbers adjacent to the logic element indicate the PCB pin number for the connecting signal line.
- 4-4. <u>State Indicators</u>. A state indicator (small circle) at the input to any logic element indicates that the relatively-low level of the input signal activates that function of the logic element. A state indicator at the output of any logic element indicates that the output level of the activated function is relatively low.
- 4-5. <u>Signal Callouts</u>. Signal callouts in the data electronics logic diagrams show the TRUE (active) state of the signal. Write Permit (-) indicates that Write Permit is TRUE when the Write Permit (-) signal is relatively low. Read Strobe (+) indicates

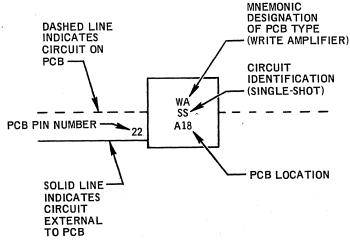


Figure 4-1
Typical Logic Symbol

that Read Strobe is TRUE when the Read Strobe (+) signal is relatively high. Run/Stop (-/+) indicates Run (-) is TRUE when the Run/Stop (-/+) signal is relatively low and Stop (+) is TRUE when the signal is relatively high.

4-6. <u>Signal Flow Direction</u>. Direction of signal flow is indicated by logic symbol orientation. Inputs to a circuit are from the left and outputs are from the right.

Signal flow other than from left to right is indicated by directional arrowheads on the signal lines.

4-7. INPUT/OUTPUT INTERFACE.

4-8. GENERAL.

Most of the signals used in the data electronics logic circuits are binary. Where binary levels are used, one of the two levels is a 0.0 ± 0.5 volt level. The second level is generally a -6 volt level. In some circuits, -12 volt, +6 volt, or +12 volt levels are used. When the binary levels are 0 and -6 or 0 and -12; the 0 volt level is relatively high and is therefore termed positive (+), the -6 volt and -12 volt levels are relatively low and are therefore termed negative (-). When the binary levels are 0 and +6 or 0 and +12; the 0 volt level is relatively low and is therefore termed negative (-), the +6 volt and +12 volt levels are relatively high and are therefore termed positive (+).

Input buffers are used in the input interface to condition the system input signals to the logic levels required by the data electronics circuits. Output drivers are used in the output interface to condition the data electronics output signals to the levels required for the system output signals.

4-9. INPUT BUFFERS (TYPICAL).

The system input line to each input buffer is returned to ground through a line terminating resistor. Each system input signal level is compared with a fixed reference voltage in transistor gate circuits on the input buffer PCB. When the level of an input signal exceeds the gate threshold level established by the reference voltage, the output of the input buffer circuit is switched from one binary logic level to the other. When the system input signal level falls below the gate threshold level, the output of the input buffer is switched back to the other binary logic level. The input buffers provide high-noise-immunity inputs for the system.

The conditioned outputs from the input buffers are applied to the data electronics logic circuits.

4-10. OUTPUT DRIVERS (TYPICAL).

The output drivers for the data electronics are located on the output driver PCB assemblies. NAND gate/drivers are used in each output driver circuit. The NAND gates provide for read strobe control of the system read data outputs and for inhibit of other system outputs when required. The NAND gates are enabled by relatively-high level (or open circuit) inputs.

4-11. WRITE LOGIC SEQUENCE.

4-12. WRITE DATA.

A TRUE (low level) Write Data signal at pin 12 of the write amplifier data input AND gate enables the AND gate. A Write Strobe pulse coincidental with the TRUE Write Data signal produces a negative-going pulse at the output of the AND gate. The negative-going pulse is applied through a NOR gate to the input of the Write Deskew single-shot delay. The positive-going pulse from the NOR gate triggers the single-shot delay, which produces a positive-going pulse. The width of the single-shot delay pulse is adjustable and is set to compensate for the gap-to-gap misalignment (static skew) of the write heads.

The negative-going trailing edge of the single-shot delay pulse triggers the Write Register flip-flop and the flip-flop changes state. When the flip-flop changes state, the direction of current flow through the write head is reversed, which causes the polarity of the head magnetic flux to reverse. The flux polarity change is impressed on the tape and is interpreted as a logical ONE during the read function.

4-13. WRITE RESET.

The Write Reset signal is used to reset the Write Register flip-flops and to generate the LPC character. The Write Register flip-flops are in the reset state at the start of each block of write data. If an odd number of data bits are written on any one track, that Write Register flip-flop is in the set state after the last data bit of the block is written. A low level status signal from the set flip-flop enables the Write Amplifier reset AND gate. The Write Reset pulse produces a negative-going pulse at the output of the reset AND gate. The negative-going pulse is applied through the NOR gate to the input of the Write Deskew single-shot delay and causes a ONE to be written as previously described for the Write Data input. The Write Register flip-flop is then in the reset state.

The reset of the flip-flops generates the LCC which provides an even number of data bits in each track of a data block.

4-14. WRITE REGISTER DC RESET.

The Write Permit signal input is inverted and NANDed with the inverted Run/Stop signal input (or with the inverted Fwd/Stop signal input in Fwd/Stop-Rev/Stop logic systems). The NAND gate is located on the strobe generator PCB. When either the Write Permit signal or the Run/Stop (or Fwd/Stop) signal is at the FALSE (high) level, the output of the NAND gate is at the low level. The low level output from the NAND gate DC resets the Write Register flip-flops and holds the flip-flops in the reset state.

4-15. TEST DESKEW.

A negative-going Test Deskew pulse train applied at test point TP1 of the Data Electronics is applied through the Write Amplifier NOR gates to the inputs of the Write Deskew single-shot delays. The pulses cause all ONEs to be written as previously described for the Write Data input. The Test Deskew input is used during off-line Write Deskew adjustment procedures. The Write Reset and the Write Strobe inputs must be FALSE when the Test Deskew input is used.

4-16. WRITE HEAD POWER.

Write Head Power is furnished by the Write Power Gate. When the Write Permit input is at the TRUE level and a write enable ring is in place in the file reel, +10 volt power is supplied to the write heads from the write power gate PCB through pins 28, 29, and 30. The write power relay on the write power gate PCB is energized when the write enable ring is sensed by the write enable switch assembly on the tape transport.

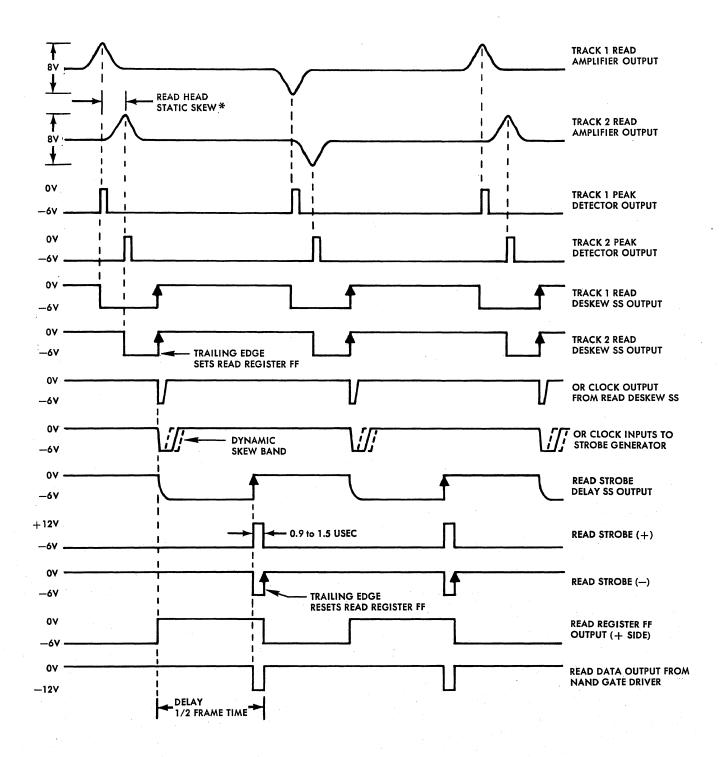
4-17. READ LOGICAL SEQUENCE.

4-18. READ PERMIT.

Read Permit TRUE enables the read strobe generator circuits. Read Permit FALSE DC resets the read register flip-flops and holds the flip-flops in the reset state.

4-19. READ DATA. (See Figure 4-2.)

Flux transitions (written ONEs) on the tape are sensed by the read heads as bipolar analog Read Data signals. The Read Data signals from each read head are amplified in a three-stage differential voltage amplifier on the associated read amplifier PCB assembly and then applied to a differential voltage amplifier on the associated read deskew PCB assembly.



^{*}The read amplifier data outputs are caused by flux reversals on the tape which are sensed by the read heads. Flux reversals on the tracks are written coincidentally; the time displacement shown (read head static skew) is caused by gap-to-gap misalignment of the read heads.

Figure 4-2 Read Deskew Timing

The differential output from the amplifier on the read deskew PCB assembly is clipped in a clipping stage at the input of the peak detector circuit. The clipping level is established by the clipping bias generated on the strobe generator PCB assembly and is selected by the Write Permit signal. The clipping bias level is higher when Write Permit is TRUE.

The clipped analog Read Data signal is applied to the peak detector circuit which produces a positive-going pulse at the positive or negative peaks of the signal. The leading edge of the peak detector output pulse is coincident with the detected peak. The positive-going pulse triggers the Read Deskew single-shot delay, which produces a negative-going pulse. The width of the single-shot delay pulse is adjustable and is preset to compensate for the gap-to-gap misalignment (static skew) of the read heads. Two pulse widths are set for bidirectional read systems; the forward deskew pulse width is selected when the Forward/Reverse (or Forward/Stop) input is TRUE, the reverse deskew pulse width is selected when the Forward/Reverse (or Forward/Stop) input is FALSE.

The positive-going trailing edge of the single-shot delay pulse sets the Read Register flip-flop and the Read Data output at pin 32 of the read deskew PCB goes to the TRUE (high) level. The Read Data output is applied to one input of a NAND gate driver circuit and enables the NAND gate. A Read Strobe (+) pulse coincidental with the TRUE Read Data signal produces a negative-going pulse at the output of the NAND gate driver. The negative-going pulse is a TRUE Read Data output representing a ONE sensed from the tape.

The Read Register flip-flop is reset by the positive-going trailing edge of the Read Strobe (-) pulse.

4-20. READ STROBE.

The Read Strobe (+) and Read Strobe (-) pulses are generated on the strobe generator PCB assembly. The positive-going trailing edge of each Read Deskew single-shot delay pulse is coupled through an associated inverter driver stage to produce a negative-going OR Clock pulse. The OR Clock pulses are applied to one common input of an AND gate on the strobe generator PCB. The other input to the AND gate is the Read Permit signal. When Read Permit is at the TRUE (low) level, the OR Clock pulses are passed through the AND gate. The first OR Clock pulse through the AND gate triggers the Read Strobe single-shot delay, which produces a negative-going pulse. The width of the single-shot delay pulse is adjustable and is preset to approximately one-half the character frame time, less the read strobe pulse time. Two single-shot delay pulse widths are preset: one for the high density packing rate, the other for the low density packing rate. Selection of the pulse width is accomplished by switching circuits on the write power gate PCB. When the HI/LO Density line is at the low level, the High Density pulse width is selected. When the HI/LO Density line is at the high level, the Low Density pulse width is selected.

The positive-going trailing edge of the Read Strobe single-shot delay pulse is coupled to a pulse generator circuit which then generates the positive-going Read Strobe (+)

pulse. The pulse width of the Read Strobe (+) pulse is approximately one microsecond. The Read Strobe (+) pulse is inverted through an inverter stage to produce the Read Strobe (-) pulse.

4-21. ERROR CHECK OPTIONS.

Error check options consist of Vertical Parity Check, Rate Check, and Echo Check. (See The Data Electronics Logic Diagrams in Section VII.)

4-22. VERTICAL PARITY CHECK.

Vertical Parity is checked during both Read Only and Write Check modes of operation by a continuous frame-by-frame check of the contents of the read register. A parity-select level from the customer selects either odd or even parity check. Odd parity requires an odd number of logical ONEs be recorded in every character frame. Even parity requires an even number of logical ONEs in every character frame. A Vertical Parity Error exists when an extra (or missing) logical ONE is detected.

Numerical values in parenthesis in the following circuit description refer to 9-track systems. The Odd/Even Parity Select line and the complementary outputs of the Read Register flip-flops are applied to the inputs of the parity checking circuit on the Exclusive OR PCB assembly. Eight Exclusive OR gates are used for 7-track systems, nine for 9-track systems. Each gate compares two inputs and produces a high level output when the logic levels of the inputs are dissimilar. Seven (or nine) Read Data (-) lines from the Read Register flip-flops and the Odd/Even Parity Select line are applied to four (or five) of the Exclusive OR gates. The outputs of the four gates are applied in pairs to the following two Exclusive OR gates, the outputs of which are compared by a single gate. The output of the single gate is compared in a final Exclusive OR gate with a fixed low level input (in 9-track systems, the output of the fifth input Exclusive OR gate is compared with the output of the single gate in the final Exclusive OR gate). The output of the final gate is ANDed with the Read Strobe (+) pulse in a NAND gate driver. If a vertical parity error is sensed, a negative-going Vertical Parity Error pulse is produced at the output of the NAND gate driver and is transmitted to the customer via the system output connector.

4-23. RATE CHECK.

Rate Check is performed only during the Write/Check mode. A Rate error pulse is generated when the interval between successive Read Strobe (-) pulses decreases to

The Rate Check circuit is located on the error check PCB and operates in the following manner. (See Figures 4-3 and 4-4.) The Read Strobe (-) pulse triggers single-shot delay A which produces a negative-going pulse. The positive-going trailing edge of the single-shot delay A pulse triggers single-shot delay B, which produces a negative-going pulse. The next arriving Read Strobe (-) pulse retriggers single-shot delay A and also is ANDed with the output of single-shot delay B. If the Read Strobe (-) pulse and the output pulse from single-shot delay B are coincident, a rate error pulse is generated.

4-24. ECHO CHECK.

An Echo output is generated by each Write amplifier whenever the amplifier changes state and reverses the Write head coil current. The Echo output is a positive-going pulse derived from the induced EMF generated by the Write head inductance when the write head coil current reverses.

In ORed Clock systems, the data that is written must cause at least one head driver to change state in each frame. The Echo output of each Write amplifier is ORed with the Echo outputs of all other Write amplifiers to generate an ORed Echo output. The ORed Echo output occurs if any Write amplifier changes state during the frame interval. If no ORed Echo occurs during the frame, a malfunction in the Write circuits is indicated and an Echo error pulse is generated by the Echo Check circuits.

The Echo error pulse is generated in the following manner. (See Figures 4-5 and 4-6.) The Write Strobe triggers the single-shot delay and the leading edge of the single-shot delay pulse sets the flip-flop. The Write Strobe holds the AND gate FALSE for the strobe duration to prevent any output from the AND gate during the period that the single-shot delay and flip-flop are going TRUE. The AND gate is also held FALSE by the single-shot delay pulse for the duration of its delay. The Echo input must occur sometime after the Write Strobe and within the duration of the single-shot output. The Echo input resets the flip-flop. If no Echo input occurs, the flip-flop remains set at the end of the single-shot delay pulse and the output of the AND gate goes TRUE, indicating an Echo Error.

4-25. WRITE/CHECK ERROR.

The Vertical Parity Check output, Rate Check output, and Echo Check output are ORed together. The occurence of any error triggers a pulse generator circuit, which produces a negative-going 1 microsecond error pulse. The error pulse is ANDed with Write Permit. If the Write Permit is TRUE, a negative-going Write Check Error pulse is produced at the output of the AND gate driver and is transmitted to the customer via the system output connector.

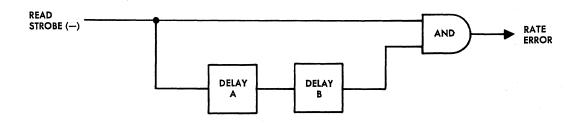


Figure 4-3 Rate Error Check, Block Diagram

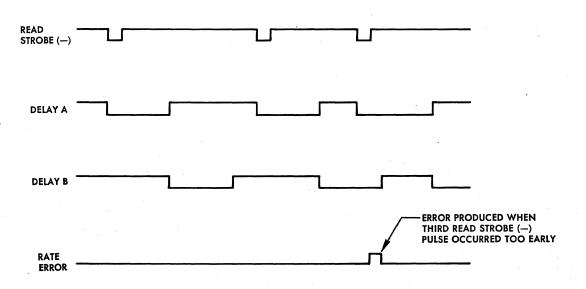


Figure 4-4 Rate Error Timing

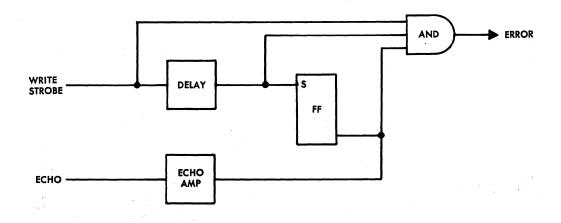


Figure 4-5 Echo Check, Block Diagram

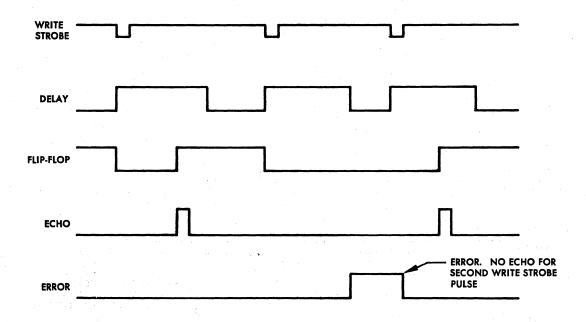


Figure 4-6 Echo Check Timing

SECTION V MAINTENANCE

5-1. INTRODUCTION.

This section contains adjustment procedures and troubleshooting techniques for the data electronics. Tape transport maintenance is included in the Tape Transport technical manual.

5-2. TEST EQUIPMENT.

Table 5-1 lists the required test equipment.

TABLE 5-1 REQUIRED TEST EQUIPMENT

EQUIPMENT	RECOMMENDED TYPE OR EQUIVALENT
Voltmeter	Hewlett-Packard HP 412A
Alignment Master Tape	Ampex 750-238
Oscilloscope	Tektronix 535
Preamplifier	Tektronix CA
Square Wave Generator	Hewlett-Packard HP 211

5-3. ADJUSTMENT SCHEDULE.

Adjustments are made by Ampex prior to the shipment of equipment. Further adjustments are not normally required unless components are interchanged or replaced. Verify adjustments every 500 hours of operation to maintain maximum data reliability.

5-4. ADJUSTMENT PROCEDURES.

Tape transport and power supply adjustments must be verified before data electronics adjustments are made. Due to the interrelationship between circuit functions, data electronics adjustments must be made in the following sequence.

- 1. Clipping Level
- 2. Read Deskew
- 3. Write Check
- 4. Write Deskew
- 5. Read Strobe Delay
- 6. Rate Check Reference Time*



An insulated blade screwdriver is recommended for making adjustments to prevent accidental shorting of components.

The following preliminary checks should be made before any read deskew, write deskew, or read strobe adjustments are made. Verify that the tape path is clean and free of any restrictions to tape movement. TM-11 and TM-12 tape transports only: In new installations or where the tape guides have been replaced, ensure that the top flanges (caps) on the spring-loaded tape guides are in contact with the center sleeves of the guides. If the attaching screws of the top flanges must be tightened to bring the flanges in contact with the sleeves, a torque driver should be used and the screws tightened to 2.5 to 3.0 inch-pounds of torque.

If adjustments are to be made off line, use Alternate Adjustment Procedure. (Refer to paragraph 5-11.)

5-5. CLIPPING LEVEL.

The bias setting adjustment on the Strobe Generator card determines the clipping level. In the Read Only Mode, the clipping level is set at 20 percent. In the Write Check Mode, the clipping level is set at 40 percent. These percentages refer to the base-to-peak amplitude of the signal into the peak detector.

Step 1: Connect the voltmeter negative lead to pin B8-32 (clip level output) and the positive lead to TS1-3 (-6 volt reference).

^{*}Required only when the optional write check circuits are used in the data electronics.

- Step 2: With power ON, select Remote Mode at the Operator control panel (OCP). When the REMOTE indicator goes ON, the system is ready for operation.
- Step 3: Set the Write Permit input to the TRUE level.
- Step 4: Adjust R9 (bottom potentiometer) on the strobe generator (SG) PCB at B8 to obtain +1.40 ±0.05 volts between B8-32 and TS1-3, as indicated on the voltmeter. (See Figure 5-1 for potentiometer location.)

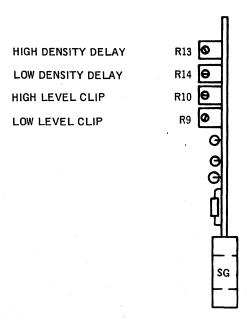


Figure 5-1 Clip Level and Strobe Delay Potentiometers

- Step 5: Set the Write Permit input to the FALSE level.
- Step 6: Adjust R10 (second-from-bottom potentiometer) on SG to obtain ± 0.02 volts between B8-32 and TS1-3, as indicated on the voltmeter.
- Step 7: Repeat Steps 3 through 6 to ensure that the level has not changed. This completes the clipping level adjustment.
- Step 8: Disconnect the voltmeter.

5-6. READ DESKEW.

The read deskew adjustment is made using a skew alignment master tape (Ampex No. 750-238). The skew correction is accomplished by setting the delay time of each read deskew single-shot so that the trailing edges of the delay pulses are coincident. A reference track is selected and the trailing edge of the center track (track 5 in 9-track systems, track 4 in 7-track systems) read deskew delay pulse is aligned with the trailing edge of the selected reference track read deskew delay pulse. The center track is then used as the reference track during the read deskew adjustment. A preliminary read-amplifier-gain check is made to ensure that the read amplifier output signal amplitude is adequate for use during the setting of the read deskew single-shot delay times. Steps 3 through 6 pertain to the preliminary read-amplifier-gain adjustment. Steps 7 through 26 pertain to the read forward deskew adjustment. Steps 27 through 41 pertain to the read reverse deskew adjustment and are applicable to bidirectional-read systems only.

Where two potentiometer or test point references are given in an adjustment procedure, the reference not in parenthesis pertains to 9-track systems and the reference in parenthesis pertains to 7-track systems.

Set the Write Permit input to the FALSE level and load the alignment master tape on the transport (ensure that the reel does not contain a write enable ring). Verify that the FILE PROTECT indicator on the OCP is ON.

CAUTION

Write power must be disabled to prevent accidental erasure of the master tape. Disabling is accomplished by the procedures of Step 1.

- Select Remote Mode at the OCP. When the REMOTE indicator goes ON, the system is ready for operation.
- Step 3: Connect an oscilloscope to observe the read signal at pin 12 of the track 1 read deskew (RD) PCB at A2. Set the vertical sensitivity of the oscilloscope to 2 v/cm.
- Step 4: Run the tape forward. Adjust the oscilloscope horizontal sweep rate as required to observe the read signal envelope (sweep rate approximately $50 \, \mu sec/cm$ for a tape speed of 75 ips).
- Step 5: Adjust 2R11 (top potentiometer) on the read amplifier (RA) PCB at B2 to obtain a read signal amplitude of 6 to 8 volts peak-to-peak, as indicated on the oscilloscope. This completes the preliminary read-amplifier-gain adjustment for read data track 1.

- Step 6: Repeat Steps 3 through 5 for each of the remaining read data tracks.

 Refer to Table 5-2 for the read amplifier adjustment and test point locations. See Figure 5-2 for the read amplifier PCB locations. Refer to Table 5-3 for the location of the read deskew PCB assemblies.
- Step 7: Connect the channel A input of the oscilloscope to observe the read signal at pin 12 of the track 1 read deskew (RD) PCB at A2.
- Step 8: Connect the channel B input of the oscilloscope to observe the read signal at pin 12 of the track 2 read deskew (RD) PCB at A3.
- Step 9: Separate the base lines of the two signals displayed on the oscilloscope.
- Step 10: Determine which of the two data bits displayed on the oscilloscope is occurring last. (In the example shown in Figure 5-3, the track 2 read data bit occurs later than the track 1 read data bit.) The track in which the data bit is occurring last is used as the comparison track for the next step.

NOTE

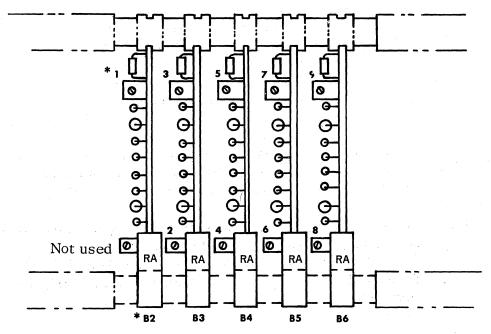
Figure 5-3 illustrates the hypothetical timing relationship between the amplified read data outputs of each track in a 7-track system; a 9-track system would have two additional amplified read data outputs. The relationship shown is for example only, the actual time at which each bit occurs is determined by the gap-scatter of the read heads in the system being adjusted.

- Step 11: Connect the oscilloscope to observe the read signal at pin 12 of the track 3 read deskew PCB at A4 and at pin 12 of the comparison track read deskew PCB selected in Step 10.
- Step 12: Determine which of the two data bits displayed on the oscilloscope is occurring last. (In the example shown in Figure 5-3, the track 2 read data bit occurs later than the track 3 read data bit.) The track in which the data bit is occurring last is used as the comparison track for the next step.

TABLE 5-2 READ AMPLIFIER ADJUSTMENTS

TRACK	*OSCILLOSCOPE POTENTION CONNECTION LOCATION		METER REF DES	
1	A2-12	B2 top	2R11	
2	A3-12	B3 bottom	1R11	
3	A4-12	B3 top	2R11	
4	A5-12	B4 bottom	1R11	
5	A6-12	B4 top	2R11	
6	A7-12	B5 bottom	1R11	
7	A8-12	B5 top	2R11	
8	A9-12	B6 bottom	1R11	
9	A10-12	B6 top	2R11	

^{*}Read Amplifier adjustments are observed on Read Deskew PCBs.



*Read Track and PCB Designations for Reference Only Figure 5-2 Read Amplifier Adjustments

- Repeat Steps 11 and 12 for the remaining read data tracks to determine which data bit of the character is occurring last. Refer to Table 5-3 for the location of the read deskew PCB assemblies. (In the example shown in Figure 5-3, track 2 would be used as the comparison track until the read data bits of tracks 2 and 5 are compared. The track 5 read data bit occurs later than the track 2 read data bit, thus track 5 would be used as the comparison track for track 6. The track 6 read data bit occurs later than the track 5 read data bit, thus track 6 would be used as the comparison track for track 7. The track 6 read data bit occurs later than the track 7 read data bit, thus the track 6 read data bit of the character occurs last in the example.) The track in which the data bit is occurring last is used as the selected reference track for the next step.
- Step 14: Connect the channel B input of the oscilloscope to observe the negative-going read deskew delay pulse at pin 34 of the selected reference track read deskew PCB.
- Step 15: Adjust R25 (top potentiometer) on the selected reference track read deskew PCB so that the read deskew delay pulse is at the 20-percent point of the delay range, as indicated on the oscilloscope. (See Figure 5-4 for potentiometer location.) For example; if the minimum delay time obtained by adjusting R25 fully counterclockwise is 10 μsec and the maximum delay time obtained by adjusting R25 fully clockwise is 25 μsec, 20-percent of the 15-μsec delay range is 3 μsec, thus the delay time is set to 13 μsec (10 μsec minimum plus 3 μsec for 20-percent of the delay range).
- Step 16: Connect pin 34 of the selected reference track read deskew PCB to the external trigger input of the oscilloscope.
- Step 17: Set the oscilloscope for external (-) trigger.
- Step 18: Connect the channel A input of the oscilloscope to observe the negative-going read deskew delay pulse at pin 34 of the center track read deskew PCB at A6 (A5).
- Step 19: Superimpose the base lines of the two signals displayed on the oscilloscope.
- Step 20: Adjust R25 (top potentiometer) on A6 (A5) to superimpose the trailing-edge of the center-track deskew delay pulse on the trailing-edge of the selected reference track read deskew-delay pulse. The trailing-edge of the center-track pulse will appear on the oscilloscope as a jitter band; the jitter band should be centered over the stable trailing-edge of the selected reference track pulse.

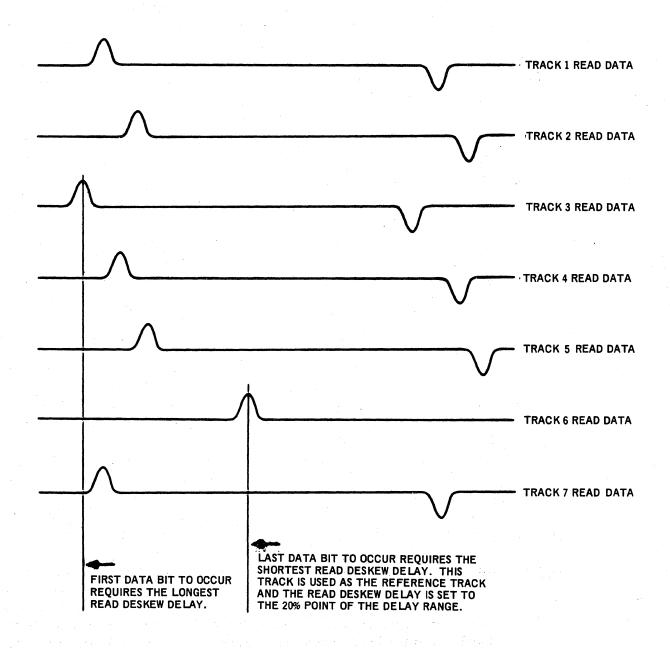
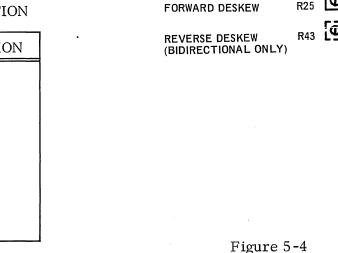


Figure 5-3
Read Deskew Reference Track Selection
(Example Only)

TABLE 5-3
READ DESKEW PCB LOCATION

TRACK	LOCATION
1	A2
2	A3
3	A4
4	A5
5	A6
6	A7
7	A8
8	A9*
9	A10*



*9-track system only.

Read Deskew Potentiometer Location

- Step 21: Disconnect the external trigger input to the oscilloscope from pin 34 of the selected reference track read deskew PCB and connect to pin 34 of the center track read deskew PCB.
- Step 22: Connect the channel B input of the oscilloscope to observe the track 1 read deskew delay pulse at pin 34 of the read deskew PCB at A2.
- Step 23: Adjust R 25 (top potentiometer) on A2 to superimpose the trailing-edge (jitter band) of the track 1 read deskew delay pulse on the trailing edge of the center track read deskew delay pulse.
- Step 24: Adjust the read forward deskew delay times for the remaining tracks by following the procedures of Steps 22 and 23. Refer to Table 5-3 for the location of the read deskew PCB assemblies.
- Step 25: When the read forward deskew delay times of all tracks have been set, connect the channel B input of the oscilloscope to observe the OR 'ed Clock signal at pin 35 of any read deskew PCB. The jitter band of the OR 'ed Clock signal should not exceed 2 μ sec*. If the jitter band exceeds 2 μ sec*, repeat Steps 16 through 25.
- When the read forward deskew adjustments are completed, stop the tape. If the data electronics contains bidirectional-read circuits, proceed to Step 27. If the data electronics contains unidirectional-read circuits, the read deskew adjustment is completed. Disconnect the oscilloscope, unload the master tape from the transport, and remove the extender board.

^{*}For 75 ips tape speed only. For other tape speeds, the jitter band change is inversely proportional to the tape speed change. For example, the jitter band is approximately 4 µsec at 36 ips.

- Step 27: Set the oscilloscope for internal trigger.
- Step 28: Repeat Steps 7 through 13, except run the tape in the reverse direction, to determine which data bit of a character is occurring last. The track in which the data bit is occurring last is used as the selected reference track for the next step.
- Step 29: Connect the channel B input of the oscilloscope to observe the negative-going read deskew delay pulse at pin 34 of the selected reference track read deskew PCB.
- Step 30: Adjust R43 (bottom potentiometer) on the selected reference track read deskew PCB so that the read deskew delay pulse is at the 20-percent point of the delay range, as indicated on the oscilloscope. (See Figure 5-4 for potentiometer location.) For example, if the minimum delay time obtained by adjusting R43 fully counterclockwise is 10 μsec and the maximum delay time obtained by adjusting R43 fully clockwise is 25 μsec, 20-percent of the 15-μsec delay range is 3 μsec, thus the delay time is set to 13 μsec (10 μsec minimum plus 3 μsec for 20-percent of the delay range).
- Step 31: Connect pin 34 of the selected reference track read deskew PCB to the external trigger input of the oscilloscope.
- Step 32: Set the oscilloscope for external (-) trigger.
- Step 33: Connect the channel A input of the oscilloscope to observe the negative-going read deskew delay pulse at pin 34 of the center track read deskew PCB at A6 (A5).
- Step 34: Superimpose the base lines of the two signals displayed on the oscilloscope.
- Step 35: Adjust R43 (bottom potentiometer) on A6 (A5) to superimpose the trailing-edge of the center-track read deskew delay pulse on the trailing-edge of the selected reference track read deskew delay pulse. The trailing edge of the center-track pulse will appear on the oscilloscope as a jitter band; the jitter band should be centered over the stable trailing-edge of the selected reference track pulse.
- Step 36: Disconnect the oscilloscope external trigger input from pin 34 of the selected reference track read deskew PCB and connect to pin 34 of the center track read deskew PCB.
- Step 37: Connect the channel B input of the oscilloscope to observe the track 1 read deskew delay pulse at pin 34 of the read deskew PCB at A2.

- Step 38: Adjust R43 (bottom potentiometer) on A2 to superimpose the trailing-edge (jitter band) of the track 1 read deskew delay pulse on the trailing edge of the center track read deskew delay pulse.
- Adjust the read reverse deskew delay times for the remaining tracks by following the procedures of Steps 37 and 38. It is not necessary to readjust the read deskew delay time of the selected reference track.

 Refer to Table 5-3 for the location of the read deskew PCB assemblies.
- Step 40: When the read reverse deskew delay times of all tracks have been set, connect the oscilloscope to observe the OR'ed Clock signal at pin 35 of any read deskew PCB. The jitter band of the OR'ed Clock signal should not exceed 2 μsec^* . If the jitter band exceeds 2 μsec^* , repeat Steps 31 through 40.
- Step 41: When the read reverse deskew adjustments are completed, stop the tape and disconnect the oscilloscope. Unload the master tape from the transport.

5-7. WRITE CHECK.

The Write Check procedures are performed with the system performing the write and read function. The write permit and read permit levels must be set TRUE and the transport placed in the Remote Mode of operation. Select high density on the OCP. Verify that the write operation is being performed by checking the write amplifiers.

- Step 1: Install the write enable ring. Load a scratch-pad tape on the transport. Set the Write Permit and Read Permit inputs TRUE. Write all ONEs at the high density rate.
- Step 2: Connect the oscilloscope to observe the signal at pin 34 of the track 1 write amplifier at A14. A voltage spike of approximately 10 volts should occur for every other current transition through the write head.
- Step 3: Connect the oscilloscope to observe the signal at pin 30 of the track 1 write amplifier. A voltage spike of approximately 10 volts should occur for every other current transition through the write head.
- Step 4: Repeat the procedures of Steps 2 and 3 for the remaining tracks. Refer to Table 5-4 for the location of the write amplifier PCB assemblies.

^{*}For 75 ips tape speed only. For other tape speeds, the jitter band change is inversely proportional to the tape speed change. For example, the jitter band is approximately 4 µsec at 36 ips.

5-8. WRITE DESKEW.

The write deskew adjustment is made while reading the tape as a series of ONEs is being written. The skew correction is accomplished by setting the delay time of each write deskew single-shot. (The write deskew single-shots are located on the write amplifier PCB assemblies.) A reference track is selected and the trailing edge of the center track (track 5 in 9-track systems, track 4 in 7-track systems) read deskew delay pulse is aligned with the trailing edge of the selected reference track read deskew delay pulse. The center track is then used as the reference track during the write deskew adjustment. The read amplifier gain is adjusted to ensure that the read amplifier output is normal for write check operation before setting the write deskew single-shot delay times. Steps 6 through 8 pertain to the read amplifier gain adjustment. Refer to Table 5-4 for the location of the write amplifier PCB assemblies and see Figure 5-5 for the location of the write deskew potentiometer.

Where two potentiometer or test point references are given in an adjustment procedure, the reference not in parenthesis pertains to 9-track systems and the reference in parenthesis pertains to 7-track systems.

- Step 1: Load a new, blank tape (or a blank tape known to be in good condition) on the tape transport, with a write enable ring in place on the reel.
- Step 2: Set the Write Permit, Read Permit, Select, and all Write Data inputs to the TRUE level.
- Step 3: Select Remote Mode at the OCP. When the REMOTE indicator goes ON, the system is ready for operation.
- Step 4: Program the tape transport to run the tape forward.

TABLE 5-4 WRITE AMPLIFIER PCB LOCATION

	
TRACK	LOCATION
1	A14
2 4 1	A 15
3	A16
4	A17
5	A18
6	A19
7	A20
8	A21*
9	A22*
L	<u> </u>

^{*9-}track system only.

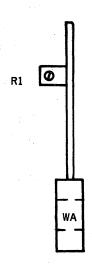


Figure 5-5
Write Deskew Potentiometer Location

- Step 5: Write all ONEs at the normal density rate (the Write Strobe period is $16.67 \mu sec$ for an 800 cpi density at a tape speed of 75 ips).
- Step 6: Connect an oscilloscope to observe the read signal at pin 12 of the track 1 read deskew PCB at A2. Set the vertical sensitivity of the oscilloscope to 2 v/cm. Adjust the oscilloscope horizontal sweep rate as required to observe the read signal envelope (sweep rate approximately 50 µsec/cm for a tape speed of 75 ips).
- Step 7: Adjust 2R11 (top potentiometer) on the read amplifier (RA) PCB at pin 32 to obtain a read signal amplitude of 8 volts peak-to-peak, as indicated on the oscilloscope. This completes the read amplifier gain adjustment for read data track 1.
- Step 8: Repeat Steps 6 and 7 for each of the remaining read data tracks. Refer to Table 5-2 for the read amplifier adjustment and test point locations. See Figure 5-2 for the location of the read amplifier PCB assemblies. Refer to Table 5-3 for the location of the read deskew PCB assemblies.
- Step 9: Set the oscilloscope controls for DC vertical input, 2 v/cm vertical sensitivity, $1 \mu sec/cm$ horizontal sweep rate, and internal (+) trigger.
- Step 10: Connect the channel A input of the oscilloscope to observe the negative-going write deskew delay pulse at test point TP1 of the track 1 write amplifier PCB at A14.
- Step 11: Adjust potentiometer R1 on A14 so that the write deskew delay pulse is at the 20-percent point of the delay range, as indicated on the oscilloscope. (See Figure 5-5 for potentiometer location.) For example; if the minimum delay time obtained by adjusting R1 fully counterclockwise is $10~\mu sec$ and the maximum delay time obtained by adjusting R1 fully clockwise is $25~\mu sec$, 20-percent of the 15- μsec delay range is $3~\mu sec$, thus the delay time is set to $13~\mu sec$ ($10~\mu sec$ minimum plus $3~\mu sec$ for 20-percent of the delay range).
- Step 12: Connect test point TP1 of the track 1 write amplifier to the external trigger input of the oscilloscope.
- Step 13: Set the oscilloscope for external (-) trigger.
- Step 14: Connect the channel B input of the oscilloscope to observe the negative-going write deskew delay pulse at test point TP1 of the track 2 write amplifier PCB at A15.
- Step 15: Superimpose the base lines of the two signals displayed on the oscilloscope.

- Step 16: Adjust R1 on A15 to superimpose the trailing edge of the track 2 write deskew delay pulse on the trailing edge of the track 1 write deskew delay pulse. The trailing edge of the track 2 pulse will appear on the oscilloscope as a jitter band; the jitter band should be centered over the stable trailing edge of the track 1 pulse.
- Step 17: Connect the channel B input of the oscilloscope to observe the write deskew delay pulse at test point TP1 of the track 3 write amplifier PCB at A16.
- Step 18: Adjust potentiometer R1 on A16 to superimpose the trailing-edge (jitter band) of the track 3 write deskew delay pulse on the trailing edge of the track 1 write deskew delay pulse.
- Step 19: Adjust the write-deskew delay times for the remaining tracks by following the procedures of Steps 17 and 18. Refer to Table 5-4 for the location of the write amplifier PCB assemblies.
- Step 20: Connect the channel A input of the oscilloscope to observe the read signal at pin 12 of the track 1 read deskew (RD) PCB at A2.
- Step 21: Connect the channel B input of the oscilloscope to observe the read signal at pin 12 of the track 2 read deskew (RD) PCB at A3.
- Step 22: Separate the base lines of the two signals displayed on the oscilloscope.
- Step 23: Determine which of the two data bits displayed on the oscilloscope is occurring last. (In the example shown in Figure 5-3, the track 2 read data bit occurs later than the track 1 read data bit.) The track in which the data bit is occurring last is used as the comparison track for the next step.

NOTE

Figure 5-3 illustrates the hypothetical timing relationship between the amplified read data outputs of each track in a 7-track system; a 9-track system would have two additional amplified read data outputs. The relationship shown is for example only, the actual time at which each bit occurs is determined by the gap-scatter of the write heads in the system being adjusted. (The gap-scatter of the read heads is compensated for by the read deskew adjustment.)

- Step 24: Connect the oscilloscope to observe the read signals at pin 12 of the track 3 read deskew PCB at A4 and at pin 12 of the comparison track read deskew PCB selected in Step 23.
- Step 25: Determine which of the two data bits displayed on the oscilloscope is occurring last. (In the example shown in Figure 5-3, the track 2 read data bit occurs later than the track 3 read data bit.) The track in which the data bit is occurring last is used as the comparison track for the next step.
- Repeat Steps 24 and 25 for the remaining read data tracks to determine which data bit of the character is occurring last. Refer to Table 5-3 for the location of the read deskew PCB assemblies. (In the example shown in Figure 5-3, track 2 would be used as the comparison track until the read data bits of tracks 2 and 5 are compared. The track 5 read data bit occurs later than the track 2 read data bit, thus track 5 would be used as the comparison track for track 6. The track 6 read data bit occurs later than the track 5 read data bit, thus track 6 would be used as the comparison track for track 7. The track 6 read data bit occurs later than the track 7 read data bit, thus the track 6 read data bit of the character occurs last in the example.) The track in which the data bit is occurring last is used as the selected reference track for the next step.
- Step 27: Connect the channel B input of the oscilloscope to observe the negative-going read deskew delay pulse at pin 34 of the selected reference track read deskew PCB.
- Step 28: Connect pin 34 of the selected reference track read deskew PCB to the external trigger input of the oscilloscope.
- Step 29: Set the oscilloscope for external (-) trigger.
- Step 30: Connect the channel A input of the oscilloscope to observe the negative-going read deskew delay pulse at pin 34 of the center track read deskew PCB at A6 (A5).
- Step 31: Superimpose the base lines of the two signals displayed on the oscilloscope.
- Adjust potentiometer R1 on the center track write amplifier PCB at A18 (A17) to superimpose the trailing edge of the center-track read deskew delay pulse on the trailing edge of the selected reference track read deskew delay pulse. The trailing edge of the center-track pulse will appear on the oscilloscope as a jitter band; the jitter band should be centered over the stable trailing edge of the selected reference track pulse.

- Step 33: Disconnect the oscilloscope external trigger input from pin 34 of the selected reference track read deskew PCB and connect to pin 34 of the center track read deskew PCB.
- Step 34: Connect the channel B input of the oscilloscope to observe the track 1 read deskew delay pulse at pin 34 of the read deskew PCB at A2.
- Step 35: Adjust potentiometer R1 on the track 1 write amplifier PCB at A14 to superimpose the trailing edge (jitter band) of the track 1 read deskew delay pulse on the trailing edge of the center track read deskew delay pulse.
- Adjust the write deskew delay times for the remaining tracks by following the procedures of Steps 34 and 35. It is not necessary to readjust the write deskew delay time of the selected reference track. Refer to Tables 5-3 and 5-4 for the location of the read deskew and write amplifier PCB assemblies, respectively.

CAUTION

Do not change the read deskew delay adjustments. An alignment master tape must be used to set the read deskew delay adjustments.

Step 39: When the write deskew delay times have been set, the write deskew adjustment is complete. Stop the tape and disconnect the oscilloscope. Unload the tape from the transport.

5-9. READ STROBE DELAY.

The read strobe delay adjustment is made while reading the tape as a series of ONEs is being written at the required data transfer rate. Two read strobe delay times are set: one for high density packing, the other for low density packing. Steps 9 through 11 pertain to the strobe delay time adjustment for high density packing, Steps 12 through 14 pertain to the strobe delay time adjustment for low density packing.

The read strobe delay adjustment procedure includes read strobe delay adjustments for density/speed combinations of 800 cpi at 75 ips and 556 cpi at 75 ips. Refer to Table 5-5 for the read strobe delays required at other density/speed combinations.

Step 1: Load a new, blank tape (or a blank tape known to be in good condition) on the tape transport, with a write enable ring in place on the reel.

TABLE 5-5
READ STROBE DELAY TIME*

DENSITY	36 IPS	45 IPS	75 IPS	112.5 IPS	120 IPS	150 IPS
200 cpi	69 µsec	56 μsec	33 μsec	22.0 μsec	29.0 μsec	16.7 μsec
556 cpi	25 μsec	20 μsec	12 μsec	8.0 µsec	7.0 μsec	6.0 μsec
800 cpi	17 μsec	14 μsec	8 μsec	5.5 μsec	5.2 μsec	4.0 μsec

^{*}Read Strobe Delay Time = 1/2 Character Frame Period

- Step 2: Set the Write Permit, Read Permit, Select, and all Write Data inputs to the TRUE level.
- Step 3: Select Remote Mode at the OCP. When the REMOTE indicator goes ON, the system is ready for operation.
- Step 4: Connect the channel A input of an oscilloscope to observe the negative-going OR Clock signals at pin 10 of the strobe generator PCB at B8.
- Step 5: Connect pin 10 of B8 to the external trigger input of the oscilloscope.
- Step 6: Connect the channel B input of the oscilloscope to observe the positive-going Read Strobe (+) pulse at pin 24 of B8.
- Step 7: Set the oscilloscope controls for DC vertical input, 2 v/cm vertical sensitivity, 1 μ sec/cm horizontal sweep rate, external (-) trigger, and chopped channel display.
- Step 8: Program the tape transport to run the tape forward.
- Step 9: Select high density operation at the OCP.
- Step 10: Write all ONEs at the high density rate (the Write Strobe period is 16.67 µsec for an 800 cpi density at a tape speed of 75 ips).
- Step 11: Adjust R13 (top potentiometer) on B8 to obtain a read strobe delay of 8 µsec* between the leading edge of the first OR Clock signal and the trailing edge of the following Read Strobe (+) pulse, as indicated on the oscilloscope. The timing relationship of the two signals is shown in Figure 5-6. See Figure 5-1 for potentiometer location.
- Step 12: Select low density operation at the OCP.

^{*}For 800 cpi at 75 ips. Refer to Table 5-5 for the read strobe delay required at other density/speed combinations.

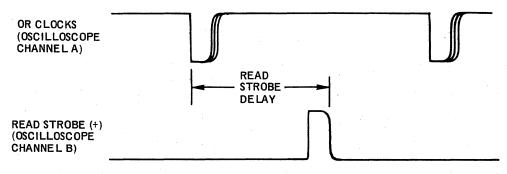


Figure 5-6
Read Strobe Delay Timing

Step 13: Write all ONEs at the low density rate (the Write Strobe period is 24 usec for a 556 cpi density at a tape speed of 75 ips).

Step 14: Adjust R14 (second-from-top potentiometer) on B8 to obtain a read strobe delay of 12* μsec between the leading edge of the OR Clock signal and the trailing edge of the following Read Strobe (+) pulse, as indicated on the oscilloscope. This completes the read strobe delay adjustment.



Systems Operating at 150 IPS.

Under worst case program conditions at 150 IPS, the cumulative timing errors introduced by dynamic skew and instantaneous speed variation (ISV) can cause a read register flip-flop set (OR Clock leading edge) and the read register reset (Read Strobe trailing edge) conditions to occur simultaneously or almost simultaneously. These conflicting commands to the read register flip-flop can cause a read data error. The following read strobe delay adjustment should be used if the read strobe timing is causing read data errors.

Connect the oscilloscope to observe the OR Clock and Read Strobe pulses. (Use the worst case program that produced the read data errors.) Adjust the read strobe delay as required to provide a guardband of approximately 1 μ sec between the Read Strobe pulse and the nearest OR Clock pulse.

Step 15: Stop the tape and disconnect the oscilloscope. Unload the tape from the transport.

^{*}For 556 cpi at 75 ips. Refer to Table 5-5 for the read strobe delay required at other density/speed combinations.

5-10. RATE CHECK REFERENCE TIME.

The rate check reference time adjustment is made while reading the tape as a series of ONEs is being written at the required data transfer rate. An error signal is produced when the interval between successive read strobe pulses is less than approximately 67-percent of the nominal interval.

The rate check reference time adjustment procedure includes rate check reference time adjustments for the density/speed combination of 800 cpi at 75 ips. Refer to Table 5-6 for the rate check reference time required at other density/speed combinations.

TABLE 5-6
RATE CHECK REFERENCE TIME*

DENSITY	36 IPS	45 IPS	75 IPS	112.5 IPS	120 IPS	150 IPS
556 cpi 800 cpi	33 μsec 23 μsec	27 μsec 19 μsec	16 μsec	11.0 μsec 7.4 μsec	10.9 µsec	8.0 μsec 5.6 μsec

^{*}Rate Check Reference Time = 2/3 Character Frame Period.

- Step 1: Load a new, blank tape (or a blank tape known to be in good condition) on the tape transport, with a write enable ring in place in the reel.
- Step 2: Set the Write Permit, Read Permit, Select, and all Write Data inputs to the TRUE level.
- Step 3: Select Remote Mode at the OCP. When the REMOTE indicator goes ON, the system is ready for operation.
- Step 4: Connect the channel A input of an oscilloscope to observe the negative-going Read Register Reset (-) pulse at pin 23 of the error check PCB at B12.
- Step 5: Connect pin 23 of B12 to the external-trigger input of the oscilloscope.
- Step 6: Connect the channel B input of the oscilloscope to observe the negative-going rate error delay B pulse at pin 27 of the error check PCB at B12.
- Step 7: Set the oscilloscope controls for DC vertical input, 2 v/cm vertical sensitivity, $2 \mu sec/cm$ horizontal sweep rate, external (-) trigger, and chopped channel display.
- Step 8: Program the tape transport to run the tape forward.

Step 9: Select high density operation at the OCP.

Step 10: Write all ONEs at the high density rate (the Write Strobe period is 16.67 µsec for an 800 cpi density at a tape speed of 75 ips).

Step 11: Adjust potentiometer R12 on B12 to obtain a rate check reference time of 11 μsec* between the leading edge of the Read Register Reset (-) signal and the trailing edge of the following rate error delay B pulse, as indicated on the oscilloscope. The timing relationship of the two signals is shown in Figure 5-7. This completes the rate check reference time adjustment.

 $\underline{\text{Step 12}}$: Stop the tape and disconnect the oscilloscope. Unload the tape from the transport.

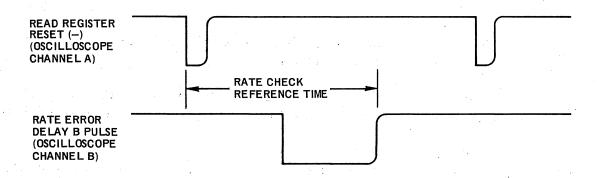


Figure 5-7
Rate Check Reference Timing

^{*}For 800 cpi at 75 ips. Refer to Table 5-6 for the rate check reference time required at other density/speed combinations.

5-11. ALTERNATE ADJUSTMENT PROCEDURE.

The alternate adjustment procedure may be used to make off-line adjustments. The tape transport must be in the LOCAL mode when making off-line adjustments.

5-12. GENERAL.

The output of a square-wave generator may be applied to test points TP1 and TP2 (TP2 is ground) to write a series of ONEs on all tracks. Verify transport and power supply adjustments. Sequence of off-line adjustments are the same as listed in paragraph 5-4.

CAUTION

To prevent accidental damage to external equipment, disconnect the input at connector J5 of the data electronics.

- 5-13. <u>Clipping Level</u>. The clipping level is adjusted in the manner described in paragraph 5-5. The input buffer PCB at B16 is extracted from B16 to simulate a Write Permit TRUE signal.
- 5-14. Read Deskew. The read deskew adjustments are as described in paragraph 5-6. For a read forward only system, ensure that -12 volts (TRUE) is at pin 21 of the read deskew PCB. For a bidirectional read system, connect -12 volts to pin 26 of J5 on the data electronics before performing forward deskew adjustment. For reverse deskew adjustment, remove the -12 volts from pin 26 of J5 and connect 0 volts to pin 26.

CAUTION

Ensure that the square-wave generator is terminated with the correct load resistance.

5-15. Write Check. The write check and write deskew adjustments are made in the manner described in paragraphs 5-7 and 5-8, with the following exceptions.

Connect a square-wave generator to TP1 and TP2 on the data electronics assembly. Simulate Write Permit and Run/Stop TRUE by removing the input buffer PCB from B16. Set the frequency of the square-wave generator according to Table 5-7. Adjust the output amplitudes for 0 and -12 volts. For a bidirectional read system, connect -12 volts to pin 26 of J5 on the data electronics.

5-16. Read Strobe Delay and Rate Check Reference Time. The read strobe delay and rate check reference time adjustments are made in the manner described in paragraphs 5-9 and 5-10, with the following exceptions. The square-wave generator is connected as described in paragraph 5-15. The generator frequencies required to simulate the bit density are listed in Table 5-7.

TABLE 5-7
TEST DESKEW INPUT REQUIREMENT
(SYSTEM DATA TRANSFER RATE)

DENSITY	36 IPS	45 IPS	75 IPS	112.5 IPS	120 IPS	150 IPS
200 cpi	7.2 kHz	9.0 kHz	15.0 kHz	22.5 kHz	24.0 kHz	30.0 kHz
556 cpi	20.0 kHz	25.0 kHz	41.7 kHz	62.5 kHz	66.7 kHz	83.4 kHz
800 cpi	27.8 kHz	36.0 kHz	60.0 kHz	90.0 kHz	96.0 kHz	120.0 kHz

5-17. TROUBLESHOOTING PROCEDURE.

The data electronics circuits are on plug-in type printed circuit boards (PCBs). The troubleshooting charts, Tables 5-9 and 5-10, facilitate the isolation of the malfunctioning PCB. The location and function of each PCB is shown in Figure 2-1.

The Theory of Operation in Section IV, the Printed Circuit Descriptions in Section VI, and the logic diagram in Section VII provide the information required for more extensive troubleshooting.

Check the equipment for evidence of damage, that no wires are disconnected, and that the PCBs are firmly seated in the connector at the proper location.

5-18. PRELIMINARY TESTS.

Establish that the input signals controlling the data electronics are as required. Table 5-8 lists the input function, the signal requirement, and the test point. These tests are made at the output of the buffer amplifiers. Should the input signals not be as required, the possibility of a malfunctioning input buffer PCB exists. A check may be made by exchanging the PCB at B16 with the PCB at B15. Use an oscilloscope to make all tests. Refer to the logic diagram in Section VII while performing all tests.

A write operation cannot be performed unless at least one Write Data input line is TRUE. The input data may be coincident with the Write Strobe pulse or may be held in the TRUE condition by a continuous -9 to -25 volt level. Removing the input buffer PCB at B15 will have the effect of conditioning tracks 1 through 8 to write all ONEs.

To determine that the write operation is being performed, connect the oscilloscope input lead to pin 24 of any write amplifier PCB at A14 through A22. A 10-volt spike should be present. The repetition rate is a function of the Write Strobe rate.

The read function is controlled by the read permit level and the strobe generator. Should no data output be present, determine if data is being read by any of the read tracks by checking the OR Clock pulse at pin 10 of the strobe generator PCB at B8. A negative-going pulse should be observed. The repetition rate will be determined by the data transfer frequency. Should the test confirm that data is being read by the read heads, but no data is being presented to the outputs, investigate the condition of the Read Permit line at pin 9 of the write power gate PCB at A24. The level of read permit at this point must be 0 volts. Should the level not be 0 volts, replace the write power gate. The Read Strobe and the Read Register Reset pulses must be present at pins 24 and 22 of the strobe generator PCB at B8; the Read Strobe pulse is positive-going, the Read Register Reset pulse is the inverse of the strobe pulse. Should the signals not be as indicated in the preceding test, replace strobe generator B8.

TABLE 5-8 INPUT SIGNALS

INPUT FUNCTION	TEST POINT	SIGNAL
Write Reset	B16-14	0V
Write Permit	B16-20	-12V
Write Strobe	B16-22	-12V pulses
Read Permit	B16-26	-12V
Run/Stop (or Fwd/Stop)	B16-28	-12V

5-19. TROUBLESHOOTING TABLES.

Troubleshooting Tables 5-9 and 5-10 may be used as a guide to further investigate any malfunction existing in the data electronics.

TABLE 5-9 WRITE SECTION TROUBLESHOOTING PROCEDURE

MALFUNCTION	FAILURE INDICATION	REMEDY
1. No head driver output on any track as measured at pins 30 and 34 of PCBs A14 through A22	 A. Input Buffer output at B16-20 is at 0 volts B. Output of Write Power Gate at pins A24-28, -29, and -30 is at 0 volts 	Replace PCB B16 Verify that Write Enable Ring is in place. If ring is in place and the malfunction still exists, replace PCB A24
	C. Write Register Reset output at B8-30 is +12 volts when Write Permit at B8-28 and Run at B8-20 are at -6 to -12 volts	Replace PCB B8
The second secon	D. Either a constant 0 volts or a constant -12 volts Write Strobe signal at B16-22	Replace PCB B16
2. No head driver output on a particular track as measured at pins 30 and 34 of PCBs A14 through A22	A. Write Data output from the input buffer of the mal-functioning track remains at 0 volts when ONEs are being written on that track	Replace the PCB corre- sponding to the mal- functioning track
	B. Input to the Write Amplifier is negative and the Write Strobe is present, but no output at pins 30 and 34 of the Write Amplifier	Replace Write Amplifier PCB associated with the malfunctioning track (A14 through A22)

TABLE 5-10
READ SECTION TROUBLESHOOTING PROCEDURE

MALFUNCTION	FAILURE INDICATION	REMEDY
1. No output on any track as measured	A. Read Permit output at B16- is at 0 volts	26 Replace PCB B16
at the output of the output drivers	B. Read Register DC Reset at A24-9 is at -6 volts	Replace PCB A24
	C. OR Data input at B8-10 remains at a constant -6 volt	
	D. Read Permit is negative at B8-12 and an OR Data signal is present at B8-10 but no Read Strobe pulse at B8-24 or no Read Register Reset output at B8-22	
	E. Read Amplifier output of 6 to 8 volts peak-to-peak at pins 12 and 14 of A2 through A10 but no OR Data output at pin 35 of A2 through A10. Clipping Level input at pins 24 of A2 through A10 at -10 volts or greater	B8
	F. No Read Register Reset output at B8-22 or no Read Strobe at B8-24 when OR data is present at B8-10. Both High and Low Density Select at B8-34 and B9-35 are at a voltage other than -12 volts	

TABLE 5-10 READ SECTION TROUBLESHOOTING PROCEDURE (Continued)

	·		
	MALFUNCTION	FAILURE INDICATION	REMEDY
2.	No output from a particular track at the output of the Output Driver	A. No Read Amplifier output at pins 12 and 14 of the Read Deskew boards of the malfunctioning track	Adjust Read Amplifier of malfunctioning track. (Refer to paragraph 5-8.) If malfunction is not corrected, replace Read Amplifier board and adjust. If malfunction still exists, replace Read Deskew board of malfunctioning track
		B. No output at pin 32 of the Read Deskew board of the malfunctioning track, but 6 to 8 volts peak-to-peak measured at pins 12 and 14 of that PCB	Replace Read Deskew PCB of the malfunctioning track
		C. No output signal from the output driver of the malfunctioning track even though both inputs to the output driver are TRUE	Replace PCB B13 or B14
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SECTION VI CIRCUIT DESCRIPTIONS

6-1. INTRODUCTION.

This section contains detailed circuit descriptions of typical printed circuit board assemblies used in the data electronics. The circuit descriptions are in alphabetical sequence by mnemonic coded designation. Schematic diagrams and assembly drawings are located in Section VII.

TABLE 6-1 LIST OF CIRCUIT DESCRIPTIONS

CODE	CIRCUIT DESCRIPTION	SCHEMATIC
ECC	Error Check	3109873
EOA	Exclusive OR	3104452
IBA	Input Buffer	3107038
ODA	Output Driver	3107043
RAB	Read Amplifier	3107118
RDB	Read Deskew	3107253
RDC	Read Deskew, Bidirectional	3109930
SGA	Strobe Generator	3107058
SLB	Select Logic	3111158
WAB	Write Amplifier	3112345
WPD	Write Power Gate	3107128

1. GENERAL DESCRIPTION.

This card contains the circuits required to perform the Write Check function.

2. THEORY OF OPERATION.

The Write Check function checks the read-after-write data for Parity, Rate and Echo errors. The outputs of the Parity, Rate and Echo check circuits are ORed together such that a Write Check error is generated at the card output if either a Parity, Rate or Echo error is generated.

 $\frac{\text{Parity.}}{\text{R17 and CR10.}} \text{ The Parity input is ANDed with the Read Register Reset by the AND gate made up of $\overline{\text{R17}}$ and CR10. The Read Register Reset pulse occurs simultaneously with the Read Clock. The output of the AND gate drives diode CR13, which is an input to the OR gate driving $Q6$.}$

Rate Check. The Rate Check circuit checks the period between successive Read Register Reset pulses and generates an output from the AND gate made up of CR11, CR12, and R18 whenever the period between Reset pulses decreases beyond an adjustable threshold. The Rate circuit operates as follows.

A negative Register Reset pulse turns Q1 ON, forcing the single-shot SS-1 (Q2 and Q3) to trigger. At the end of single-shot SS-1's delay, the single-shot SS-2 (Q4 and Q5) is set. The output of SS-2 is ANDed with the next arriving Register Reset pulse. The sum of the delays of SS-1 and SS-2 is adjusted by potentiometer R12 to give a total delay of 0.67 (1/upper Data Transfer frequency). Under normal conditions the next arriving Register Reset pulse will not coincide with the output of SS-2 and the AND gate will give no output. If the tape speed was slow at the time of writing such that the distance between frames was decreased to 0.67 (normal frame time) or less, then coincidence will occur at the AND gate and a Rate Error will be indicated.

Echo Check. The Echo Check circuit verifies that at least one Head Driver changes state after each Write Strobe. The Echo Check circuit operates as follows.

The flip-flop made up of transistors Q16 and Q17 is held reset at all times that the Write Amplifiers are reset. This is done by the Write Register DC Reset input at pin 19. When writing, the Write Register DC Reset is FALSE and the flip-flop is no longer forced reset. The Write Strobe input at pin 11 causes the single-shot (SS-3), made up of Q10 and

2. THEORY OF OPERATION. (Continued)

Q11 to trigger. The output of SS-3 is inverted by the inverter made up by Q12. The flip-flop is set by the single-shot at the moment that the single-shot triggers. The input to the AND gate at CR26 is held FALSE for the duration of the delay of SS-3.

The Echo outputs from the Write Amplifiers arrive at pin 15 before the delay of SS-3 ends, and the first arriving Echo resets the flip-flop. If there is no Echo input after a Write Strobe, the flip-flop remains set and at the end of the delay of SS-3, the flip-flop output coincides with the output of the inverter, made up of Q12, and an Echo Error output is generated by the AND gate.

OR Gate. The outputs from the Parity, Rate and Echo AND gates drive the OR gate made up of CR13, CR14, and CR29. This gate drives the circuit made up of Q6 and Q7 which limits the duration of the Write Check Error output pulse. Resistor R24 and diode CR16 make up an AND gate ANDing the Write Permit with the Write Check Error output. Q8 makes up the inverter that repowers the Write Check output.

3. OPERATIONAL CHARACTERISTICS.

		
FUNCTION	UP LEVEL	DOWN LEVEL
Write Permit	0 ±0.5 volt -12 volts	
Parity	0 ±0.5 volt	-12 volts
Read Register Reset	0 ±0.5 volt	-6 volts most positive
Write Strobe	0 ±0.5 volt	-6 volts
Write Register DC Reset	+12 volts	Open circuit
Echo	+5 volt transition	
Write Check Error	0 ±0.5 volt	-12 volts

4. POWER REQUIREMENTS.

VOLTAGE	CURRENT	
+12 VDC ±3%	20 ma	
-12 VDC ±3%	78 ma	
- 6 VDC ±4%	16 ma	

This card contains four independent logic elements. Two of the elements require external termination. Each element performs an Exclusive OR function. Electrically, the output assumes UP level only when the polarities of the two inputs are dissimilar.

2. TRUTH TABLE.

INPUT 1	INPUT 2	OUTPUT
-6	-6	-6
-6	0	0
. 0	-6	0
0	0	-6

3. THEORY OF OPERATION.

Diodes CR1 and CR2 comprise an OR gate. Diodes CR3 and CR4 comprise an AND gate. Transistors Q1 and Q2 are inverters.

Two 0 volt inputs forward bias CR1 and CR2 which conduct and place a positive voltage on the base of Q1 (with respect to the emitter), causing Q1 to cut off. Diodes CR3 and CR4 are back biased and 0 volt appears at the anode of CR6. With Q1 cut off, CR6 is forward biased and conducts, placing 0 volt on the base of Q2. Transistor Q2 is cut off and -6 volts appears at the output.

Zero volt at Input 1 and -6 volts at Input 2 will cause the following sequence of events. Diode CR1 is forward biased and conducts, causing CR2 to be back biased, placing 0 volt on the base of Q1 and causing Q1 to cut off. Diode CR4 is forward biased and conducts, causing CR3 to be back biased and placing -6 volts on the anode of CR6. With Q1 cut off, CR6 is forward biased and conducts, placing -6 volts on the base of Q2. Transistor Q2 conducts and 0 volt appears at the output. When the input voltages are reverse, (-6 volts at Input 1 and 0 volt at Input 2), the circuit action is the same except that diodes CR2 and CR3 conduct and CR1 and CR4 are cut off.

Two -6 volt inputs reverse bias CR1 and CR2 which drives the base of Q1 negative and Q1 conducts. Diodes CR3 and CR4 are forward biased and conduct, placing -6 volts on the anode of CR6. With Q1 conducting and CR6 back biased, the base of Q2 goes positive. Transistor Q2 cuts off and -6 volts appears at the output.

4. OPERATIONAL CHARACTERISTICS

	INPUT		OUTPUT	
FUNCTION	UP LEVEL	DOWN LEVEL	UP LEVEL	DOWN LEVEL
Voltage	0.0V to -0.5V	-5V to -13V	0.0V to 0.5V	-5.7V to -6.7V
Current	5.4 ma max	1 ma max at -6.3V	13.5 ma max	1 ma max
Rise Time			150 ns ma x *	
Fall Time			1100 ns max*	
Delay	750 ns max** Signal Propagation Delay			

^{*}With 220 pf load returned to ground or 390 pf returned to ground in parallel with 430 ohms returned to -6 volts.

VOLTAGE	CURRENT
+12 VDC ±3%	11 ma max
-12 VDC ±3%	60 ma ma x
- 6 VDC ±4%	6.8 ma max

^{**}Total delay of 4 circuits in series.

This card contains eight identical, independent input buffer circuits. Each circuit provides a non-inverted output and has an input noise rejection of approximately 5 volts.

2. THEORY OF OPERATION.

With 0 volt input, Q1 conducts and -6 volts appears at the collector of Q1. Q2 is driven into saturation by base current via R4. With Q2 conducting, the output is zero.

With -12 volts input, Q1 is reverse biased and cut off. The base of Q2, through R4, goes positive, driving Q2 to cutoff. With Q2 cut off, the output is -12 volts.

3. OPERATIONAL CHARACTERISTICS.

	INPUT		OUTPUT	
FUNCTION	HIGH LEVEL	LOW LEVEL	HIGH LEVEL	LOW LEVEL
Voltage	0.00 ±1.25V	-12 ±12V	0.5V max	-12V thru 2.7K ±10%
Current	2.6 ma max	4.7 ma max	30 ma max	-12V thru 2.7K ±10%
Rise Time			100 ns max	
Fall Time			500 ns max	

VOLTAGE	CURRENT
+12 VDC ±3%	+40 ma ma x
-12 VDC ±3%	-40 ma max
- 6 VDC ±4%	+56 to -19 ma max

Eight identical output driver circuits are mounted on this card. Each circuit provides a two-way gating function.

2. TRUTH TABLE.

INPUT 1	INPUT 2	OUTPUT
HIGH	HIGH	LOW
H I GH	LOW	HIGH
LOW	HIGH	HIGH
LOW	LOW	HIGH

3. THEORY OF OPERATION.

During the following discussion, a 2K output load is assumed. When both inputs are at the high level of zero volts, the input to the base of Q1 becomes positive. Q1 is cut off. When Q1 cuts off, the base of Q2 goes negative. Q2 conducts and functions as an emitter follower until the output reaches approximately -12 volts.

When either one or both inputs are at the low level of -6 volts, the input to the base of Q1 goes negative and Q1 conducts. The base of Q2 goes positive with respect to emitter of Q2 and Q2 cuts off. The output is zero volts.

4. OPERATIONAL CHARACTERISTICS.

	INPUT		OUTPUT	
FUNCTION	HIGH LEVEL	LOW LEVEL	HIGH LEVEL	LOW LEVEL
Voltage	0V to -1V	-5V to -12V	0V to -1V	-12 ±2V
Current	350 µa max	1.5 ma max at -6V	5 ma max	5 ma max

VOLTAGE	CURRENT
+12 VDC ±3%	5.5 ma max
-12 VDC ±3%	55.0 ma ma x

This card contains two independent and identical circuits. Each circuit is a three-stage, variable gain, linear differential preamplifier.

2. THEORY OF OPERATION.

The inputs to the differential preamplifiers are direct coupled to the Read Heads. The first stage, made up of Q1 and Q2, is a typical differential amplifier. The collectors of Q1 and Q2 are capacitively coupled to the second differential stage, made up of Q3 and Q4. A gain potentiometer, R11, is connected between the collectors of Q3 and Q4 to provide a variable gain adjustment. The second state output is capacitively coupled to the third stage made up of Q5 and Q6. Third stage output of Circuit Number 1 appears at pins 14 and 16. Output of Circuit Number 2 appears at pins 22 and 24.

The differential input impedance is from 7K minimum to 15K maximum across the input terminals. Input voltages are from 12 mv to 24 mv peak-to-peak differentially.

To measure gain, band pass, and output amplitude, the Read Amplifier board must be loaded with the Read Deskew board, assembly 3107252-10. Gain is 310 minimum at the maximum setting of potentiometer R11. Band pass is from 90 cps minimum to 35KC maximum with gain set to maximum. The output amplitude is 3.7 volts peak-to-peak minimum without limiting.

VOLTAGE	CURRENT
+12 VDC ±3%	10 ma max
-12 VDC ±3%	10 ma max

This card contains one stage of a differential amplifier, a clipping circuit, a peak detector, a deskew single-shot, and a skew register flip-flop.

2. THEORY OF OPERATION.

The differential input from pins 8 and 10 is applied to the differential amplifier made up of Q1 and Q2. The output of the amplifier is summed with the Clipping Bias input from pin 16, and appears at the bases of Q3 and Q4. Q3 and Q4 form a full-wave rectifier with power gain. The amplitude of the Rectifier output is a function of the Clipping Bias input and appears at the base of emitter follower Q5. Q5 is directly coupled to Q6 and Q7. When the input to Q5 goes positive, Q5 drives the bases of Q6 and Q7 positive. Q6 conducts, charging capacitor C11, and Q7 cuts off. Capacitor C11 reaches maximum charge at the peak of the input waveform at the base of Q6. Following the peak of the waveform, the voltage begins to drop. C11 is charged to the peak voltage and holds the emitter of Q6 to that level. When the voltage at the base of Q6 drops, the base-emitter junction becomes back biased and Q6 cuts off. At the moment Q6 cuts off, the collector of Q6 goes positive, turning on emitter follower Q8. As input to the base of Q7 drops, Q7 begins to conduct and fully discharges C11 when the input waveform reaches zero. The circuit is then prepared for the next positive-going signal. When Q8 conducts, Q9 also conducts, causing Q10 to conduct. When Q10 conducts, a positive signal is fed via CR4 and C12 into the single-shot made up of Q11 and Q12. The output of the single-shot goes negative for the duration of its time delay. The single-shot time delay is dependent on the RC network of C13, R25, and R26. At the end of the time delay, the collector of Q12 goes positive, causing Q13 to conduct. The collector of Q13 goes negative, generating an OR Clock output at pin 35. At the time the collector of Q12 goes positive, the read register flip-flop made up of Q14 and Q15 is set. The flip-flop is later AC reset by a positive-going pulse from AC Reset input, pin 24. The flipflop may also be forced to reset by a Skew Register DC Reset input from pin 26 through R37. The flip-flop output appears at pins 30 and 32.

VOLTAGE	CURRENT
+12 VDC ±3%	16 ma max
-12 VDC ±3%	40 ma max
- 6 VDC ±4%	80 ma max

This card contains one stage of a differential amplifier, a Clipping circuit, a peak detector, a deskew single-shot, and a skew register flip-flop. The deskew single-shot provides two adjustable deskew delays, which are selected by applying +12 volts at one of two inputs.

2. THEORY OF OPERATION.

The Differential input from pins 8 and 10 is applied to the differential amplifier made up of Q1 and Q2. The output of the amplifier is summed with the Clipping Bias input from pin 16, and appears at the bases of Q3 and Q4. Q3 and Q4 form a full-wave rectifier with power gain. The amplitude of the Rectifier output is a function of the Clipping Bias input and appears at the base of emitter follower Q5. Q5 is directly coupled to Q6 and Q7. When the input to Q5 goes positive, Q5 drives the bases of Q6 and Q7 positive. Q6 conducts, charging capacitor C11, and Q7 cuts off. Capacitor C11 reaches maximum charge at the peak of the input waveform at the base of Q6. Following the peak of the waveform, the voltage begins to drop. C11 is charged to the peak voltage and holds the emitter of Q6 to that level. When the voltage at the base of Q6 drops, the base-emitter junction becomes back biased and Q6 cuts off. At the moment Q6 cuts off, the collector of Q6 goes positive, turning on emitter follower Q8. As input to the base of Q7 drops, Q7 begins to conduct and fully discharges C11 when the input waveform reaches zero. The circuit is then prepared for the next positive-going signal. When Q8 conducts, Q9 also conducts, causing Q10 to conduct. When Q10 conducts, a positive signal is fed via CR4 and C12 into the single-shot made up of Q11 and Q12 The output of the single-shot goes negative for the duration of its time delay. The single-shot time delay is dependent on the RC network of C13, R25, and R26 when -12 volts is applied at pin 21, or C13, R43 and R26 when -12 volts is applied at pin 20. Diodes CR16 and CR17 isolate the two inputs. At the end of the time delay, the collector of Q12 goes positive, causing Q13 to conduct. The collector of Q13 goes negative, generating an OR Clock output at pin 35. At the time the collector of Q12 goes positive, the read register flip-flop made up of Q14 and Q15 is set. The flip-flop is later AC reset by a positive-going pulse from AC Reset input, pin 24. The flip-flop may also be forced to reset by a Skew Register DC Reset input from pin 26 through R37. The flip-flop output appears at pins 30 and 32.

VOLTAGE	CURRENT
+12 VDC ±3%	16 ma max
-12 VDC ±3%	40 ma max
- 6 VDC ±4%	80 ma max

This card contains four separate circuits. These circuits generate the Read Strobe, AC Read Register Reset signal, a Write Register DC Reset signal, and a Clipping Level output.

2. THEORY OF OPERATION.

Read Strobe and Read Register AC Reset. The Read Strobe circuit generates a Read Strobe and a Read Register AC Reset output at the time of the arrival of the first OR Clock input. The OR Clock (-) and Read Permit (-) inputs are fed to an AND gate comprised of CR1, CR2, and R20. The output of the gate goes negative, driving the base of Q6 negative, and Q6 conducts. The collector of Q6 goes positive, the OR Clock output at pin 14 goes positive, and a positive spike is coupled to the collector of Q7 through diode CR5 and capacitor C6. Q7 is the first transistor in a three-transistor flip-flop made up of Q7, Q8, and Q9. The positive pulse arriving at the collector of Q7 triggers the single-shot and the collector of Q9 goes negative for the duration of the single-shot delay. At the end of the delay, the collector of Q9 goes positive. This positive-going transition is coupled through CR12 and charges C11. When C11 is charged, the base of Q10 goes positive and Q10 cuts off. (Q10 remains cut off until capacitor C11 discharges to a level which causes the base of Q10 to go negative.) The period in which Q10 is cut off is approximately 1.5 µs. While Q10 is cut off, Q11 cuts off, and the collector of Q11 goes positive causing the Read Strobe output at pin 24 to go positive. The collector of Q11 remains positive for the period of time Q10 is cut off. When the collector of Q11 goes positive, Q12 cuts off and the collector of Q12 goes negative. When Q10 conducts, Q11 conducts and the Read Strobe output at pin 24 goes negative. The negative transition of the Read Strobe is the trailing edge of the Read Strobe pulse. When the collector of Q11 goes negative, Q12 conducts and the collector of Q12 goes positive. The positive transition of Q12 is the Read Register AC Reset signal, and appears at pin 22.

The single-shot in the preceding paragraph operates in the following manner. When a positive pulse is coupled into the collector of Q7, this pulse is also seen at the base and emitter of emitter follower Q8 and charges C8. When C8 is charged, the base of Q9 goes positive, and Q9 is cut off. Q7 is forced into conduction and the collector of Q7 drops to ground potential. The emitter of Q8 also falls to approximately ground and completes the charge cycle of C8. Capacitor C8 then begins a slow discharge through R28, R31, and R13 or R14. Resistors R13 and R14 are selected externally to change the time delay range. R13 is selected in high density. R14 is selected in low density. When C8 is discharged to a point where the base of Q9 goes negative, Q9 conducts and the single-shot delay has ended. Emitter follower Q8 totally discharges C8 through diode CR10 and resistors R30 and R29.

2. THEORY OF OPERATION. (Continued)

Write Register DC Reset. The Write Register Reset signal is a composite of the Run and Write Permit input signals. The Run and Write Permit are ANDed in the following manner. The collector of Q2 is normally negative. If Run or Write Permit inputs are positive, the collector of Q2 goes positive. With Write Permit input at pin 28 negative and Run input at pin 20 positive, Q1 is cut off and the collector of Q1 goes positive. Q13 is conducting. The collector of Q13 goes negative. CR19 is back biased and isolates the collector of Q13 from the collector of Q1. Q2 is conducting. The collector of Q2 goes to +12 volts and appears at output pin 30.

With the Run input negative and Write Permit input positive, Q13 is cut off and Q1 is conducting. The collector of Q1 goes negative. Diode CR19 becomes forward biased and lowers the collector voltage of Q13 to -6 volts. Q2 conducts and +12 volts appears at the collector of Q2 and at output pin 30.

With both Run and Write Permit inputs negative, Q1 and Q13 are cut off. The collector of Q13 rises to a value more positive than the emitter of Q2, driving Q2 to cutoff. The output at pin 30 is negative.

<u>Clipping Level</u>. The Clipping Level circuit provides a negative clipping bias voltage for the Read Deskew circuits. This bias voltage may be varied from approximately -6 to -9 volts. In normal operation, a higher clipping level is required in the Write Mode than that used in the Read Mode. The Clipping Level circuit automatically provides a higher clipping level when the circuit is in the Write Mode.

Transistor Q4 functions as an emitter follower and provides a low impedance voltage source to the output at pin 32. Q4 is driven by the voltage divider network comprised of trim pots R9 and R10, resistor R8, and zener diode VR1. A maximum output of approximately -9 volts is required. This output is obtained by placing VR1 in series with -6 volts to give approximately -9 volts between the anode of VR1 and ground.

When Write Permit (-) is TRUE, Q1 is cut off, causing Q3 to be cut off. With Q3 cut off, the voltage at the base of Q4 may be varied from approximately -6 volts to -9 volts by varying trim pot R9. When Write Permit (-) is FALSE, Q1 and Q3 conduct. The collector of Q3 goes to -6 volts. The voltage at the base of Q4 may then be adjusted between -6 volts and the voltage present at the slider of R9.

VOLTAGE	CURRENT
+12 VDC ±3%	86 ma max
-12 VDC ±3%	100 ma max
- 6 VDC ±4%	30 ma max
+24 VDC ±15%	3 ma ma x

This card contains six independent circuits as follows: two Input Buffers, one Output Driver, one Inverter, one Hi/Lo Density Select Driver, and one Deskew and Amplifier Select Driver.

2. THEORY OF OPERATION.

<u>Input Buffers</u>. The input to Buffer #1 is at pin 12 and the output is at pin 15. The input to Buffer #2 is at pin 13 and the output is at pin 16. The Input Buffer circuits are identical. Only Input Buffer #1 is described.

With 0 volts input, Q5 conducts and -6 volts appears at the collector of Q5. Q6 is driven into saturation by base current via R14. With Q6 conducting, the output is zero.

With -12 volts input, Q5 is reverse biased and cuts off. The base of Q6, through R14, goes positive, driving Q6 to cutoff. With Q6 cut off, the output is -12 volts.

Output Driver. The Output Driver circuit has two inputs at pins 18 and 19, and an output at pin 17. The theory of operation is as follows.

During the following discussion, a 2K output load is assumed. When both inputs are at the high level of zero volts, the input to the base of Q14 becomes positive. Q14 is cut off. When Q14 cuts off, the base of Q15 goes negative. Q15 conducts and functions as an emitter follower until the output reaches approximately -12 volts.

When either one or both inputs are at the low level of -6 volts, the input to the base of Q14 goes negative and Q14 conducts. The base of Q15 goes positive with respect to emitter of Q15 and Q15 cuts off. Output is zero volts.

<u>Inverter</u>. The Inverter circuit has an input at pin 9 and an output at pin 10. The theory of operation is as follows.

When Read Permit input is -12 volts, Q9 is biased to cutoff and the output is 0 volts. When Read Permit input is 0 volts, Q9 is conducting and the output is -6 volts.

2. THEORY OF OPERATION. (Continued)

Density Select Driver. The Density Select Driver input is at pin 25 and the outputs are at pins 21 and 23. The theory of operation is as follows.

The Density Select Driver input is controlled by a pushbutton on the OCP. When the input at pin 25 is 0 volts (Low Density), Q10 and Q11 are cut off. High Density output at pin 23 is open circuit. Q12 and Q13 are conducting and Low Density output at pin 21 is -12 volts.

When the input at pin 25 is -12 volts (High Density), Q10 and Q11 are conducting. High Density output at pin 23 is -12 volts. Q12 and Q13 are cut off and Low Density output at pin 21 is open circuit.

Deskew and Amplifier Select Driver. The Deskew and Amplifier Select Driver input is at pin 27 and the Deskew Select outputs are at pins 29 and 31, and Amplifier Select outputs are at pins 32 and 33.

The theory of operation is as follows. An input of -12 volts causes Q1 and Q2 to conduct and Q3 and Q4 to cut off. When Q2 is conducting, the outputs at pins 31 and 32 are driven to approximately -12 volts by transistor Q2.

When Q4 is cut off, the output at pin 29 goes to \pm 12 volts and the output at pin 33 is isolated from pin 29 by back biased diode CR5.

An input of 0 volts causes Q1 and Q2 to cut off and Q3 and Q4 to conduct. When Q4 is conducting, the outputs at pins 29 and 33 are driven to approximately -12 volts by transistor Q4. The output at pin 31 goes to +12 volts and the output at pin 32 is isolated from pin 31 by back biased diode CR2.

3. OPERATIONAL CHARACTERISTICS.

		INP	UT	OUTPUT		
CIRCUIT	PARAMETER	HIGH LEVEL	LOW LEVEL	HIGH LEVEL	LOW LEVEL	
	Voltage	0.00 ±1.25V	-12 ±2V	0.5V max	-12V thru 2.7K ±10%	
Input	Current	2.6 ma max	4.7 ma max	30 ma max	-12V thru 2.7K ±10%	
Buffer	Rise Time	100 ns		100 ns		
	Fall Time		100 ns		500 ns max	
Output	Output Voltage 0.V to -1		-5V to -12V	0V to -1V	-12 ±2V	
Driver	Current	350 μα ma x	1.5 ma max at -6 volts	5 ma max	5 ma max	
Density Select	Density negative negative		-5.5V least negative	0.3V more positive than -12V supply	Open circuit	
Read Permit			-5.5V least negative	+0.5V max	-6.0 ±0.5V	
Deskew &	Voltage Deskew	0.00 ±1.25V	-9V to -25V	+12V with no load	-12V	
Amplifier Select	Voltage Amplifier Select	0.00 ±1.25V	-9V to -25V	0.0 ±0.8V with no load	-12V	

This card contains the input gating, deskew single-shot and the write head driver flip-flop.

2. THEORY OF OPERATION.

When Write Data input is coincident with the Write Strobe input for a period of $2\,\mu sec$, the Write Data signal is fed through OR diode CR7 to the base of Q2. Transistor Q2 conducts and the collector of Q3 is placed at ground.

Capacitor C7 charges, causing Q4 to cut off and allowing Q3 to conduct. After capacitor C7 discharges, Q4 conducts again. The discharge time of C7 is based on the time constant of C7, R1 (or R2) and R12. The discharge time determines the deskew delay time and can be varied by adjusting potentiometer R2. When the dual speed option is used, potentiometer R1 is used.

With Q4 conducting, Q5 conducts and a negative input is fed to the trigger flip-flop Q7 and Q8. The steering diodes CR18 and CR26 gate the input pulse to the proper transistor, causing the flip-flop to change state.

Assuming the flip-flop is in the reset state, Q6 and Q7 are conducting, Q8 and Q9 are cut off. Diode CR18 is forward biased and CR26 is reverse biased. The collector output of Q6 is at ground and that of Q9 is near +10 volts.

When a negative set pulse arrives at C10 and C11, the pulse through C11 is applied to reverse biased CR26, producing no change. The pulse through C10 is conducted through forward biased CR18 to the base of Q7, cutting Q7 off. When Q7 cuts off, Q6 turns off and opposite state transistors Q8 and Q9 turn on.

When Q8 and Q9 conducts, a ground is provided through the emitter-collector path to output B, pin 30. Simultaneously, the Q6 collector voltage rises to a positive voltage and is applied to output A, pin 34. Each voltage polarity change at the outputs A and B causes a current reversal in the write coil, producing a written ONE on the tape. The positive voltage is also conducted through CR21 to the Echo output, pin 24, for optional Write Check Error usage.

A positive signal at DC Reset input pin 26 causes CR19 to be forward biased, applying a positive potential to the base of Q7. Q7 is forced into conduction. A negative signal at pin 26 causes CR19 to be back biased and disconnects this input.

2. THEORY OF OPERATION. (Continued)

Write Reset input at pin 10 is combined with the Reset output of the flip-flop via Q1 and is handled in the same manner as data, except that a Write Strobe input is not required.

Test Deskew is an input provided for use in the system alignment procedures. Test signals are handled in the same manner as data, except that no other inputs are required.

3. POWER REQUIREMENTS.

VOLTAGE	CURRENT
+12 VDC ±3%	14 ma max
-12 VDC ±3%	14 ma max
- 6 VDC ±4%	8 ma max

This card contains three independent circuits.

The Write Power Gate provides power to the write amplifiers when Write Permit is TRUE and when the Write Enable relay has been energized.

The Read Permit inverter inverts and amplifies the Read Permit signal.

The Density Select driver applies voltage to the density potentiometers located on the Read Deskew Assembly (3107252).

2. THEORY OF OPERATION.

Write Power Gate. When input 1 or 2 is -12 volts, Q1 is biased to cutoff. With Q1 cut off, Q2 is driven into saturation by positive base current through R3. When Q2 conducts, the base of Q3 goes to approximately +3 volts causing Q3 to conduct. With Q3 conducting, the voltage at the base of Q4 goes to approximately +3 volts, causing Q4 to conduct. When Q4 conducts, the output, through pins 7 and 1 of K1, is at +10 volts. Relay K1 is energized when the External File Protect switch is closed.

When input 1 or 2 is 0 volts, Q1 conducts and -6 volts appears at the base of Q3, driving it to cutoff. With Q2 cut off, the base of Q3 goes to +15 volts. As Q3 is conducting, approximately +15 volts appears at the base of Q4, driving it to cutoff. The output is 0 volts.

Read Permit Inverter. When Read Permit input is -12 volts, Q9 is biased to cutoff, and the output is +12 volts. When Read Permit input is 0 volts, Q9 is conducting and the output is -6 volts.

<u>Density Select Driver</u>. The Density Select Driver input is controlled by a pushbutton on the OCP. When input at pin 11 is 0 volts (Low Density), Q5 and Q6 are cut off. High Density output at pin 16 is open circuit. Q7 and Q8 are conducting and Low Density output at pin 17 is -12 volts.

2. THEORY OF OPERATION. (Continued)

Erase Head Driver. Whenever the Write Power Gate is on, current is supplied to the Erase Head through R19. The current is 100 milliamperes nominal.

When input at pin 11 is -12 volts (High Density), Q5 and Q6 are conducting. High Density output at pin 16 is -12 volts. Q7 and Q8 are cut off and Low Density output at pin 17 is open circuit.

3. OPERATIONAL CHARACTERISTICS.

	INP	UT	OUTPUT		
CIRCUIT	HIGH LEVEL	LOW LEVEL	HIGH LEVEL	LOW LEVEL	
Write Power Gate	0.0V to -0.5V	-5.70V to -12.36V	0V to -12.36V +11V to +12V 0.0V		
Density Select -0.5V most -5.5V least negative negative			0.3V more positive Open circuit than -12V supply		
Read Permit	-0.5V most -5.5V least negative negative		0.5V max	-6.0 ±0.5V	
Write Enable Relay	11.64V min at	100 ma max	+11V to +12V	0.0V to -1.5V	

VOLTAGE	CURRENT
+12 VDC ±3%	2 ma max
-12 VDC ±3%	103 ma max
- 6 VDC ±4%	13 ma max
+24 VDC ±15%	30 ma max
-24 VDC ±15%	5 ma max

SECTION VII DRAWINGS

7-1. INTRODUCTION.

Printed circuit board schematics and assembly drawings are included in this section and are located in alphabetic order by the mnemonic code, as shown on Table 7-1.

The master part selector drawings show the standard PCB assemblies used for the various versions of the data electronics. Drawing 3124744 covers the TM-7 series, drawing 3124745 covers the TM-9 series, and drawing 3124746 covers the TM-11/TM-12 series. The part number of the standard data electronics assembly (with or without the echo, rate, or vertical parity check options) is 3115771-10. The part number of a data electronics assembly containing one or more of the special features (special positive input/output levels, vertical parity generate, longitudinal parity check, and longitudinal check character generate) is 3115770- followed by a two digit version number which is determined by the version table on the master part selector drawing. For example, part number 3115770-01 identifies a data electronics assembly wired for bidirectional read (run/stop logic); standard input/output levels; echo, rate, and vertical parity checking; and 7-track vertical parity generate.

Two sets of logic diagrams are located at the end of this section. Logic Diagram 3112457 is for standard DE-211 (7-track) and DE-291 (9-track) systems which use Forward/Reverse and Run/Stop commands. Logic Diagram 3115496 is for standard systems which use Forward/Stop and Reverse/Stop commands.

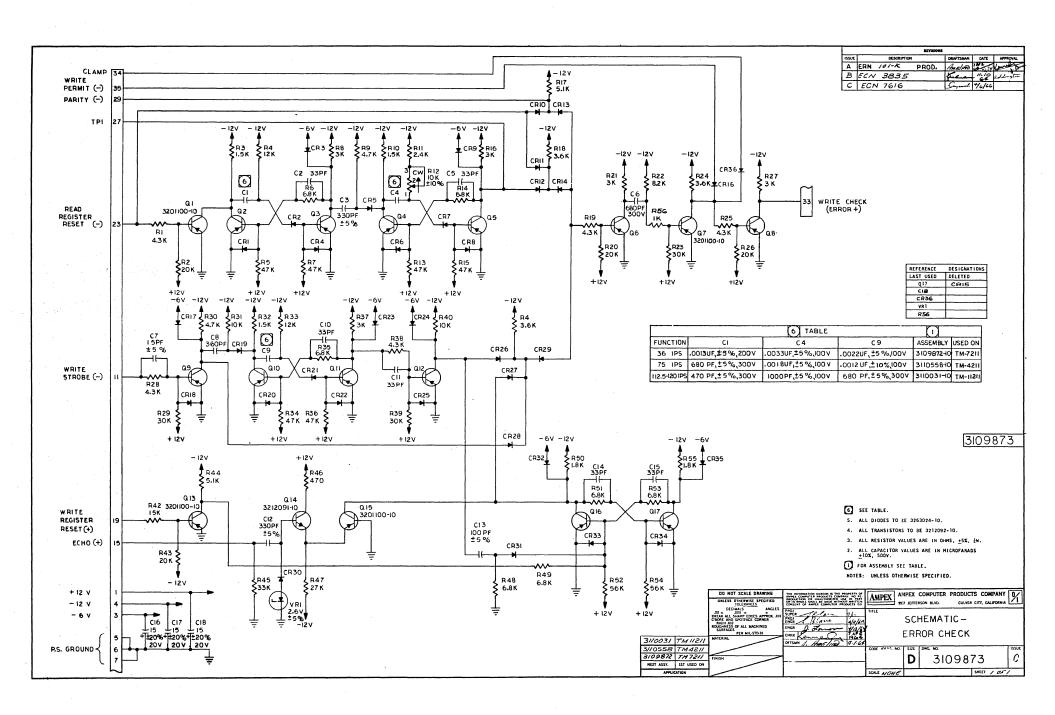
TABLE 7-1 LIST OF DRAWINGS

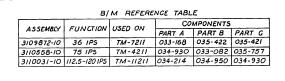
CODE	DESCRIPTION	SCHEMATIC	ASSY DWG
ECC	Error Check	3109873	3109915
EOA	Exclusive OR	3104452	3107274
FFB*	Flip-Flop	3104541	3107275
IBA	Input Buffer	3107038	3107251
IBT*	Input Buffer	3118175	3118174
LGB*	LCC Generator	3116076	3116075
LPB*	LPC Timing -B	3116088	3116087
ODA	Output Driver	3107043	3107255
ODL*	Output Driver	3118184	3118183
ODM*	Output Driver	3118166	3118165
PRB*	Long. Parity Reg -B	3116083	3116100
RAB	Read Amplifier	3107118	3107270
RDB	Read Deskew	3107253	3107273
RDC	Read Deskew, Bidirectional	3109930	3109933
SGA	Strobe Generator	3107058	3107276
SLB	Select Logic	3111158	3111157
WAB	Write Amplifier	3112345	3112347
WPD	Write Power Gate	3107128	3107272

^{*}Required for special features. Refer to Section VIII.

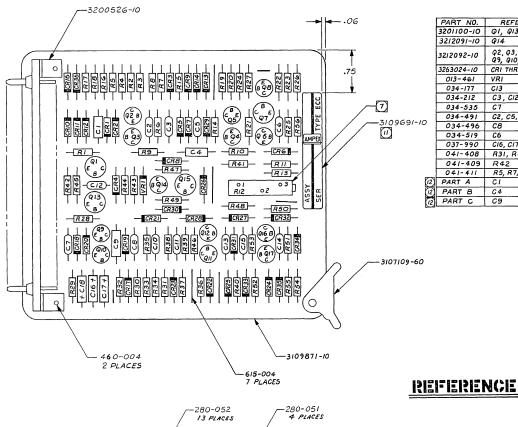
MISCELLANEOUS DRAWINGS

	DESCRIPTION	DWG NO.
		• .
	Master Part Selector	
	Std TM-7 Series	3124744
$\mathcal{T}_{\mathcal{A}}(x,y) = \mathcal{T}_{\mathcal{A}}(x,y) = \mathcal{T}_{\mathcal{A}}(x,y)$	Std TM-9 Series	3124745
	Std TM-11/TM-12 Series	3124746
	Card Location Chart (DE-211/DE-291)	3124747
	Logic Diagram, DE-211 Data Electronics	
	(Fwd/Rev-Run/Stop)	3112457
	(Fwd/Stop-Rev/Stop)	3115496
$(\mathbf{x}_{i}) = \frac{\mathbf{x}_{i}^{(i)}}{2} (\mathbf{x}_{i}) = \frac{\mathbf{x}_{i}^{(i)}}{2} (\mathbf{x}_{i}^{(i)}) = \frac{\mathbf{x}_{i}^{(i)}}{2} (\mathbf{x}_{i}^{(i)})$		
the state of the pro-		a · · · · · · · · · · · · · · · · · · ·





	REVISIONS							
ISSUE	DESCRIPTION	DATE	DRAFTSMAN	DATE	APPROYAL			
A	ERN 101-K PROD REL	4,4	AMELINO	+,64	KEHNED			
В	ECN	\$ 364	MAKANO	8,64	foost			
c	ECN 3835	11065	UPPERMAN	11,60	Gonel			
0	ECN 7616	4,,67	Quint					



TYPICAL TRANSISTOR INSTALLATION

PART NO.	REFERENCE DESIGNATION	PART NO.	REFERENCE DESIGNATION
3201100-10	Q1, Q13, Q15, Q7	041-412	R9, R30
3212091-10	Q14	041-413	R6, R14, R35, R48, R49, R51, R53
3212092-10	Q2, Q3, Q4, Q5, Q6, Q8,	041-428	R46
3212072-10	99, 910, 911, 912, 916, 917	041-430	R3, RIO, R32
3263024-10	CRI THRU CRI4, CRI6 THRU CR36	041-434	R50, R55
013-461	VRI	041-482	R4, R33
034-177	C13	041-483	R47
034-212	C3, C12	041-495	R22
034-535	C7	041-508	R2, R20, R26, R43
034-491	C2, C5, C10, C11, C14, C15	041-518	R45
034-496	CB	041-519	R52, R54
034-519	C6	041-550	R8, R16, R21, R27, R37
037-990	CI6, CI7, CI8	041-561	RI7, R44
041-408	R31, R40	041-570	RII
041-409	R42	041-571	RIB, R24, R41
041-411	R5, R7, RI3, RI5, R34, R36	041-584	RI, RI9, R25, R28, R38
PART A	CI	041-612	R23, R29, R39
PART B	C4	041-410	R56
PART C	C9	044-197	RI2

- [12] INSTALL PARTS 'A' THRU'C' PER TABLE I.
- MARK PART NO. AND NAMEPLATE INFORMATION PER MIL-STD-130.
- 10. PART NO. TO BE AS SHOWN ON B/M.
- 9. SEAL PRINTED CIRCUIT SIDE ONLY WITH HUMISEAL TYPE 1B15 COLUMBIA TECH. CORP. OR EQUIV.
- AMARK POT REF NOS. 12 HIGH CHARACTERS, SOIOR WHITE, PER MILETO-130, DO NOT IMPRESSION STAMP
- 7. TRIMPOTS NOT TO BE SUBMERGED IN WATER.

 6. COMPONENT DESIGNATIONS ARE FOR REF. ONLY.
- -----
- 5. PLUS SIGN ON CAPACITOR INDICATES POSITIVE.
- 4. HEAVY LINE ON DIODES INDICATES CATHODE.
- 3. ASSEMBLE PER PRODUCTION PRACTICES MANUAL.
- 2. FOR ASSEMBLY SPECIFICATION SEE 3/09874.

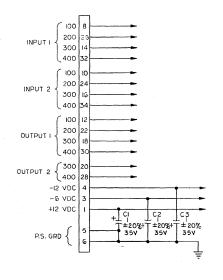
SHEET / OF I

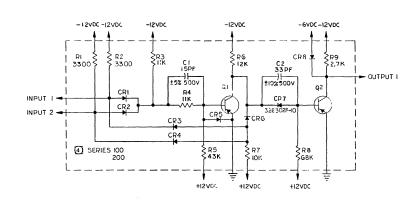
1. FOR SCHEMATIC SEE 3/09873. NOTES:

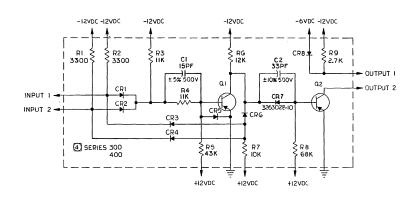
	DO NOT SCALE DRAWING UNLESS OTHERWISE SPECIFIED DIMENSIONS ARE IN INCHES DECIDIALS TOLERANCES ANGLES		DWG. N	DUCTION	DRMATION HEREON IS THE DMPUTER PRODUCTS DIVISI OR UNAUTHORIZED USE HALL BE MADE WITHOUT OF AMPEX COMPUTER PR	ON NO REPRO-	A	MPEX	COMPU P.O. BO	TER PROD	VER CITY,	
		XX± XXX	E ± DGES APPROX010. C'BORE NENER RADII APPROX010 LL MACHINED	109	PROJ ENGR ENGR CHKR	S. BLANK S. BLANK T. CARSON KENNEDY	9/13/44 9/13/44 9/13/44		CIRCU EI	UT BO RROR		
3110031	TM- 11211	1		9	DEISMA	K AMELINO	3/20/14		CODE IDENT. NO.	DWG. NO.		
3//0558 3/09872 NEXT ASSY.		FINISH		5	<u> </u>			D	09150	3	109	

APPLICATION

REVISIONS								
ISSUE	DESCRIPTION	DRAFTSMAN	DATE	APPROVAL				
1	51 - 11	H.B		s				
3	ECN 3149 Pezo.	Cutter. E.	1	12-151.00				
C	ECN 8061	Aremoh	11 4	- 2				







5. ALL TRANSISTORS TO BE 32/2092-10.

(4) REF DESIGNATIONS ARE ABBREVIATED PER MILS-STO-16. PREIKT THE PART DESIGNATION WITH THE SUBASSEMBLY DESIGNATION.

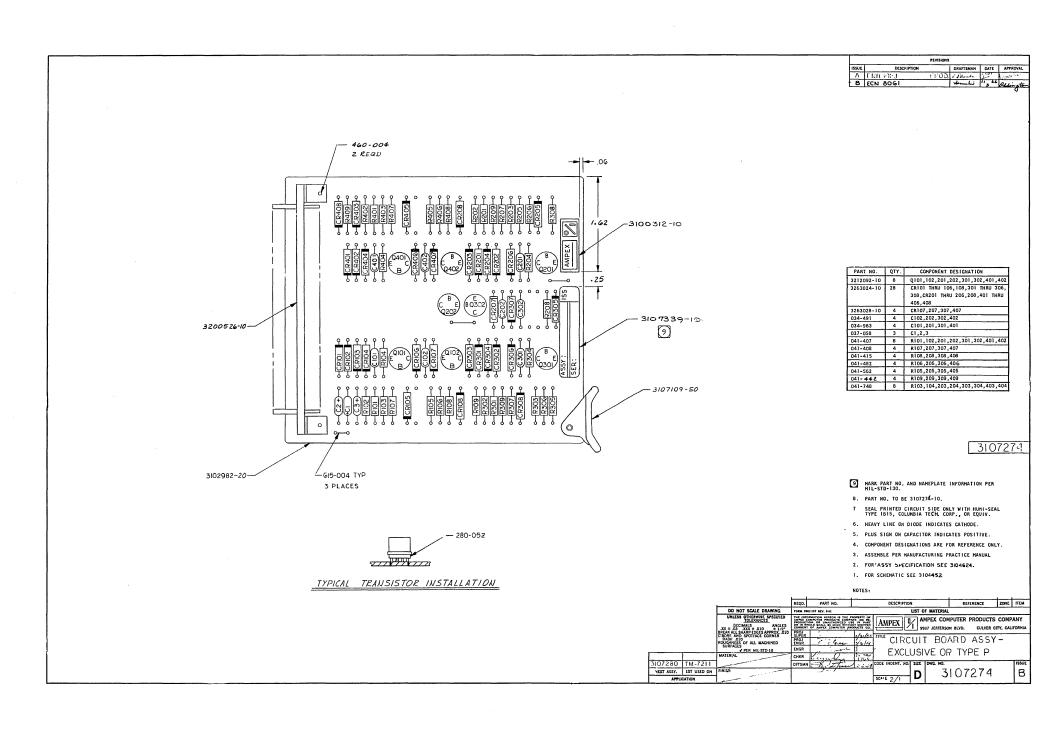
3. ALL DIODES TO BE 32/63024-10.

2. ALL RESISTORS IN OHMS 1-9/6, 1/4 W.

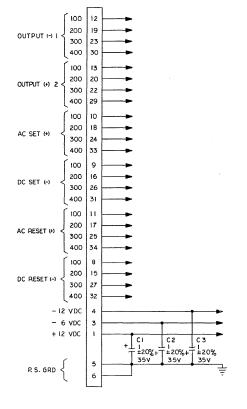
1. ALL CAPACITORS IN MICROFARADS

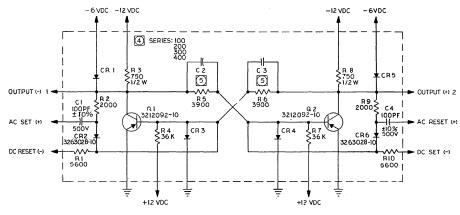
NOTES: UNLESS OTHERWISE SPICIFIED

			REQD.	PART NO.		DESCRIPTION	1	7	REFERENCE	ZONE	ITEM
		DO NOT SCALE DRAWING	FORM 2	102 107 REV. 941		LIST OF MATERIAL					
UNLESS OTHERWISE SPECIFIED TOLERANCES DECIMALS XX ± .03		PRODUC	ORMATION HEREON IS THE PH COMPUTER PRODUCTS COMPA TION OR UNAUTHORIZED US PHOLE SHALL BE MADE WITHOUT T OF AMPEX COMPUTER PRO	T IN PART	AMPEX 0	1	EX COMPUTEI				
		BREAK ALL SHARP EDGES APPROX010 C'BORE AND SPOTFACE CORNER RADII .010 ROUGHNESS OF ALL MACHINED	PROJ SUPER PROJ ENGR	M. Mary V	in	TITLE	5CHE	MATIC,			
		SURFACES # PER MIL-STD-10 MATERIAL	ENGR	4/23,000		EXCLUS	SIVE	OR TY	PE P		
		MATERIAL	CHKR	10 ication	1. 8-40						
	DE-100		DFTSM	A. Wibando	9-2-62	CODE INDENT. NO.	SIZE DW	rg. No.			ISSUE
	1ST USED ON	FINISH		7103-254			D	31044	52		l C
·LI	CATION			1100-204		SCALE NONE		3,011	02		1









TABL	LE I 🗐
ASSY NO.	C2 & C3
3102970-10	33PF,±10%, 500V
3107275-10	33PF,±10%, 500V
3109115-10	15 PF,± 5 %, 500V
3111790 - 10	NONE

5 SEE TABLE 1.

ARE DESIGNATIONS ARE ABBREVIATED PER MILESTD-16, PREFIX THE PART DESIGNATION WITH THE SUBASSEMBLY DESIGNATION.

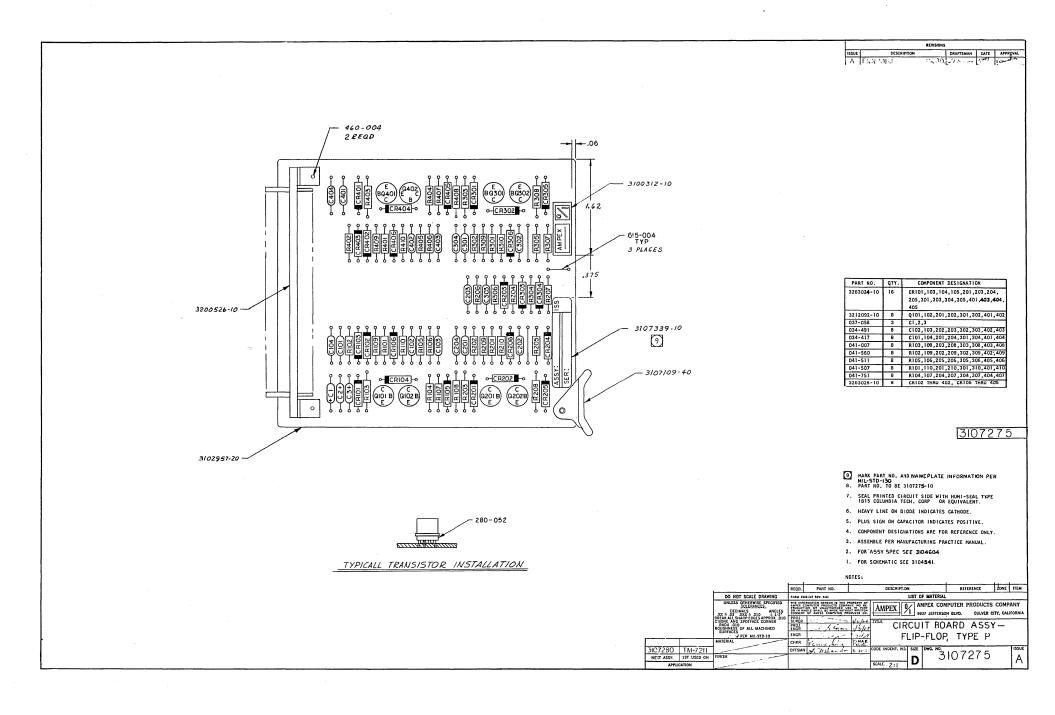
3. ALL DIODES TO BE 3263024-10.

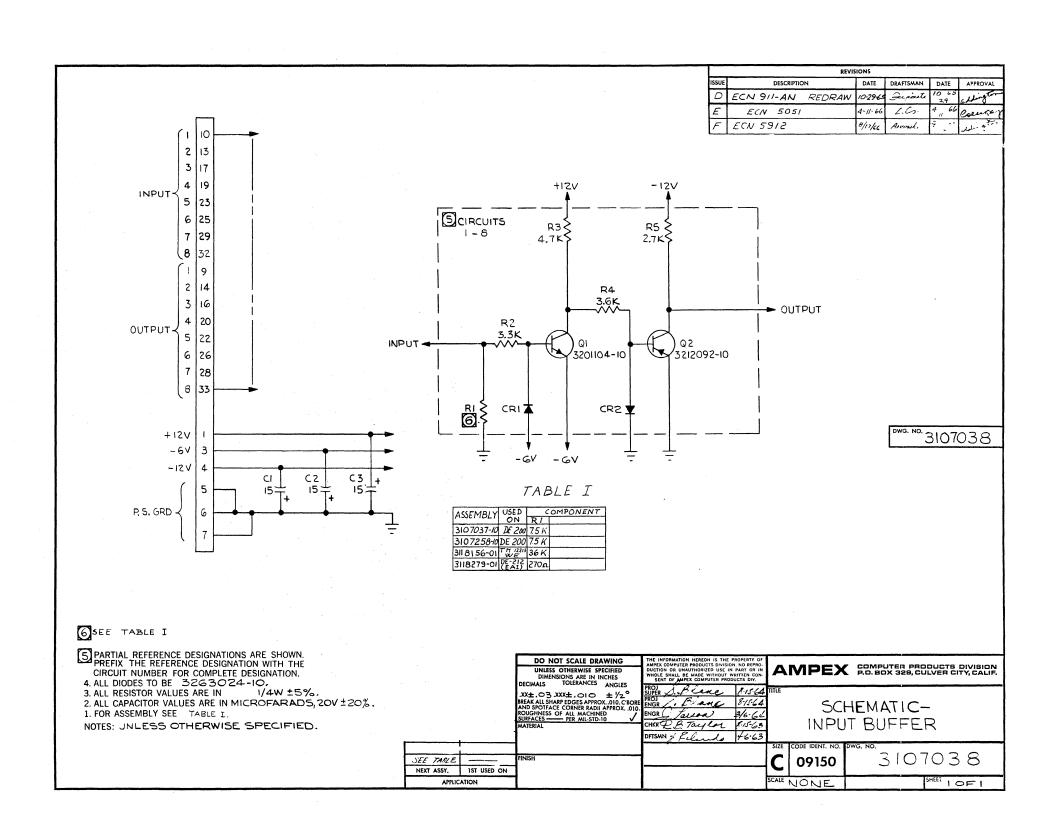
2. ALL CAPACITORS IN MICROPARADS.

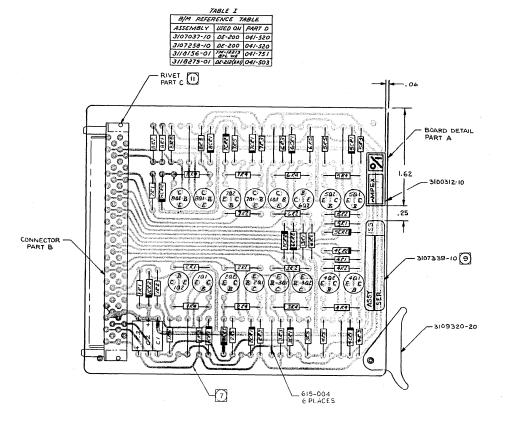
1. ALL RESISTORS IN GHMS ±5%,1/4 W.

NOTES: UNLESS OTHERWISE SPECIFIED

	REQO.	PART NO.		DESCRIPTION	REFERENCE	ZONE ITEM
DO NOT SCALE DRAWING	FORM 26	02-107 REV. 9-61		LIST OF M.	ATERIAL	
UNLESS OTHERWISE SPECIFIED TOLERANCES. DECIMALS XX ± .03 .XXX ± .010 ± .1.7 BREAK ALL SHAPP EOGS APPROX .0	PROJECT	DRMATION HEREON IS THE POPULET PRODUCTS COMP- TION OR UNAUTHORIZED U HOLE SHALL BE MADE WITH F OF AMPEX COMPUTER, PR	ROPERTY OF ANY. NO RE- SE IN PART OUT WRITTEN ODUCTS CO.	HAMPEX II %	EX COMPUTER PRODUCTS DEFFERSON BLVD. CULVER	S COMPANY CITY, CALIFORNIA
C'BORE AND SPOTFACE CORNER RADII - 010 ROUGHNESS OF ALL MACHINED SURFACES PER MIL-STD-10	SUPER PROJ ENGR ENGR	Il Amel	Pyet	SCH FLIP-FI	EMATIC, LOP. TYPE P	
3109115 TM-4122 MATERIAL	CHKR	W hare	1.5.4			
3102970 TM-4111	DFTSMN	1 L Louis	9,0€2	CODE INDENT. NO. SIZE DW	G. NO.	ISSUE
NEXT ASSY. 1ST USED ON FINISH APPLICATION		7103 - 252	2	SCALE NONE D	3104541	E







-280-052

TYPICAL TRANSISTOR INSTALLATION

	REVISION	3		
ISSUE	DESCRIPTION	DRAFTSMAN	DATE	APPROVAL
Á	E N 3., 31 157,615	A. 5 p. 2.	2.	2,100
25	ECH 911-76	Cotum	1	1/13/1
C	ECN 911-AN PROD	O Richarder	3.3.64	Jayley
D	ECN 5051	S. Arenoli	1/11/66	course
E	ECN 59/2	Aronali	9/0/44	

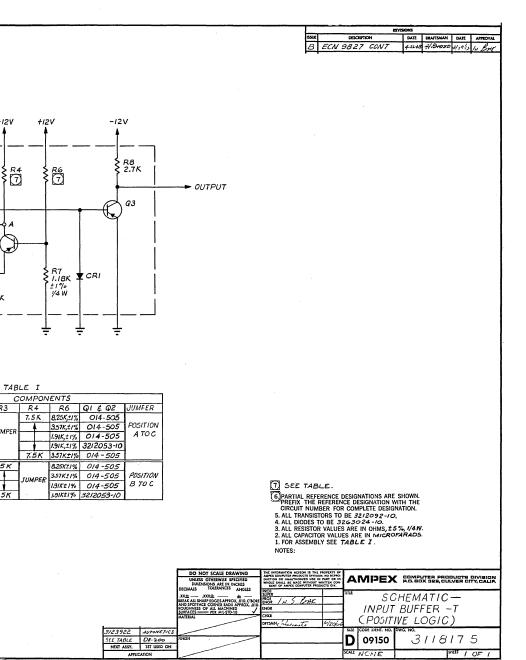
	PART NO.	REFERENCE DESIGNATION
	3201/04 -/0	IQI, THEU BQI
	32/2092-10	IQZ THEU BOZ
	37 : 7024-10	ICKI THEU BOTI, ICEZ THEU BLEE
	037-990	C 1/2/3
	041-407	IR2 THRU BE?
	041-442	IRS THEU 8RS
	091-412	IRR THEU BES
0	PART D	IRI THRU 8EI
_	041.571	IR 4 THRU 8R4

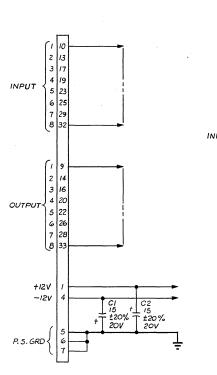
REFERENCE

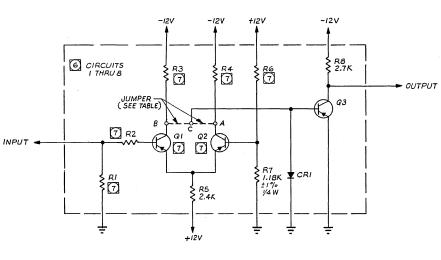
	REQD. PART NO.	DESCRIPTION REFERENCE ZONE ITEM
DO NOT SCALE DRAWING	FORM 2602-107 REV. 9 61	LIST OF MATERIAL
UNLESS OTHERWISE SPECIFIED TOLERANGES DECIMALS ANGLES XX ± .03 XXX ± .00 ± 1 2′ BREAK ALL SHARP EOGES APPROX010	THE INFORMATION HEREON IS THE PAPER COMPUTER PRODUCTS COMPPRODUCTION OR UNAUTHORIZED US OR IN WHOLE SHALL BE MADE WITHOUT CONSENT OF AMPLE COMPUTER PROPURED TO THE PROPURED TO THE COMPUTER PROPUTER TO THE COMPUTER PROPURED TO THE COMPUTER PROPURED TO THE COMPUTER PROPURED TO THE COMPUTER PROPURED TO THE COMPUTER PROPUTE	AMPEX OMPUTER PRODUCTS COMPANY OCCUPATION OF THE PRODUCTS COMPANY 9937 JEFFERSON BLVD. CULVER CITY, CALIFORNIA
C'BORE AND SPOTFACE CORNER RADII -010 ROUGHNESS OF ALL MACHINED	SUPER PROJ ENGR	CIRCUIT BOARD ASSEMBLY-
CIOTO37 TM7211 SURFACES PER MIL-STD-10	ENGR & June	INPUT BUFFER
010725 : 7447218 MATERIAL	CHKR	1735 31
10	DETSMN - Winner	+-ZZ-CODE INDENT. NO SIZE DWG. NO. ISSUE
NEXT ASSY. IST USED ON FINISH		D 31.7031 E
APPLICATION		SCALE C

- INSTALL PART D PER TABLE I
- [] RIVET PART C USED ONLY WITH 3200526-10.
- 10. SEAL PRINTED CIRCUIT SIDE ONLY WITH HUMI-SEAL TYPE 1815, COLUMBIA TECH CORP OR EQUIV.
- MARK PART NO AND NAMEPLATE INFOPMATION PER MIL-STD-130.
- B. PART NO. TO BE AS SHOWN ON TABLE I.
- 7 CIRCUITEY ON FARSIDE.
- 6. PLUS SIGN ON CAPACITIE INDICALLS POSITIVE.
- 5. COMPONENT DESIGNATIONS ARE FOR REFLICENCE ONLY.
- 4. ASSEMBLE PER MANUFACTURING PRACTICE MANUAL.
- 3. HEAVY LINE ON DIODE INDICATES CATHODE.
- Z. FOR PRODUCT SPECIFICITION SEE 3107039.
- 1. FOR SCHEMATIC SEE 7107038.

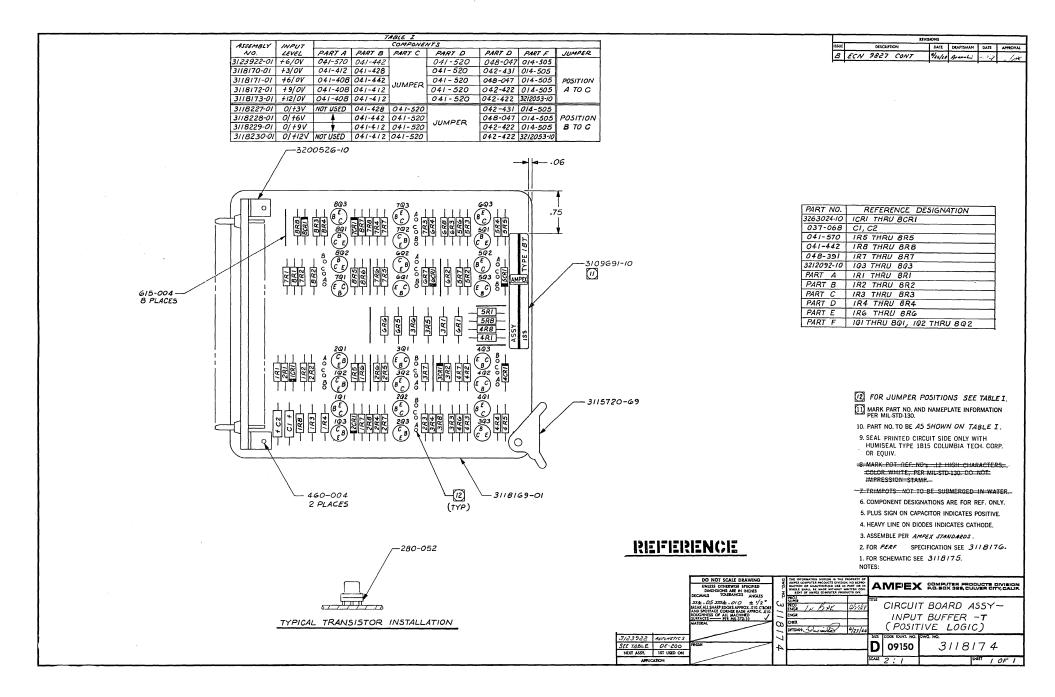
NOTES: UNLESS OTHERWISE SPECIFIED

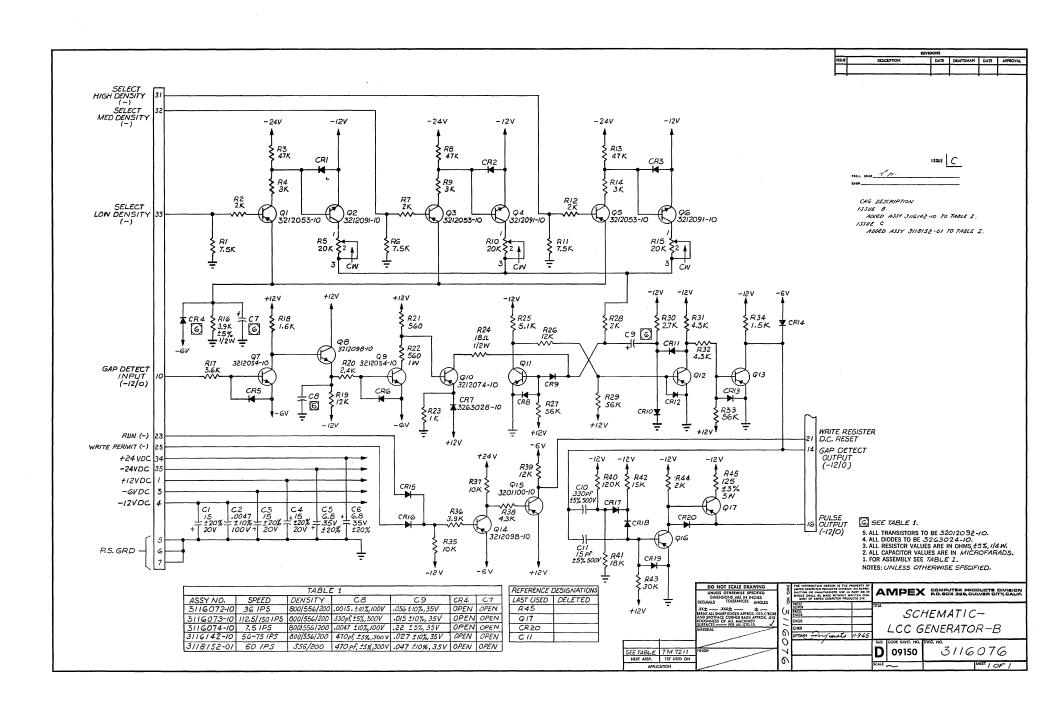


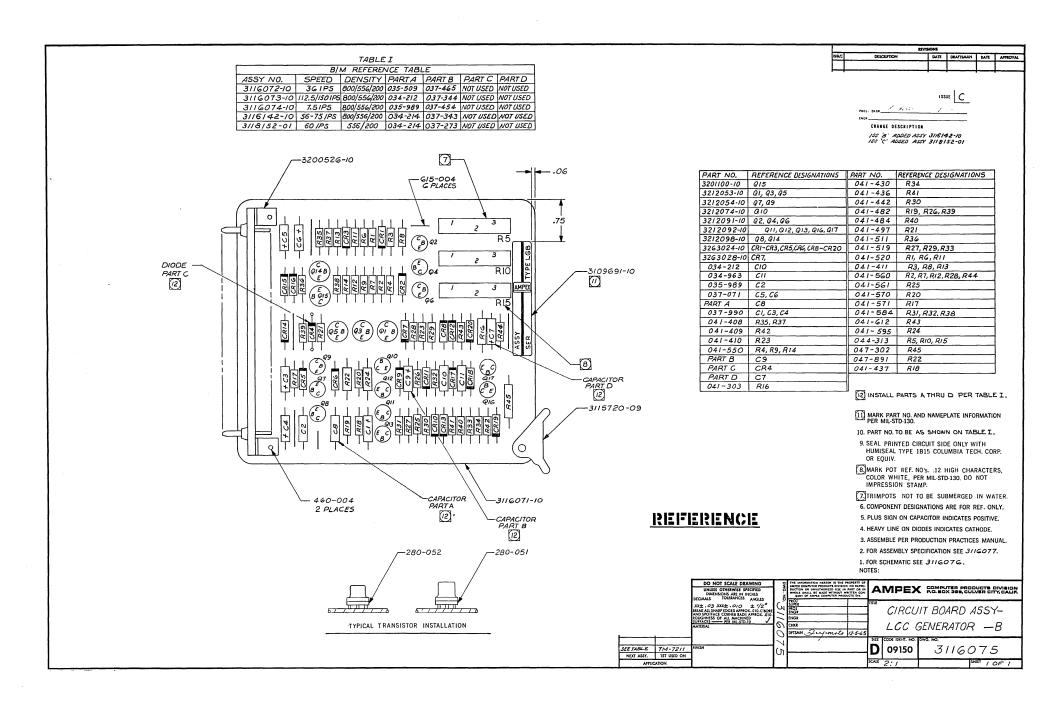


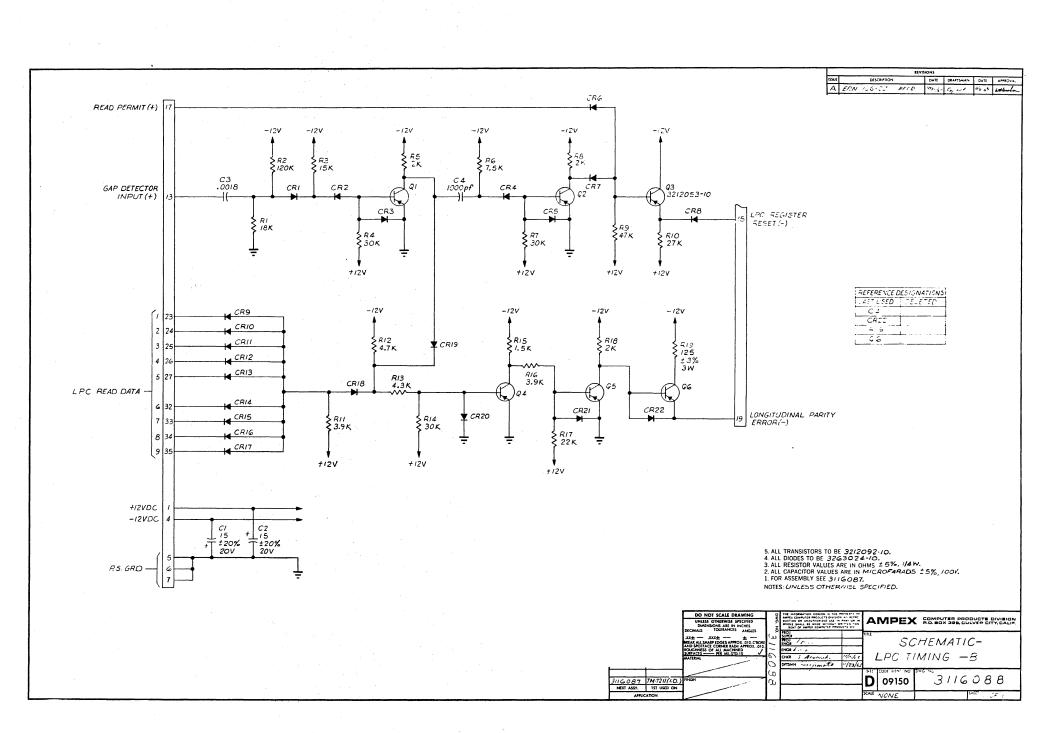


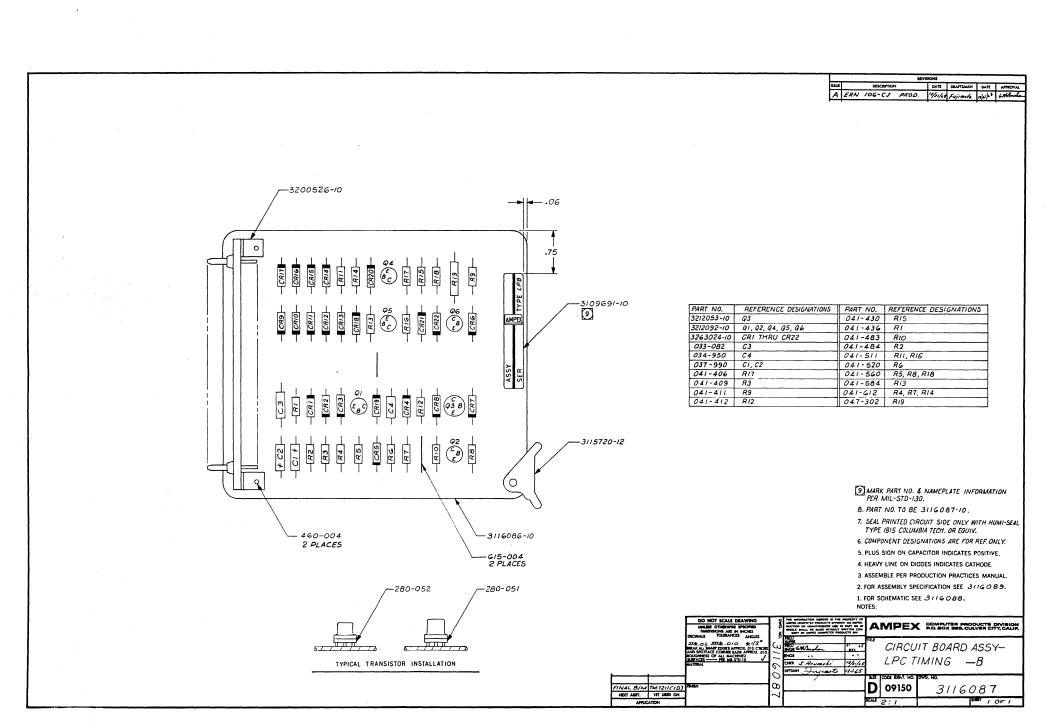
ASSEMBLY	INPUT		COMPONENTS						
NO.	LEVEL	RI	R2	R3	R4	R6	Q1 £ Q2	JUMFER	
3118170-01	+3/01	4.7K	470 L		7.5 K	8.25K,±1%	014-505		
3118171-01	+6/0V	10 K	2.7K	JUMPER	A	3.57K,±1%	014-505	POSITION	
3118172-01	+9/0V	10K	4.7 K	JUMPEN		1.91K,±1%	014-505	ATOC	
3118173-01	+12/01	IOK	4.7K		,	1.91K,±1%	3212053-10		
3123922-01	+6/0V	2.4 K	2.7K	l	7.5K	3.57K±1%	014 - 505		
3/18227-01	0/+31	OPEN	470 SL	7.5 K		8.25K±1%	014-505		
3118228-01	0/+61	-	2.7K		JUMPER	3.57K±1%	014-505	POSITION	
3118229-01	0/+91		4.7K		JUMPEN	1.91K±1%	014-505	<i>B 70</i> C	
3/18230-0/	0/+121	OPEN	4.7K	7.5K		1.91K±1%	3212053-10	1	

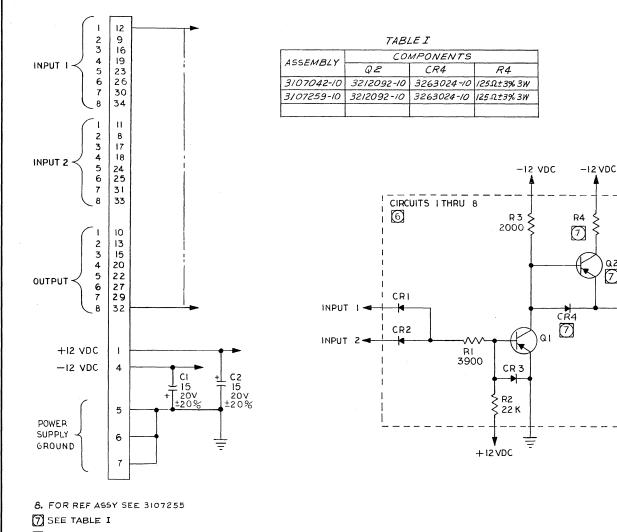












[6] PARTIAL REFERENCE DESIGNATIONS ARE SHOWN, PREFIX THE DESIGNATING NUMBER WITH THE CIRCUIT NUMBER FOR COMPLETE DESIGNATION.

5. ALL DIODES TO BE 3263024-10.

4. ALL TRANSISTORS TO BE 3212092-10.

3. ALL RESISTOR VALUES ARE IN OHMS, 1/4 W,±5%.

2.ALL CAPACITOR VALUES ARÉ IN MICROFARADS.

I. FOR ASSEMBLY SEE TABLE I

NOTES: UNLESS OTHERWISE SPECIFIED

	REQD.	PART NO.		DESCRIPTION	1		REFERENCE	ZONE	ITEM
DO NOT SCALE DE	RAWING FORM 25	502-107 REV. 9-61			LIST OF	MATERIAL			
UNLESS OTHERWISE TOLERANCE DECIMALS .XX ± .03 .XXX ± .010	ANGLES OR IN W	ORMATION HEREON IS THE P COMPUTER PRODUCTS COMPA TION OR UNAUTHORIZED US MOLE SHALL BE MADE WITHO T OF AMPEX COMPUTER PRO	ROPERTY OF INY, NO RE- IE IN PART UT WRITTEN DDUCTS CO.	AMPEX 0	1	PEX COMP JEFFERSON	UTER PRODUCTS BLVD. CULVER C		
BREAK ALL SHARP EDGES A C'BORE AND SPOTFACE O	ORNER SUPER	- Blan	3/6/0	TITLE					
3107042 TM-5 ROUGHNESS OF ALL MAC	HINED PROJ	2 Pin-	8/24/		SCHE	MATIC	2 —		
310 7259 TM 7211 SURFACES ✓ PER MIL-STE	0-10 ENGR	down-	3,		T DU	± DO			
3107042 TM 7211 MATERIAL	CHKR	Lutres	8.15.63		TPU	I DR	IVER		
3107259 TM7212	DFTSM	N B, Herr	4-22-63	CODE INDENT, NO.	SIZE D	WG. NO.			ISSUE
NEXT ASSY. 1ST USED ON FINISH						7	3107043		F
APPLICATION				SCALE NONE			7101043		_

REVISIONS

DRAFTSMAN DATE APPROVAL

2-26-68

Bravo 3-12-68 alling to.

Soulery

H Braw

PROD. A Ribando

DESCRIPTION

A ECN 800-54 DEV. PRO.(x-c)

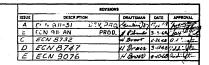
B ECN 911-31

C ECN 911-AN

D ECN 8732

E ECN 8747

→OUTPUT



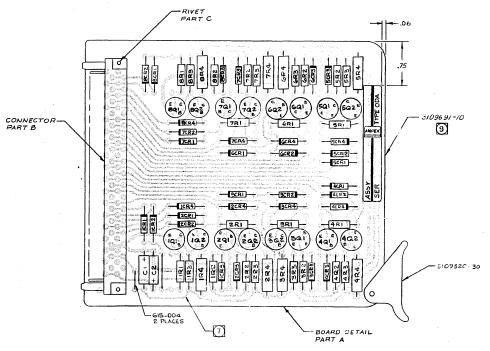


TABLE I

ASSEMBLY	PART A	PART B	PART C	PART D	PART E	PART F
3107042-10	3107041-10	3200504-10	NOT USED	3212092-10	3263024-10	047-302
3107259-10	3107041-20	3200526-10	460-004	3212092-10	3263024-10	047-302

(I) INSTALL PART A THRU F PER TABLE I

SEAL PRINTED CIRCUIT SIDE ONLY WITH HUMI-SEAL TYPE 1815, COLUMBIA TECH CORP OR EQUIV.

MARK PART NO AND NAMEPLATE INFORMATION PER MIL-STD-130.

& PART NO. TO BE AS SHOWN IN BILL OF MATERIAL

& PLUS SIGN ON CAPACITOR INDICATES POSITIVE

5 COMPONENT DESIGNATIONS ARE FOR REFERENCE ONLY

4. ASSEMBLE PER AMPEX STANDARDS

3. HEAVY LINE ON DIODE INDICATES CATHODE

2. FOR PERF SPECIFICATION SEE 3101044

I. FOR SCHEMATIC SEE 3107043

NOTES: UNLESS OTHERWISE SPECIFIED

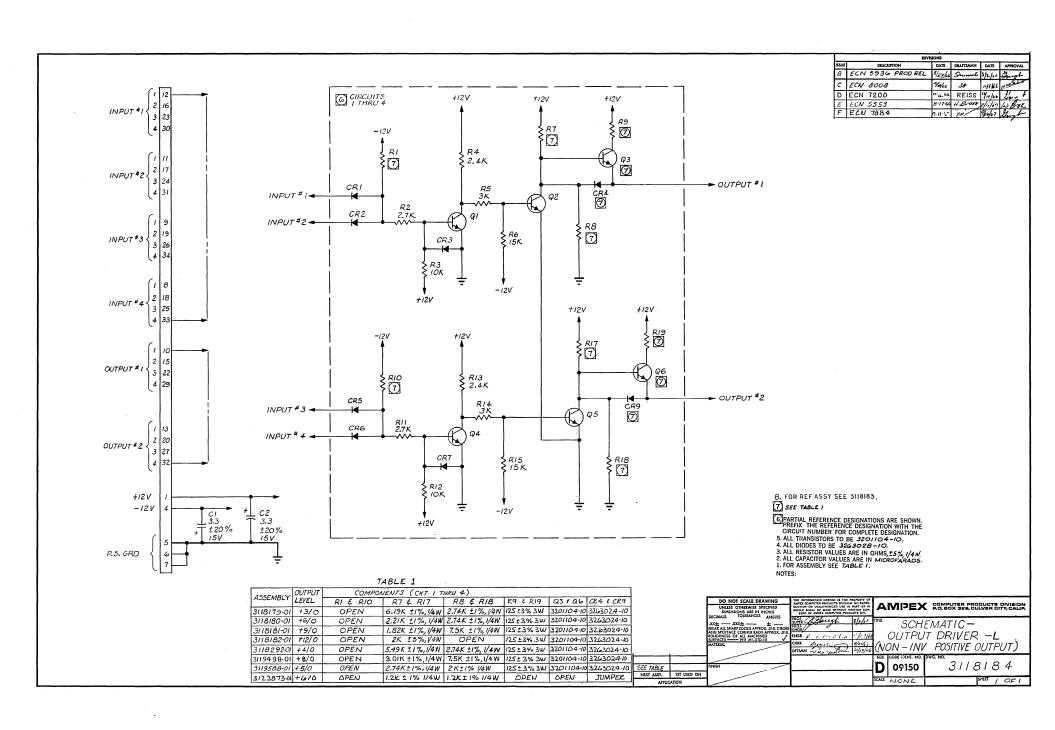
REFERENCE

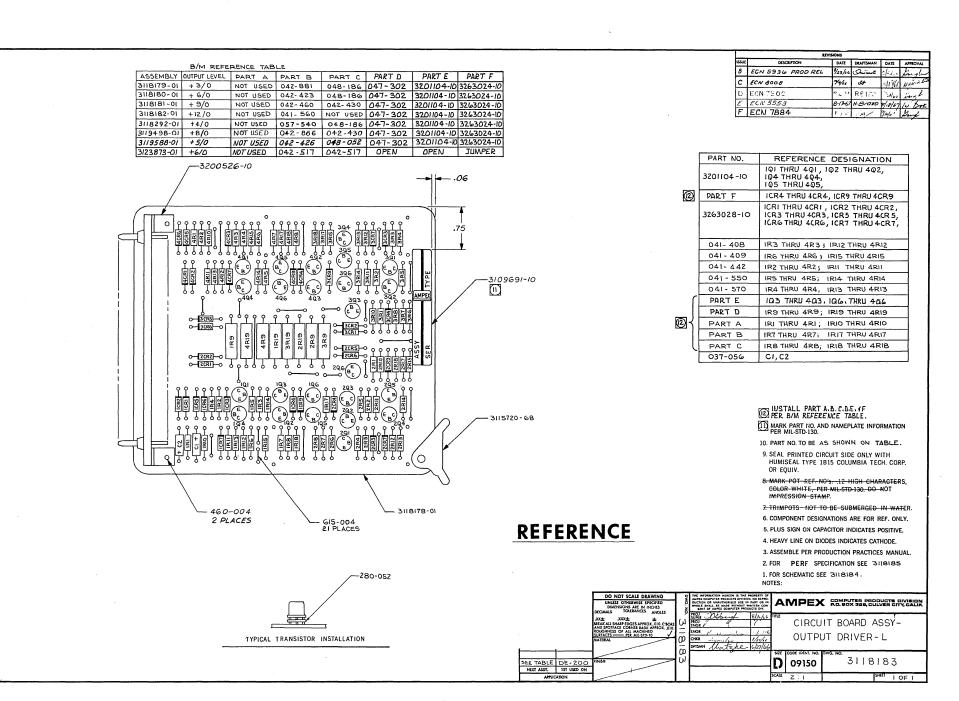


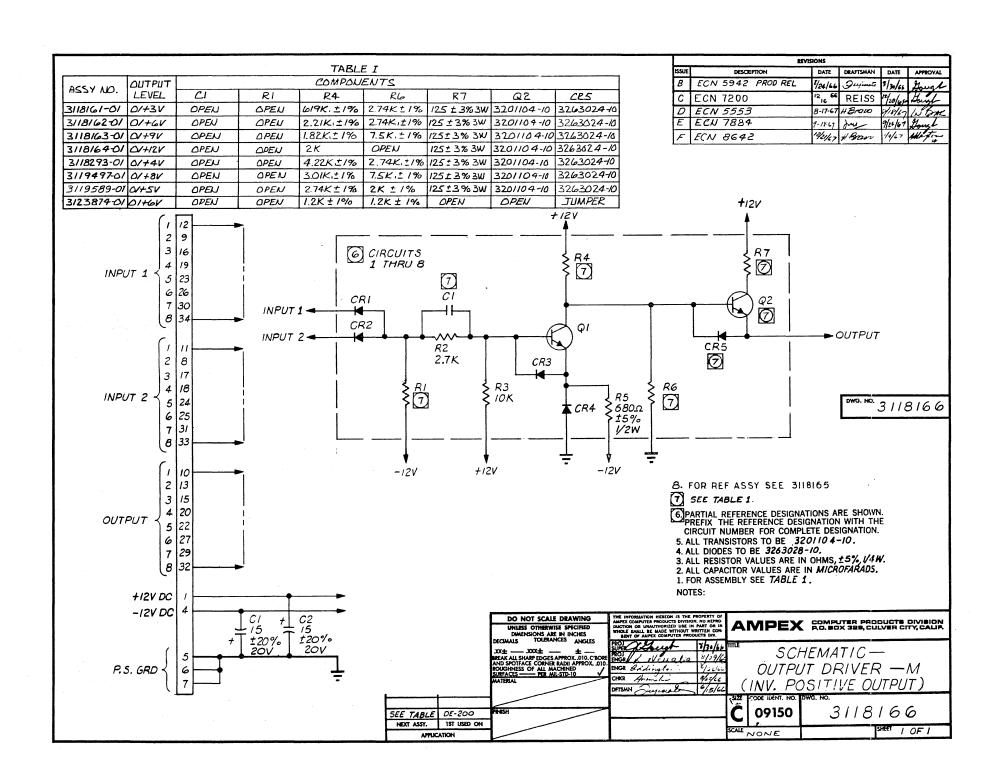
TYPICAL	TRANSISTOR	INSTALLATION

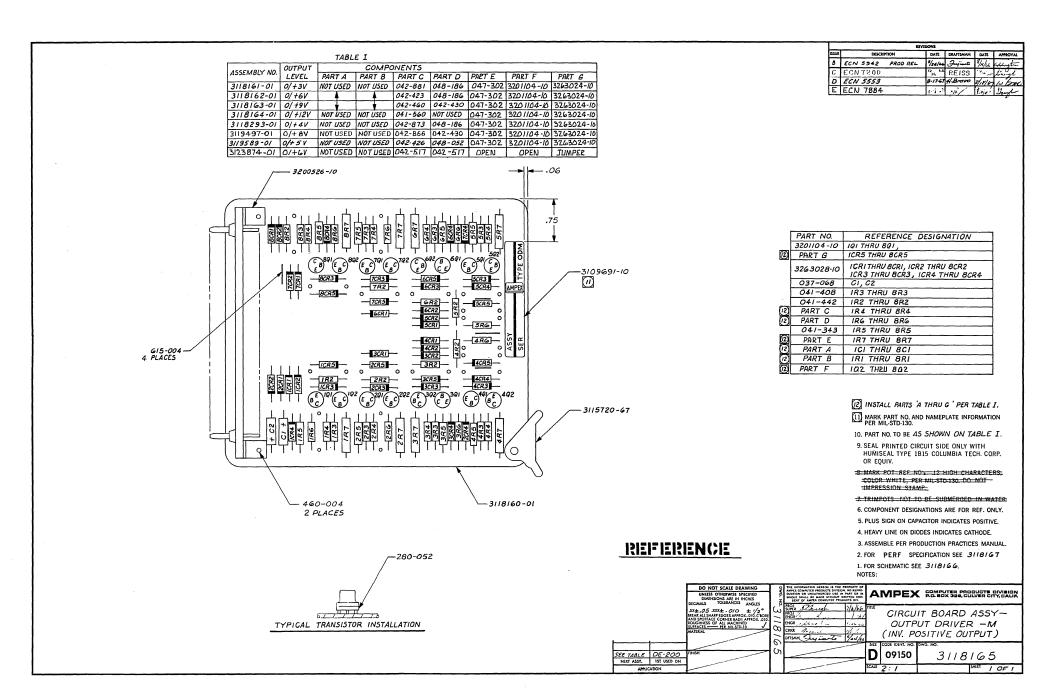
PART NO.	REFERENCE DESIGNATION
3212092-10	1Q1 THRU BQ1
3263024-10	ICRI THRU BCRI, ICRZ THRU BCR2, ICR3 THRU BCR3
037-990	C1, C2
041-406	1R2 THRU BR2 .
041- 511	1R1 THRU BR1
041-560	IR3 THRU BR3
FART F	1R4 THRU 8R4
PART D	IQ2 THRU 8Q2
PART E	ICR4 THRU OCR4

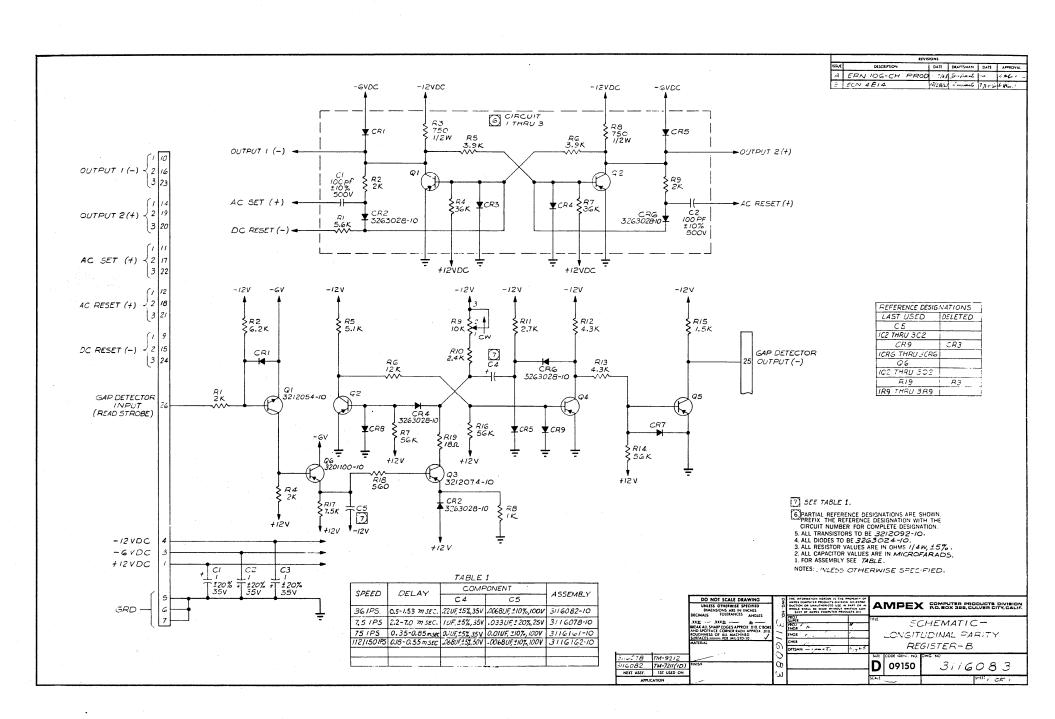
			REQD.	PART NO.		DESCRIPTION	REFERENCE	ZONE	ITEM
		DO NOT SCALE DRAWING	FORM 20	102-107 REV. 941		LIST OF MATERIA	1		
		UNLESS OTHERWISE SPECIFIED IOLERANCES DECIMALS ANGLES XX ± .03 XXX ± .010 ± 1/2*	PRODUC OR IN IN COMBEN	ORMATION HEREON IS THE P COMPUTER PRODUCTS COMP TION OR UNAUTHORIZED UI HOLE SMALL BE MADE WITHOUT TOP AMPEX COMPUTER PR	ME IN PART	AMPEX O AMPEX CO	MPUTER PRODUCTS ON BLVD. CULVER CT		
		BREAK ALL SHARP EDGES APPROX .010	PROJ	1. Blan	3/64	TITLE		<u> </u>	
3107042	TM7211	RADII .010 ROUGHNESS OF ALL MACHINED	PROJ ENGR	Pliane	Hists	CIRCUIT BO	DARD ASSEM	BIY	
3107259	TM7211	SURFACES PER MIL-STD-10	ENGR	17	\$/6/4	ν			
3107259	TM7212	MATERIAL	CHKR	The Enge	51500	001701	DRIVER		
3107042	TMS		DFTSM	B.Hom	4.2363	CODE INDENT. NO. SIZE DWG. NO.			ISSUE
NEXT ASSY.	1ST USED ON	FINISH				D	3107255		מו
APPLICA	ATION					SCUE 2/1	3107233)	Ι .







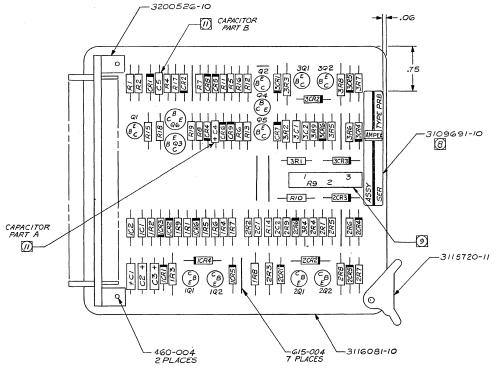




REYISIONS							
ISSUÉ	DESCRIPTION	DRAFTSMAN	DATE	APPROVAL			
A	ECN 4814 PRODREL	Aromaki	11/16/65	6. No. 1			

BI	

B/M REFERENCE TABLE							
ASSY NO.	SPEED	DELAY	PART A	PART B			
3//6082-/0	36 IPS	0.5-1.53 msec.	C37-454	030-195			
3//6078-10	7.5 IPS	2.2-7.0 mSEC.	037-455	030-294			
3116161-10	75 IPS	.3585 m SEC.	037-453	035-219			
3116162-10	112/150 IPS	.1855 m SEC.	033-100	035-568			



CAST AVO	DESCRIPTION DESIGNATIONS
PART NO	REFERENCE DESIGNATIONS
3201100-10	Q6
3212074-10	Q3
3212054-10	QI
3212092-10	Q2,Q4,Q5, IQI, IQ2, 2Q1, 2Q2, 3Q1, 3Q2
706 3004 10	CRI,CR5,CR7, ICRI,2CRI,3CRI,ICR3,2CR3,3CR3,
3263024-10	ICR4, 2CR4, 3CR4, ICR5, 2CR5, 3CR5, CR8, CR9
3263028-10	CR2, CR4,CR6,ICR2,2CR2,3CR2,ICR6,2CR6,3CR6
PART A	C4
034-417	ICI, IC2, 2CI, 2C2, 3CI, 3C2
037-058	CI, C2, C3
041-007	IR3, 2R3, 3R3, IR8,2R8, 3R8
041-410	R8
041-430	RI5
041-442	RII
041-482	RG
041-497	R18
041-507	IRI, 2RI, 3RI
041-511	IR5, 2R5,3R5, IRG,2RG,3RG
041-519	R7, R14,RIG
041-538	R2
041-560	RI, R4, IR2, 2R2, 3R2, IR9, 2R9, 3R9
041-561	R5
041-570	RIO
041-584	RI2, RI3
041-751	IR4, 2R4,3R4,IR7, 2R7, 3R7
044-197	R9
041 - 520	RI7
041-547	RI9
PART B	C5

3116100

REFERENCE



TYPICAL TRANSISTOR INSTALLATION

MINSTALL PT. 'A' & B' PER TABLE 1.

10. SEAL PRINTED CIRCUIT SIDE ONLY WITH HUMI-SEAL TYPE 1815, COLUMBIA TECH CORP OF EQUIV.

10. TRIMPOT NOT TO BE SUBMERGED IN WATER.

[3] IRIMPO NOTO BE SUBMERGED IN [BMARK PART NO, AND NAMEPLATE INFORMATION PER MILSTO-130.

PART NO, TO BE AS SHOWN ON B/M, 6. COMPONENT DESIGNATIONS ARE FOR REF. ONLY.

5. PLUS SIGN ON CAPACITOR INDICATES POSITIVE.

4. HEAVY LINE ON DIODES INDICATES CATHODE.

3. ASSEMBLE PER PRODUCTION PRACTICES MANUAL.

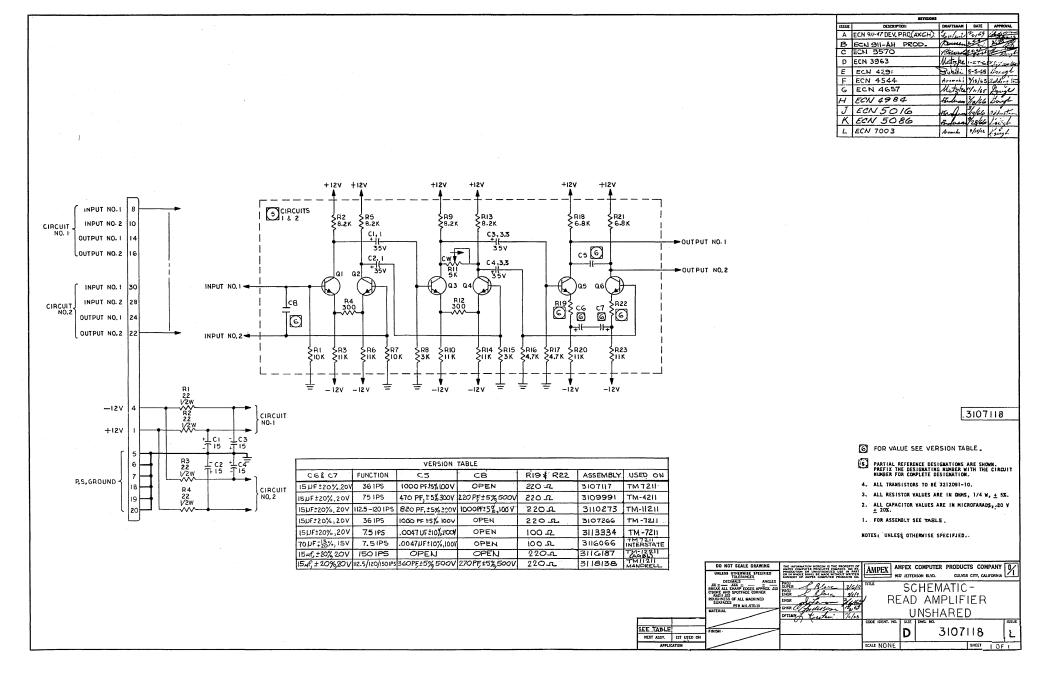
2. FOR ASSEMBLY SPECIFICATION SEE 3/16084.

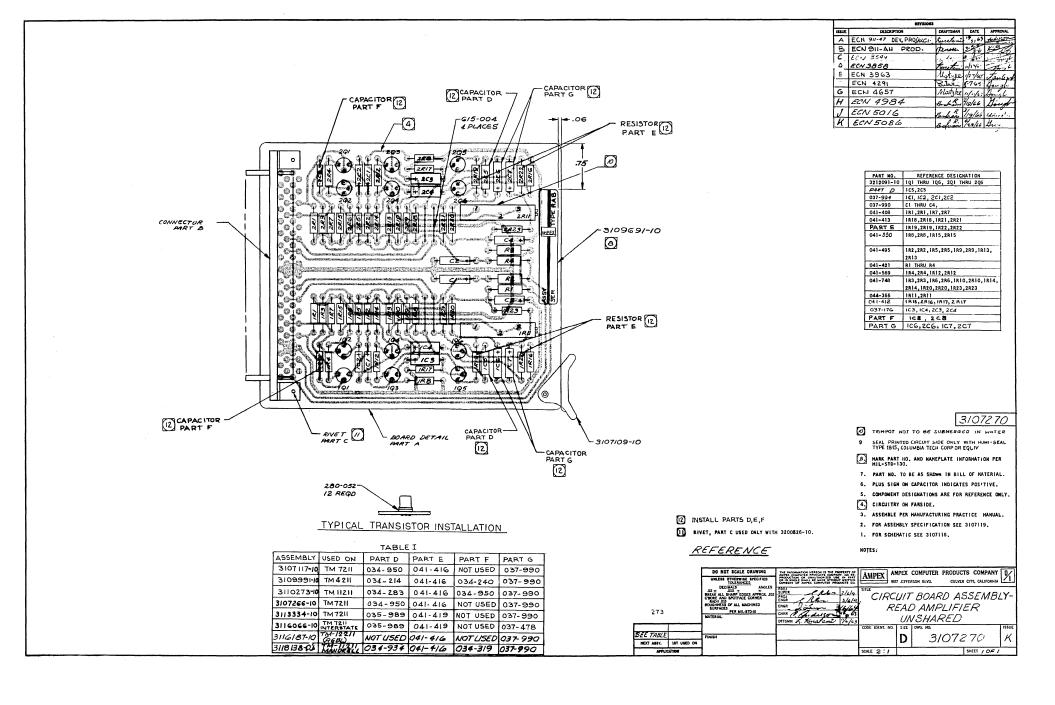
1. FOR SCHEMATIC SEE 3/16083.

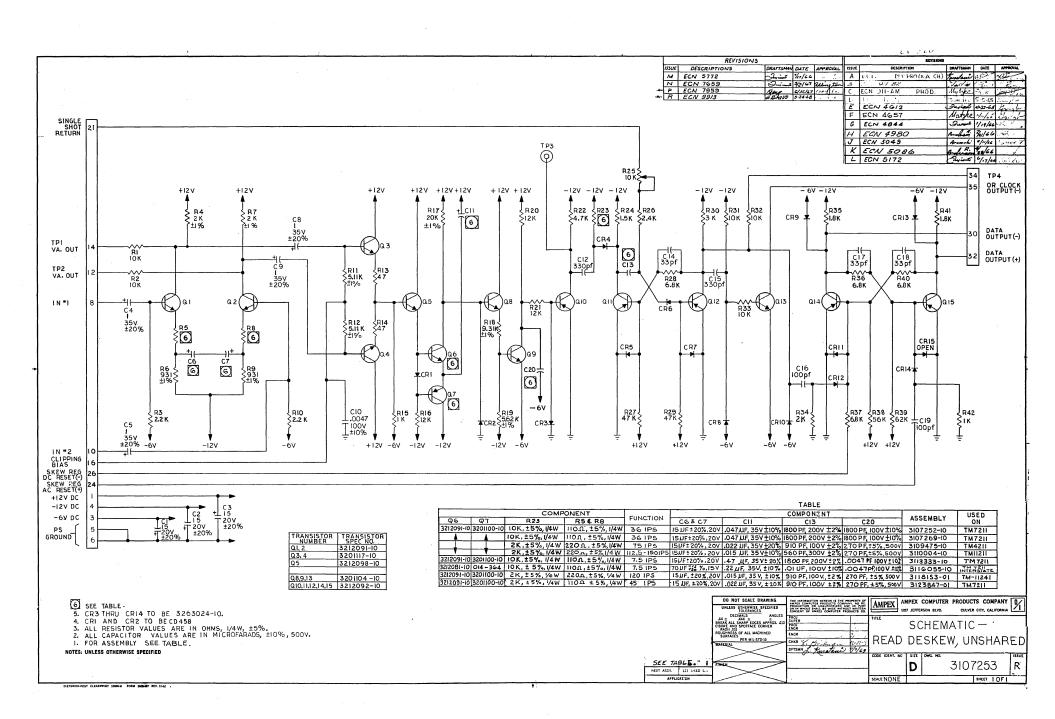
1. FOR SCHEMATIC SEE 3/16083.

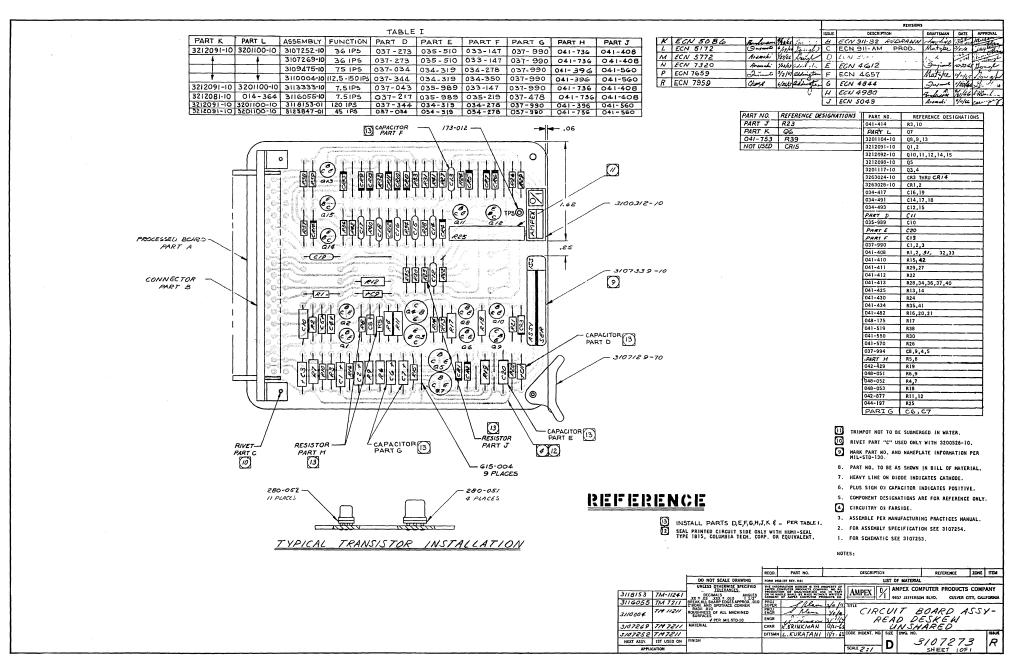
NOTES: UNLESS OTHERWISE SPECIFIED.

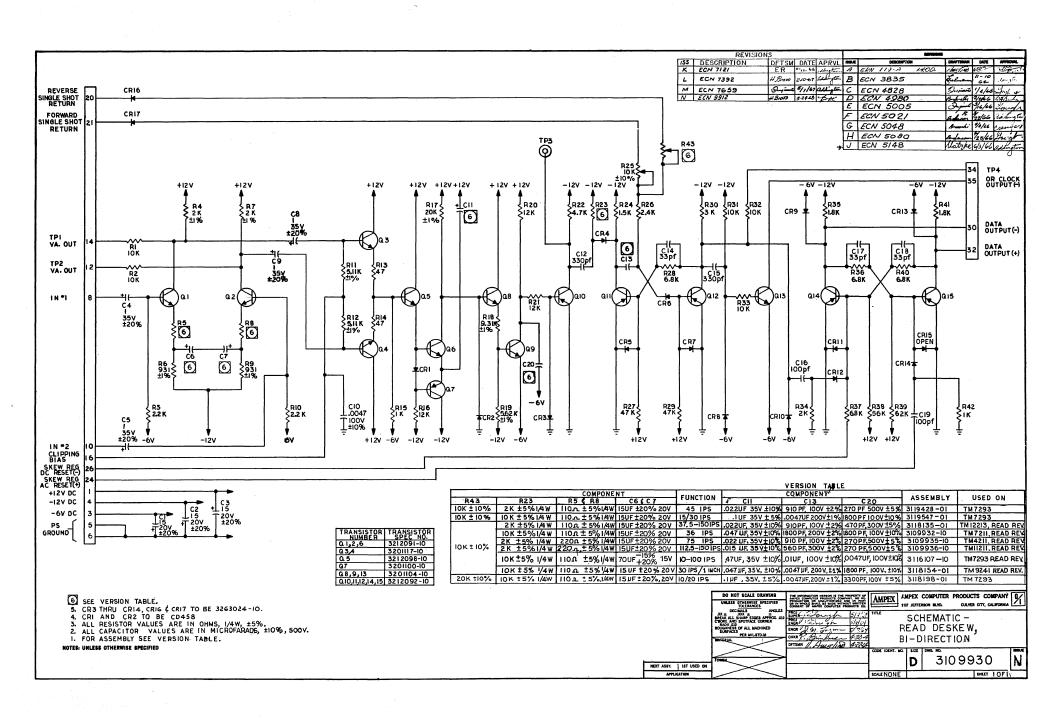
DO NOT SCALE DRAWING UNLESS OTHERWISE SPECIFIED TOLERANCES	THE INFORMATION MEREON IS THE PROPERTY OF AMPEX COMPUTER PRODUCTS COMPANY, NO. RE-PRODUCTION OR UNAUTHORIZED USE. IN PART OR IN WHOLE SHALL BE MADE WITHOUT WRITTEN CONSENT OF AMPEX COMPUTER PRODUCTS CO.	AMPEX COMPUTER PRODUCTS COMPANY 1937 JEFFERSON BLVD. CULVER CITY, CALIFORNIA
C'BORE AND SPOTFACE CORNER RADII JUD	PROJ SUPER PROJ ENGR	CIRCUIT BOARD ASSY-
SURFACES PER MIL-STD-10 MATERIAL	ENGR addination " 455 CHERACON Ed. DETERM SINGUISTO 10.865	LONGITUDINAL PARITY REGISTER-B
SEE TABLE TM-7211(1D) FINISH NEXT ASSY. 1ST USED ON		CODE IDENT. NO. SIZE DING. NO. ISSUE A
APPLICATION		SCALE 2:1 SHEET / OF 1

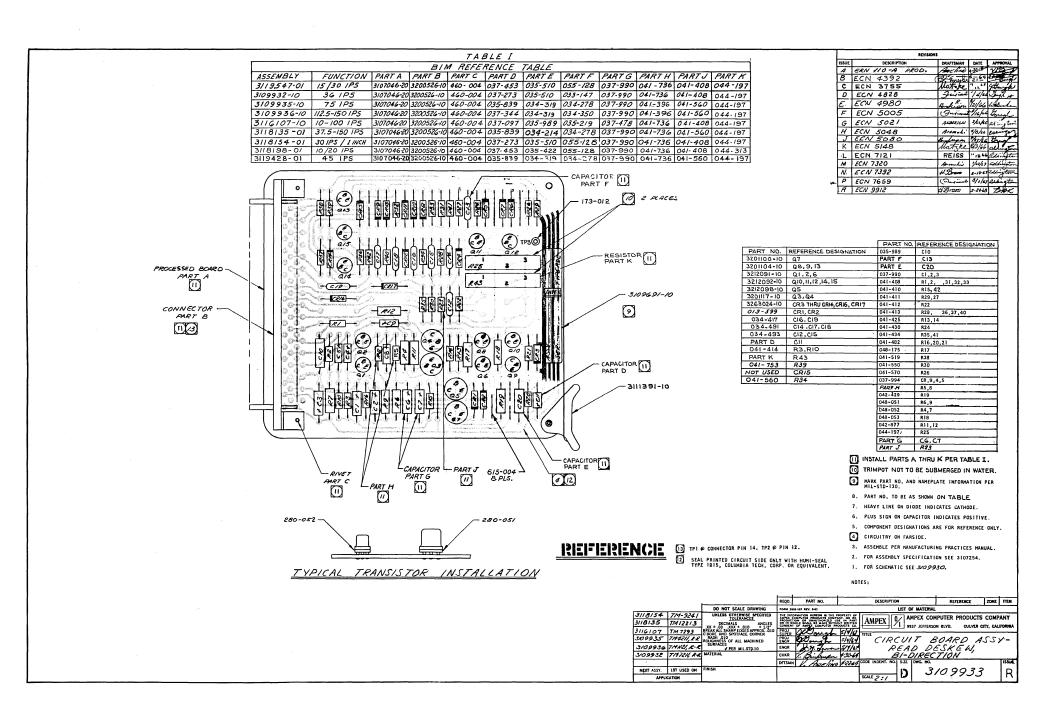


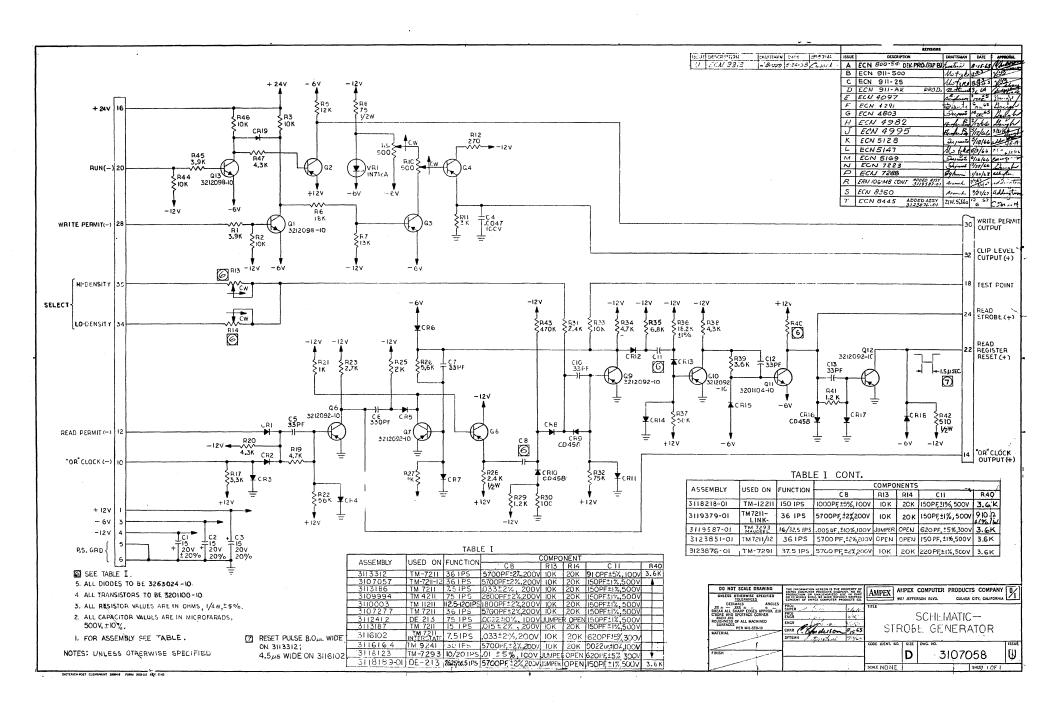


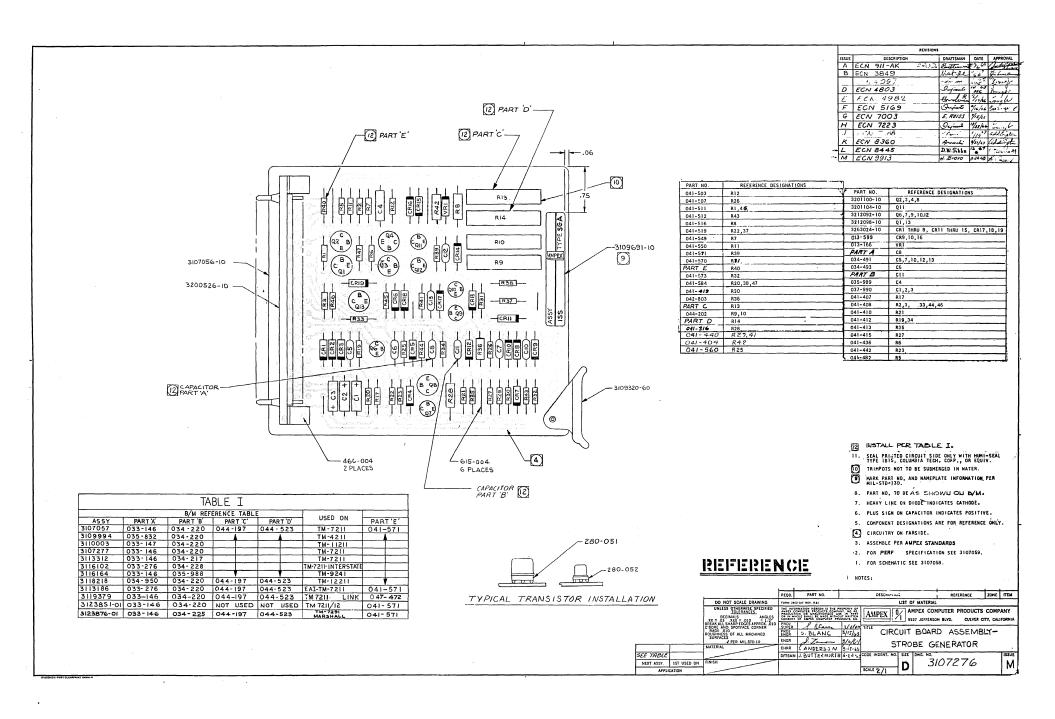


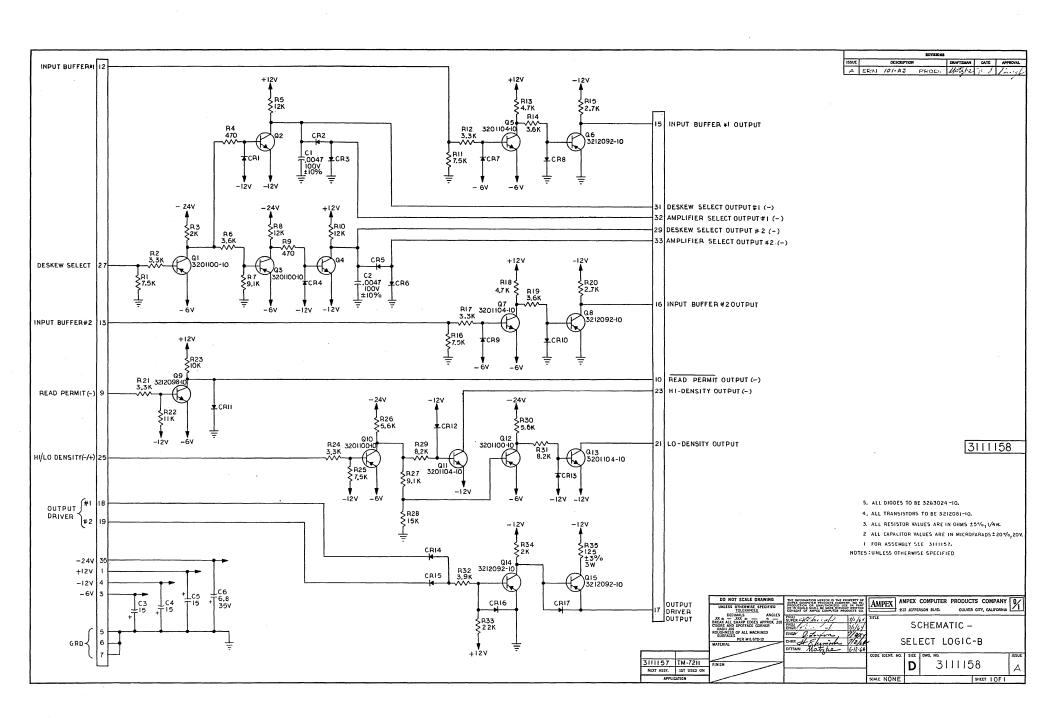


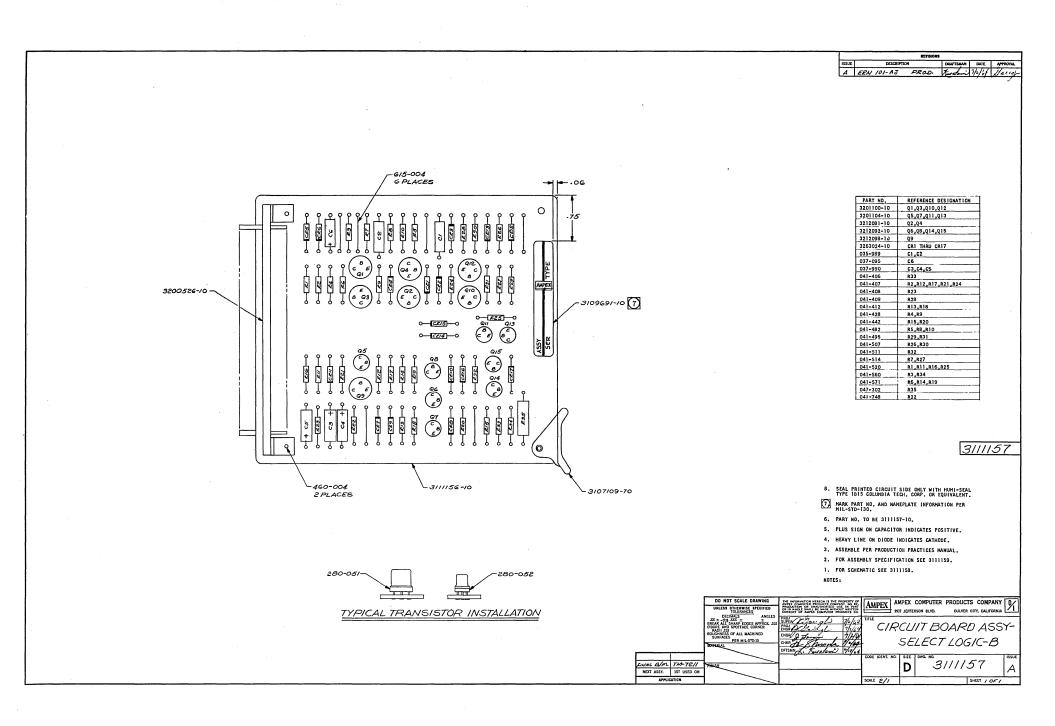


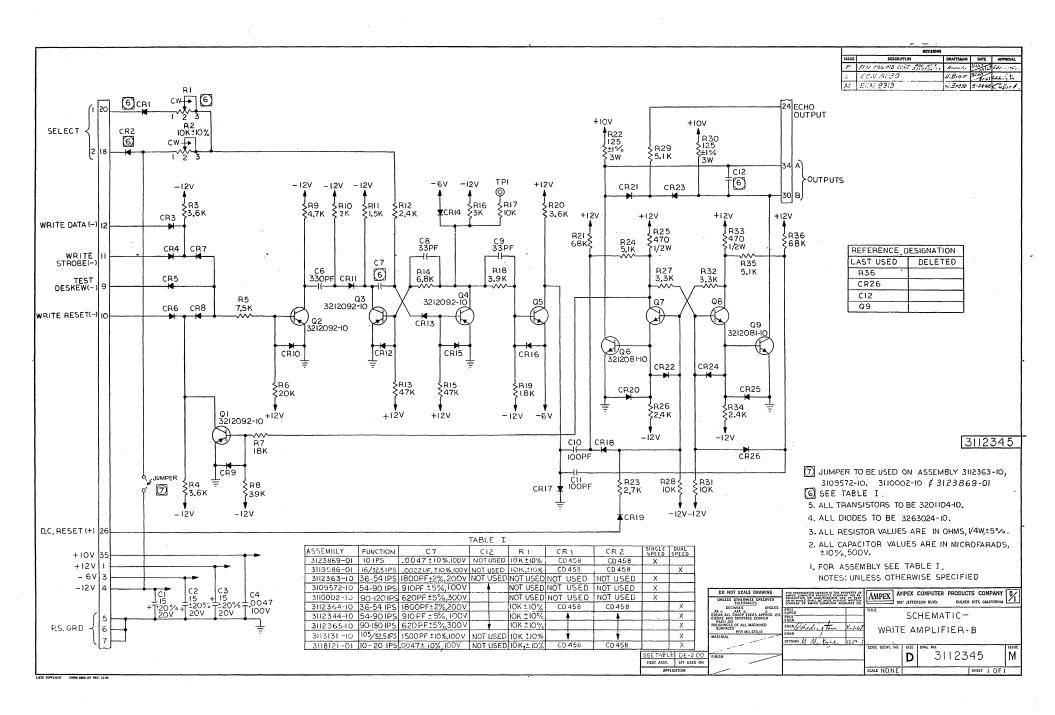


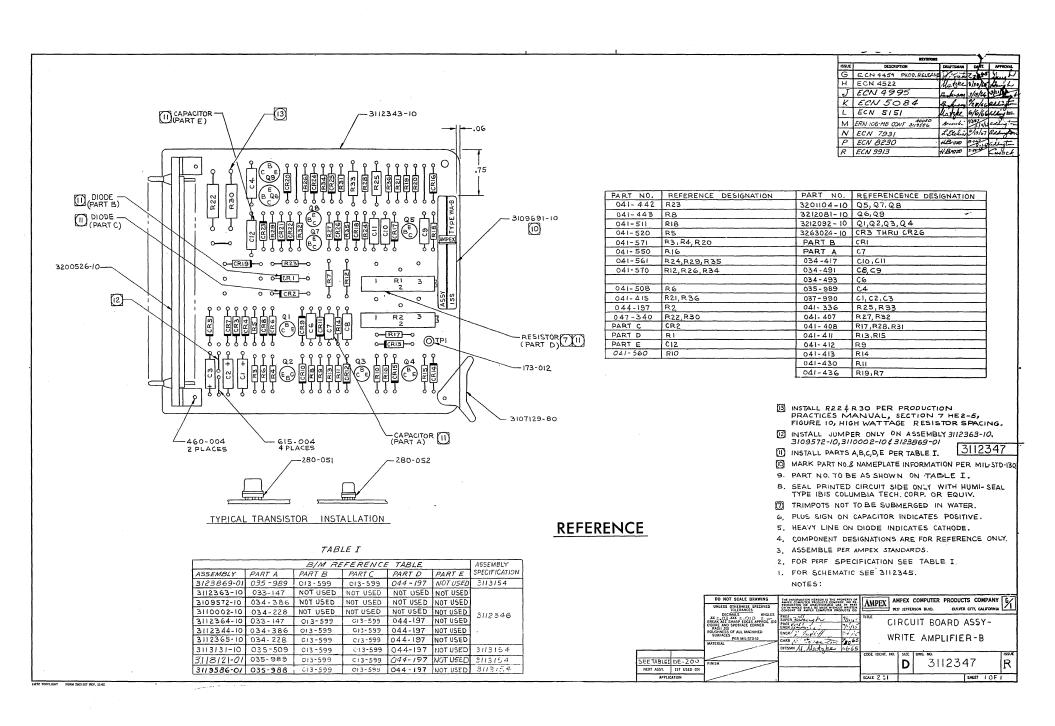


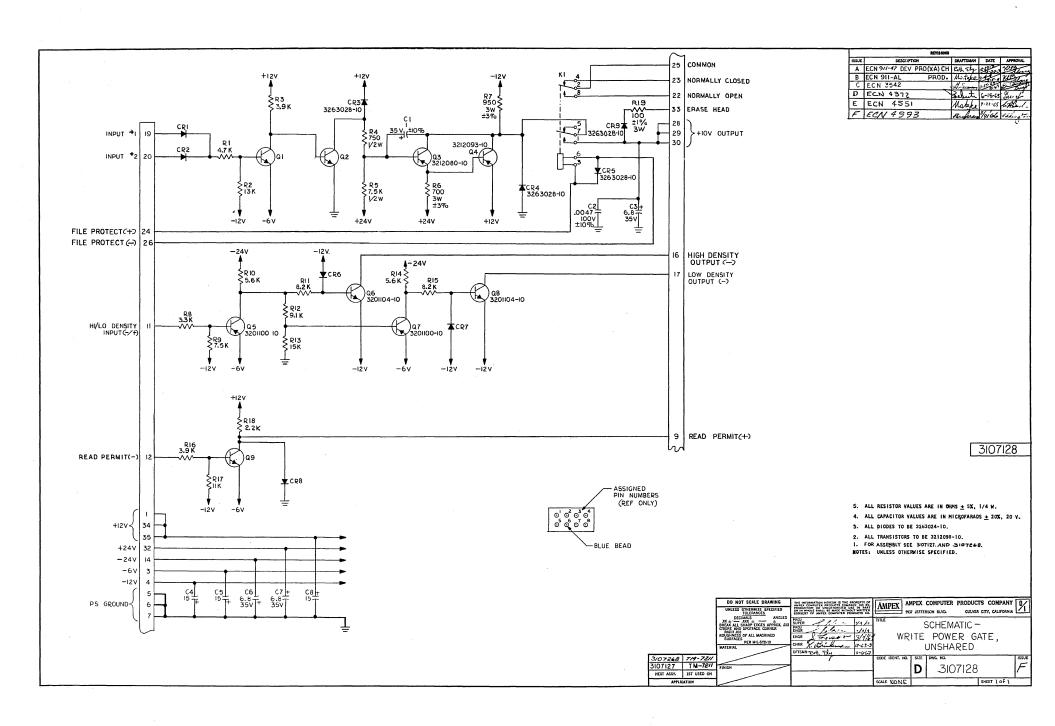


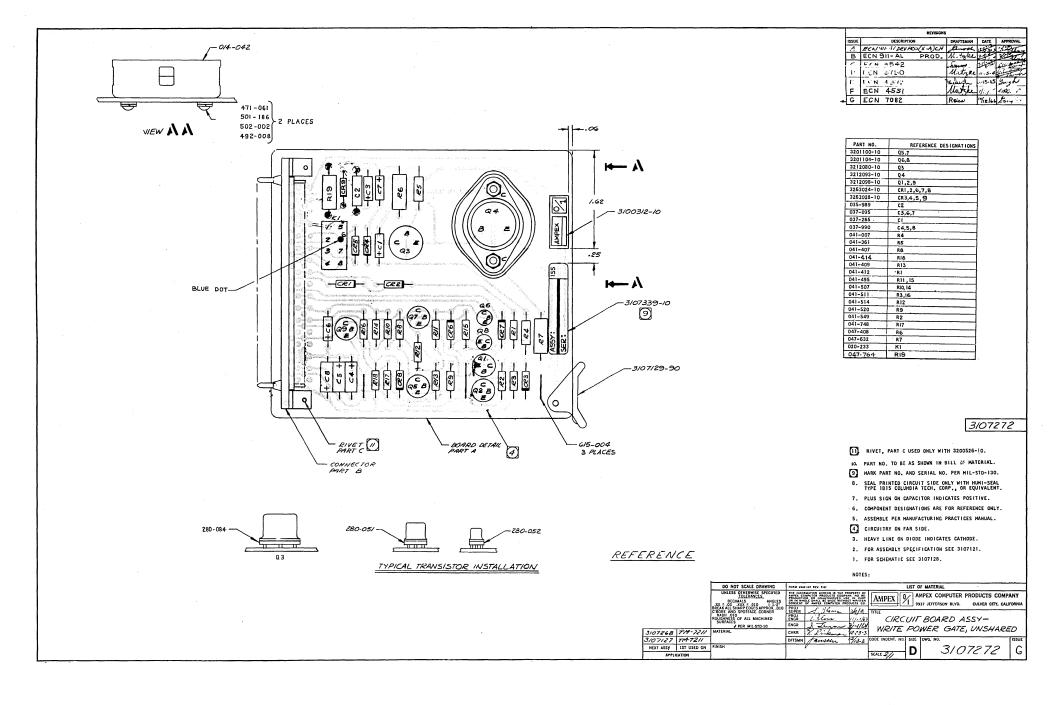


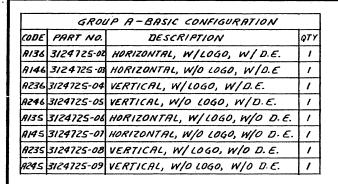












	GROUP E	3 - REEL RETAINERS	
CODE	PART NO.	DESCRIPTION	977
8/	3113100-10	IBM HOLD DOWN KNOB	1
67	3101267-10	FIXED TAKE UP REEL	1
B2	3113100-10	IBM HOLD DOWN KNOB	2
82	3/08273-30	EMPTY REEL	/

•		GROUP C	- HEADS	
	CODE	PART NO.	DESCRIPTION	<i>9</i> 7 y
	CI	3119337-01	1CH. W/O ERASE	1
	CZ	3/18430-01	7 CH. W/ ERASE	1
	C3	3118429-01	9 CH. W/ ERASE (STD. IBM WIRING)	1
Ð	<i>C4</i>	3118429-02	9 CH. W/ ERASE (SPECIAL IBM WIRING)	1

	GROUP I	D - MOTION COMMAND		
CODE	PART NO.	DESCRIPTION	LOCAT.	974
D1	31195 98 -01	PCBA, RUN/STOP	14	1
DZ	3/19529-01	PCBA, FWD/STOP	14	1

	GROUP	E - CABINET	
CODE	PART NO.	DESCRIPTION	474
EI	3110719-10	LO BOY CABINET	1
EZ	3111257-10	19" VERTICAL CABINET	1
E4	[NO CABINET .	

GROUP F - VERTICAL HINGE						
CODE	PART NO.	DESCRIPTION	QTY			
FI	3/09889-10	VERTICAL HINGE ASSY	1			
FZ		NO VERTICAL HINGE	_			

	GROUP	G- TAPE SPEED		
CODE	PART NO.	DESCRIPTION	LOCAT.	974
-,	3119593-01	PCBA, REEL SERVO 36 IPS	17	1
61	3107097-10	PCBA, REEL SERVO 36 IPS PCBA,CAPSTAN SERVO 36 IPS	16	1
12	3119594-01	PCBA, REEL SERVO 45 IPS	17	1
62	3112170-10	PCBA,REEL SERVO 45 IPS PCBA,CAPSTAN SERVO 45 IPS	16	1

O WITH ITEM CA INCLUDE ADDENOUM 3123716-01

GROUP H- INPUT LEVELS						
CODE		FALSE	PART NO.	Q7Y	LOCATION	
HI	-12	0	3107258-10	2	BI5, BI6	
нг	+3	0	3118170-01			
H3	+6	0	3118171-01		815	
H4	+9	0	3/18172-01			
HS	+12	0	3/18/73-01	3	<i>B1</i> 6	
H 6	0	+3	3118227-01	٥	876	
H 7	0	+6	311822 8 -01			
н8	0	+9	3118229-01		<i>B22</i>	
H 9	0	+12	3118230-01			

6.	ROU	P J	- OUTPUT	LEV	ELS
CODE		FALSE	PART NO.		LOCATION
J/	-12	0	3107259-10	*2	813, 814
12			3118179-01	* 2	B13, 814
J2	+3	0	3118161-01	1	823
J3	+4	0	3118292-01	*2	BI3, BI4
3	7.4	Ů	3118293-01	/	823
J4	+5	0	3/19588-01	*2	B13, B14
04	73	Ů	3119589-01	1	<i>B</i> 23
JS	+6	0	3/18/80-01	*2	BI3, BI4
7		Ľ	3118162-01	/	<i>B23</i>
J6	+8	0	3119498-01	*2	813, 814
00	,,,	٢	3119497-01	/	<i>B23</i>
J7	ļ +9	0	3118181-01	*2	813, 814
0,	,,	Ľ	3118163-01	1	823
J8	+12	0	3118182-01	*2	813, 814
00	112		3118164-01	1	B23
J9	0	+3	3118161-01	*2	B13, B14
00	L	,,,	3118179-01	1	B23
310	0	+4	3118293-01	*2	813,814
0,0	Ĺ	/ +	3118292-01	/	<i>823</i>
JII	0	+÷	3/19589-01	*2	813, 814
077	Ľ	73	3119588-01	1	B23
JIZ	6	+6	3118162-01	*2	B13, B14
0,2	Ľ	7.6	3118180-01	1	<i>B23</i>
J/3	0	+8	3119497-01	*2	813, 814
0,3	L		3119498-01	1	<i>B23</i>
J14	0	<i>+9</i>	3118163-01	*2	B13, B14
	Ľ		3118181-01	1	<i>B23</i>
JI5	0	+12	3118164-01	*2	B13, B14
3,3	Ľ		3118182-01	1	823

3/12	DUP K - STD. DAT	H ELECT., I	NRITE	WIO	NIUI	RECTIONA	L REHU
CODE	DESCRIPTION	PART NO.	SPEEN	Q	TY	LOCA	TION
	Descin non	, ,,,,,	5, 202	7 <i>CH</i>	9 <i>CH</i>	7 CH	9 CH
	WRITE POWER GATE	3107268-10	ALL	1	/	A24	A24
	STROBE GENERATE	3107057-10	36 £ 45	1	1	88	88
KI	READ AMP	3107266-10	36 £ 45	4	5	<i>B2 1HRU B</i> 5	82 THRU 86
	WRITE AMP	3112363-10	36 £ 45	7	9	AIA THRU ALI	AI4 THRU AZZ
i	READ DESKEW	3107269-10 3123847-01		7	9	AZ THRU A8	AZ THRU AIU

GRO	UPK-STO. DATA	ELECT., W	RITE V	1/81	DIR	ECTIONAL	READ
CODE	DESCRIPTION	PART NO.	SPEED	QT	Υ	LOCAT	TION
	2232		5. 55 2	7 <i>CH</i>	9 <i>CH</i>	7 CH	9 CH
	WRITE POWER GATE	3107268-10	ALL	1	1	A24	A24
	STROBE GENERATE	3107057-10	36 € 45	1	1	88	88
KZ	READ AMP	3107266-10	36 £ 45	4	5	BZ THRU BS	BZ THRU BL
	WRITE AMP	3112363-10	36 £ 45	7	9	AI4 THRUA20	AI4 THRUAZZ
	READ DESKEW	3109932-10 3119428-01		7	9	AZ THRU A 8	AZ THRU AIO
	SELECT LOGIC	311157-10	ALL	7	7	<i>B</i> 7	<i>B</i> 7

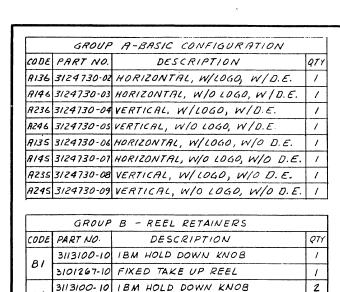
	GROUP L-	DATA ELECTR	ONICS OF	PTIONS	-				
CODE	OPTION	PCBA	PART NO.	SPEED	97	У	LOCA	9710NS	
		DESCRIPTION	7 11111 7101	0, 220	7CH	9СН	7CH	9 CH	
LI	NO OPTIONS		l ———			—			
LZ	ECHO & RATE	ERROR CHECK	3109872-10	36 £ 45	1	1	<i>B12</i>	BIZ	
L3	VERT. PARITY CHK	EXCLUSIVE OR	3107274-10	ALL	2	3	89, BIO	89, 810, 811	
L4	VERT. PARITY GEN.	EXCLUSIVE OR	3107274-10	ALL	2	2	AII, AIZ	AII, AIZ	
L S	CONGIT. PARITY GEN.	LONG. PARITY GEN.	3116072-10	36 £ 45	1	1	AI3	A13	
	LONGIT	LONG. PARITY REG	3116082-10	36 £ 45	_	1	<i>B19</i>	B19	
L6	PARITY	LPC TIMING	3116087-10	ALL	1	/	<i>B20</i>	820	
	CHECK	FLIP FLOP	3107275-10	ALL	1	2	<i>B</i> 17	B17, B18	

							3	//	5	77	0	-	5	E	E	0	7	P	R	P	E	9	V	EI	95	1	01	/								
USED W/CODES	OPTION OR FEATURE	55	01	02	03	04	05	06	07	08	09	10	13 /	5	7 2	0 2	2 2	4 25	30	31	32	33	36	37.	38	39	40	41	43	46	18	49	50	6	50	T
KI	UNIDIRECTIONAL READ								×	T	1	x	7	×Τ	7	4	Ī	×	×	x	х	х	х	Х	x	x	X	х	X	T	x	×	1	x z	x	T
K2 W/01	BIDIRECTIONAL READ W/RUN/STOP	x	x	х	x		X	x		x	x		×	T	T)	4	1	T	Γ									П	x	7		x	1	T	Ť
KZ W/02	BIDIRECTIONAL READ W/ FWD/STOP	Γ		П		x					1	1	1	1	K	T	T	T	Γ	Γ										П	1		1	T	T	T
HI, JI	-12 LEVELS	X	х	х	x	x	х	X	X	x	x	x.	x :	x i	4	()	4	×	X	x								x	П		x	x	1	1	x	Ť
HZ TO HO W/DI	POSITIVE LEVELS W/RUN/STOP	Г		П							1	1	T	1	T	T	T	T	١.			х	x	Х	х	X			х	x	1	1	x	1	T	T
IZ TO JIS W/OZ	POSITIVE LEVELS W/FWD/STOP									7			T		T	T	1	T	T	Γ	x						x		П		7	1		χŢ	T	T
12	ECHO & RATE	X	х	x	x	x	Х	х	x	x	x	X.	x i	x i	4	4	4	(x	X	x	x	x	х	X	x	x	х	x	x	X.	x	x	x	x :	хŤ	†
<i>ل</i> 3	VERTICAL PARITY CHECK	х	х	х	x	x	X	х	x	x	x	X :	x >	X)	(4		×	x	x	x	Х	х	Χ	x	X	X	х	x	X	x	x	x	x :	x	Ť
L4	VERTICAL PARITY GEN. 7 CH.		х	П			χ	х	x	1	1	1	x >	x i	()	1	1	1	X	Τ				П	x				x	T	7	1	7	1	T	Ť
L4	VERTICAL PARITY GEN. 9 CH.			x						х	1	1	T	T	T	T	7		T	Γ		П	х	П		-	x	x	П	T	x	x	x	1	T	Ť
15	LONGITUDINAL PARITY GEN.						χ				x		x		7	ф	4	×	x	x		П	х	х	x		х		x	T	x	x	x	x	T	T
16	LONGITUDINAL PARITY CHECK	Γ			х			x		x	x	X :	x i	x :	x i	त	T	ĺχ	T	1	Г	П	х			x	x	П	x	T	7	x	x	7	十	†

* ONLY 1 REQD IF 7 CH. NO OPTIONS, OR 1 CH. \$ OPTION \$4, OR \$15 OR BOTH, \$ NO OTHER OPTIONS.

NOTE: FOR TRI DENSITY SUBSTITUTE STROBE GENERATOR
3114894-10, & ADD DENSITY CONTROL 3115632-10
IN B21. FOR DATA C.C. SEE DW4 3115170

		DO NOT SCALE DRAWING	THE INFORMATION HEREON IS THE PROPERTY OF AMERIC COMPUTER PRODUCTS DAYSON. NO REPRO-
		UNLESS OTHERWISE SPECIMED DIMENSIONS ARE IN INCHES DECIMALS TOLERANCES ANYMES	DUCTION OF UNAUTHORIZED USE HI PART OR IN MODEL SHALL BE BLOCK WINDOWN THE PRODUCTS DIVISION AMPLE SHALL BE BLOCK WINDOWN PRODUCTS OF AMPLE CONVEYED FROUCTS ON. AMPLE CONVEYED FROUCTS ON.
		We york	PROJ SUPER TITLE
		MEAK ALL SHARP EDGES APPROX. 010, C'BORE AND SPOTFACE CORNER RADII APPROX. 010.	
		ROUGHNESS OF ALL MACHINED	BIGR CA WATSON 9/2/68
		MATERIAL	DITISMA CA MATERIA 9/2/18 STD. TM-707,709,7211,7291
			SIZE CODE IDENT, NO, HOWG, NO.
		PNASK	
WEXT ASSY.	1ST USED ON		D 09150 3/24744
APPLICA			SCALE SHEY
		L	



	В2	3113100-10	IBM HOLD DOWN KNOB	2
	02	3108273-30	EMPTY REEL	1
ĺ		GROUP	C- HEADS	
	CODE	PART NO.	DESCRIPTION	QTY
	CI	3//2686-10	7 CH. W/O ERASE	1
	CZ	3112442-10	1CH. W/ERASE	1
	C3	3112443-10	9 CH. W/ERASE (STD. IBM WIRING)	1
0	C4	3112443-20	9 CH. W/ERASE (SPECIAL IBM WIRING)	1

	GROV	P D - MOTION COMMAND		
CODE	PART NO.	DESCRIPTION	LOCAT.	QTY
DI	3119598-01	PCBA, RUN/STOP	J4	./
D2	3119529-01	PCBA, FWD / STOP	14	1

	GROUP	P E - CABINET	
CODE	PART NO.	DESCRIPTION	QTY
E/	3110719-10	LO BOY CABINET	1
E2	3111257-10	19" VERTICAL CABINET	1
E4		NO CABINET	

	GROU	P F - VERTICAL HINGE	
CODE	PART NO.	DESCRIPTION	QTY
FI	3109889-10	VERTICAL HINGE ASSY	1
F2		NO VERTICAL HINGE	

	GROUP G - TAPE SPEED
CODE	DESCRIPTION
<i>G</i> 3	TAPE SPEED PCBA'S INCLUDED IN GROUP A

	GRO	UP	H - INPU	r L	EVELS			
CODE	LEV	ELS	PART NO.	QTY	LOCATION			
	TRUE	FALSE	PART NOT	Q I I	LUCATION			
HI	-/2	0	3107258-01	2	B15, B16			
H 2	+ 3	0	3118170-01		B 15			
43	+6	0	3118171-01		15/5			
H 4	+9	0	3118172-01					
# 5	+/2	0	3118173-01	3	816			
46	0	+3	3118227-01	٥	010			
<i>H</i> 7	0	+6	3118228-01					
HB	0	+9	3118229-01		B 2 2			
49	0	+/2	3118230-01		522			

	GRO	UP	J - OUT PUT	LE	VELS
CODE	LE	VEL	PART NO.	QTY	LOCATION
	TRUE	FALSE	PAILT NO.		LOCATION
J1_	-12	0	3/07259-10	*2	B/3,B/4
J2	+3	0	3/18/79-01	* 2	B15,B14
			3118161-01	1	B23
J3	+4	0	3118292-01	* 2	B13,B14
0.5	7 7)	3118293-01	1	B 23
J4	+5	0	3119588-01	*2	B13,B14
J 4			3119589-01	1	B23
	.,		31/8180-01	*2	B13,B14
J 5	+6	0	31/8162-01	1	B23
			31/9498-01	*2	B13,B14
16	+8	0	3/19497-01	1	B 23
			3118181-01	*2	B13,B14
J7	+9	0	3118163-01	1	1323
			3118182-01	*2	8/3,8/4
J8	+12	0	3118164-01	/	B23
			3118161-01	*2	B13, B14
J9	0	+3	3118179-01	1	B23
			31/8293-01	*2	B13,B14
JIO	0	+4	3//8282-01	1	823
			31/9589-01	*2	B/3,B/4
JII	0	+5	3119588-01	1	<i>B 2</i> 3
			3118162-01	* 2	B13, B14
J12	0	+6	3118180-01	1	B23
			3119497-01	*2	813,814
J13	0	+8	31/9498-01	1	B23
			3118163-01	*2	B13, B14
J 14	0	+9	3118181-01	1	B23
			3118164-01	*2	B13, B14
/15	0	+12	3118182-01	1	B23

	STD DATA EL	ECT., WRITE	W/UI	VIDI	REC	TIONAL RE	A D
CODE	DESCRIPTION	PART NO.	CDEEN	QT	Y	LOCAT	ION
	DESCRIPTION	TARY NO.	31660	7 <i>CH</i>	9CH	7 CH	9 C H
[WRITE PWR GATE	3107268-10	ALL	1	1	A24	A 24
	STROBE GENERATE	3109994-10	75	1	1	88	88
KI	READ AMP	3109991-10	75	4	5	B2 THRU B5	BZ THRU BG
	WRITE AMP	3109572-10	75	7	9	A 14 THRU A20	AI4 THRU A22
<u></u>	READ DESKEW	3109475-10	75	7	9	AZ THRU AB	A 2 THRU AID

	STD DATA EL	ECT., WRITE	W/E	BIDI	REC	TIONAL	READ
CODE	DESCRIPTION	PART NO.	CPEED	QT	rY	LOCI	ATION
COL	DESCRIPTION	PART NO.	3166		9CH	7 CH	9 CH
	WRITE PWR GATE	3107268-10	ALL	1	1	A 24	A 24
	STROBE GENERATE	3109994-10	75	1	1	88	88
K2	READ AMP	3109991-10	75	4	5	B2 THQU B5	B2 THRU BG
	WRITE AMP	3109572-10	75	7	9	AI4 THRU A20	AIA THRU AZZ
	READ DESKEW	3109935-10	75	7	9	AZ THRU AB	AZ THRU AIO
	SELECT LOGIC	3111157-10	ALL	1	1	87	<i>B</i> 7

	CROUR	DATA ELECT	BONICE	OPTIO	AIC			
L	GROUP L -	DATA ELECTI	2017123	<i>UF 110</i>	~ 3			
CODE	OPTION	PCBA	PART NO	SPEED	Q.	TY	LOCA	TION
COOL	OFTION	DESCRIPTION	-AZ / /VD	SPECD	7 <i>CH</i>	9 <i>cH</i>	7 CH	9CH
41	NO OPTIONS				_			
L2	ECHO & RATE	ERROR CHK.	3110558-10	36 € 45	1	1	B12	B12
L3	VERT. PARITY CHK.	EXCLUSIVE OR	3107274-10	7 5	2	3	B9, B10	89, BIO, BII
14	VERT. PARITY GEN.	EXCLUSIVE OR	3107274-10	75	2	2	A11, A12	A11, A12
L5	LONG. PARITY GEN.	LONG PARITY GEN.	3116142-10	75	1	1	A /3	A/3
	LONG.	LONG. PARITY REG	3116161-10	75	1	1	·B19	B19
16	PARITY	LPC TIMING	3116087-10	ALL	1	1	B20	B20
	CHECK	FLIP FLOP	3107275-10	ALL	1	2	817	B17,B18

									3	11	5	7 7	0	_	:	SE	4	= 0	= 7	-	P	20	P	è	R	ļ	15	72	S	10	ント	J		
USED W/CODES	OPTION OR FEATURE	55	01	02	03	04	05	06	070	28	9/	0 1	3 15	17	20	22	24	25	30	31 3	2 3	3 36	37	38	3 39	40	41	43	46	48	19 5	50	661	0
ΚI	UNIDIRECTIONAL READ		Г						×	T	7	7	×		×			x	x	X)	<u>۲</u> ۷	(x	×	×	×	×	×	X		X	X	×	(x	Τ
K2 W/DI	BI DIRECTIONAL READ W/RUN / STOP	х	×	×	X		X	X		×I.	×	,	₹ 1	T		×	×	Ī	$ \top $	T	T	T	Ī	T	Τ				×	T	7	×	T	Τ
K2 W/D2	BI DIRECTIONAL READ W/FWD/STOP	Γ		П		X				T	T	T	T	×	Γ			1	1	T	T	Τ	T	T	T				T		T	Т		Γ
HI, JI	-12 LEVELS	×	×	×	X	х	×	X	×	×.	× ,	4)	< x	: X	X	×	×	X	X	X	Τ			Τ	Π		х	П	7	× ;	×	T	X	
1270H9 W/DI	POSITIVE LEVELS W/RUN STOP	Γ		П						T	T	T		Τ				1	T	T	7>	\×	×	×	×		П	x	хĪ	T	7	x	T	T
2 TOJI5 W/D2	POSITIVE LEVELS W/FWD/STOP			П							T	T	T	Τ	Γ				1	7	~	Τ			Τ	×		П	٦		T	1	₹	Г
L 2	ECHO & RATE	×	×	×	×	×	Х	×	×	×	×	4	< ×	×	×	×	×	×	x :	×,	ا ×	×	×	×	×	×	×	×	×	×	× .	x >	۲×	
۷ 3	VERTICAL PARITY CHECK	×	X	×	×	x	×	×	×	× ;	× ;	٦,	۲ >	<	×	×	×	×	×	× ;		(×	×	×	×	×	×	×	×	\times	× .	××	ďχ	Ţ
	VERTICAL PARITY GEN. 7 CH	Γ	×				X	×	×		T	Τ,	۷ ×	(×	×			1	×		Т	T		×	Τ		П	×		T	T	T	T	Γ
L4	VERTICAL PARITY GEN. 9 CH			x					T	X	1	T	T	T	Г		X	1		T	T	×	T	Γ	Γ	×	×	П	1	×,	۸,	↲	T	T
L 5	LONGITUDINAL PARITY GEN						×				X	,	4	Τ	×	×	×	×	X.	X	T	×	×	×	T	×		×	7	X	×,	χ,	4	Γ
L6	LONGITUDINAL PARITY CHECK	Г	Γ	П	X			x	\exists	X.	χİ,	4)	۱,	ί×	x			x	7	T	T	×	1	Γ	×	×		x	T	7	×	XT	T	Γ

NEXT ASSY. 1ST USED ON APPLICATION

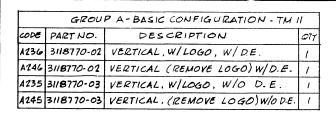
O WITH ITEM C4 INCLUDE ADDENDUM 31237/6-01

* ONLY ONE REQUIRED IF 7 CH NO OPTIONS, OR 7 CH & OPTION L4 OR L5 OR BOTH, & NO OTHER OPTIONS.

NOTE: FOR TRI DENSITY SUBSTITUTE STROBE GENERATOR
3/14897-10, AND ADD DENSITY CONTROL 3/15632-10
IN B21. FOR DATA CC. SEE DWG 3/15770

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.XX± .XXX± ± BREAK ALL SHARP EDGES APPROX010. C'BORE AND SPOTFACE CORNER RADII APPROX010.	ENGR Aulatzon CHKR	5-3-68	ST			SELECTOR 9211,9291
FINISH			SCALE	09150		124745 ISHEET

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GROU	P A · BASIC CONFIGURATION - TMI	2
PART NO.	DESCRIPTION	QT
3118770-06	VERTICAL, W/LOGO , W/ D.E.	1
3118770-06	VERTICAL, (REMOVELOGO) W/D.E.	1
3118770-07	VERTICAL, W/LOGO, W/O D.E.	1
3118770-07	VERTICAL , (REMOVE LOGO), W/O D.E.	7
	PART NO. 3118770-06 3118770-06 3118770-07	GROUP A · BASIC CONFIGURATION - TM I PART NO. DESCRIPTION 3118770-06 VERTICAL, W/LOGO, W/D.E. 3118770-06 VERTICAL, (REMOVE LOGO) W/D.E. 3118770-07 VERTICAL, W/LOGO, W/O D.E. 3118770-07 VERTICAL, (REMOVE LOGO), W/O D.E.

	GROU	PB-REEL RETAINERS	
CODE	PART NO	DESCRIPTION	OTY
		IBM HOLD DOWN KNOB	1
ΒI	3101267-10	FIXED TAKE UP REEL	1
-B2	3113100-10	IBM HOLD DOWN KNOB	Z
-82	3108273-30	EMPTY REEL	1

		GROUF	C-HEADS - TM-11	
	CODE	PART NO.	DESCRIPTION	QTY
	<i>C1</i>	3110206-30	7 CH. W/O ERASE	1
	CZ	3110213-30	7 CH. W/ERASE	1
	<i>C3</i>	3112721-20	9 CH. W/ERASE (STD. IBM WIRING)	/
ө	<i>C4</i>	3112721-50	9 CH. WERRSE (SPECIAL IBM WIRING)	1

		GROU	P C - HEADS - TM-12	
	CODE	PART NO.	DESCRIPTION	QTY
	CI	3110206-50	1 CH. W/O ERASE	1
	CZ	3110213-50	1 CH. W/ ERASE	1
	<i>C3</i>	3112721-40	9 CH. W/ERASE (STD. IBM WIRING)	/
0	C4	3112721-60	9 CH. W/ERASE (SPECIAL IBM WIRING)	1

	GROUP	D - MOTION COMMAND		
CODE	PART NO.	DESCRIPTION	LOCAT-	QTY
DI	3107082-10	PCBA, RUN / STOP	J4	1
DZ	3112360-10	PCBA, FWD / STOP	J4	1

	GROUP	E - CABINET	
C00€	PART NO.	DESCRIPTION	917
EЗ	31/2647-10	14" VERTICAL CABINET	1
£4		NO VERTICAL HINGE	1

	GROUP G . TAPE SPEED
core	DESCRIPTION
G3 THRU GG	TAPE SPEED PCBA'S INCLUDED IN GROUP A

O WITH ITEM C4 INCLUDE ADDENDUM 3123716-01

GROUP H - INPUT LEVELS											
CODE	LEL	ELS	PART NO.	077	LOCATION						
LOVE	TRU ϵ	FALSE	PAICT 100.	311	LOCATION						
HI	-12	0	3107258-10	2	B15, B16						
H 2	+3	0	3118170-01		6.45						
НЗ	+6	0	3!18171-01		B 15						
H4	+9	0	3118172-01								
H 5	+12	0	3118173-01	3	B 16						
H6	0	+3	3118227-01	١	5.0						
H7	0	+6	3/18728-01								
48	0	+9	3118229-01		B 2 2						
H9	0	+12	3118230-01		022						

4	GROU	IP J	- OUTPUT	EVE	LS
CODE	LEVE	ELS	PART NO.	QTY	LOCATION
	IRVE	FALSE			
11	-12	0	3107259-10	*2	B13, B14
J2	+ 3	0	3118179-01	* 2	B13, B14
02	- 3		3118161-01	1	B23
J 3	+4	0.	311 8 292-01	* 2	B13, B14
V 5			3118293-01	1	B23
11	+5	0	31195 88-0 1	* 2	B13,B14
J4	73		3119589-01	1	B 23
J 5	+6	0	3118180-01	*2	B13, B14
J J			3118162-01	1	B23
16		0	3/19498-01	* 2	B13,814
16	+8		3119497-01	1	B23
J 7	_		3118181-01	*2	BI3,BI4
J /	<i>+</i> 9	0	3118163-01	1	823
10		0.	3118182-01	*2	B/3,8/4
JB	+12		3118164.01	1	823
19	0		3118161-01	*2	B13, B14
35		+3	3118179-01	1	B23
110		+4	3118293-01	*2	B13,B14
310	0	+ 4	3118292-01	1	B 23
		+5	3119589-01	*2	B13, B14
JII	0	75	3119588-01	1	B 23
112	0	+6	3118162-01	*2	B13, B14
212		7 6	3118180-01	1	B 23
			3119497-01	*2	R13, B14
J 13	0	+8	31/9498-01	1	B23
1.0		10	3/18/63-01	*2	813,814
J 14	0	+9	3118181-01	1	B23
115		4.12	3118164-01	* 2	813,814
115	0	+ 12	3/18187-01	1	<i>B</i> 23

		 	1	1						
CODE	DESCRIPTION	PART NO.	SPEEOS	07	<u> </u>	LOCATION				
			,,,,,,	7CH	9 <i>CH</i>	7 CH	9 CH			
	WRITE POWER GATE	3107268-10	ALL	1	1	A 24	A 24			
	670006	3109994-10	75							
	STROBE GENERATOR	3110003-10	112.5/120	1	1	B8	88			
		3/18218 - 01	150				i			
	READ AMPLIFIER	3109991-10	75			BZ	82			
K1		3110273-10	112.5/120	4	5	THRU	THRU			
		3118138-01	150			<i>B5</i>	86			
	WRITE	3109572-01	75			A 14	A14			
	AMPLIFIER	3110002-10	112.5	7	9	THRU A 20	THRU			
	READ	3109475-10	75	7	9	42	AZ			
	DESKEW	3110004-10	112.5	1	7	THRU AB	THRU			

		T		0	TY	LOCA	TIONS		
CODE	DESCRIPTION	PART NO	SPEEDS	7CH	904	7 CH	9 CH		
	WRITE POWER GATE	3107268-10	ALL	1	1	A24	A24		
		3109994-10	75						
	STROBE GENERATOR	31/0003-10	112.5/120	1	1	88	88		
	40100417014	3/182/8-10	150						
KZ		3109991-10				82	BZ		
``-	READ AMPLIFIER	3110273-10	117.5/120	4	5	THRU	THRU		
		3118138-10	150			85	86		
	WRITE	3109572-10	75	_	4	A /4	A 14		
	AUPLIFIER	3110002-10	112.5	7	9	THRU AZO	THRU AZZ		
	READ	3109935-10	75			A2	AZ		
	DESKEW	3109936-10	112.5	7	9	THRU AB	THRU		
	SELECT LOGIC	3111157-10	ALL	1	1	87	B7		

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	GROUP	L - DATA ELEC	TRONICS	SOP	TIO	√ 5		
CODE	OPTION	PCBA	PART NO.	SPEED	97	-у	LOCAT	IONS
		DESCRIPTION			7CH.	9 <i>CH</i>	7 CH.	9 CH.
11	NO OPTIONS				-	_		
12	ECHO	ERROR CHECK	3110558-10		,	,	0.14	812
LZ	AND RATE	ERROR CHECK	3110031-10	12.5		′	B12	872
<i>L3</i>	VERT- PARITY CHK	EXCLUSIVE OR	3107274-10	ALL	2	В	B9,810	89,810,811
14	VERT. PARITY GEN	EXCLUSIVE OR	3107274-10	ALL	2	2	A 11, A12	A11, A12
15	LONGITUDINAL	LONG-PAR. GEN	3116142-10	75	,	,	4/3	A 13
7.5	PARITY GENERATE	LONG. PAR GEN	3116073-10	112.5 120/150		′	Д/5	X 13
	LONGITUDINAL	LONG. PAR. REG.	3116161-10	75		,	B19	B/9
,,	PARITY	LONG. PAR. REG.	3116162-10	112-5	1	/	577	5,7
26	CHECK	LPC TIMING	3116087-10	ALL	1	1	820	B20
		FLIP FLOP	3107275-10	ALL	1	2	B17	B17,B18

		Γ							31	115	5 7	7	0	,	_	S	E	40	-	7	P	R	0 F	E	R	V	E	R	5/	0	N					
USED WITH CODES	OPTION OR FEATURE	55	01	02	аз	04	05	06	07	08	09	10	13	15	17	20 2	2 2	4 2	5 3	0 3	3	2 33	36	, 3.	38	3 54	9 40	41	43	46	48	49	50	56	60	brack
KI	UNIDIRECTIONAL READ								×			×		×	-	×	1	١,	را,	٠ĺ×	(×	×	×	×	×	×	×	×	×		x	×		×	x	
K2 W/ DI	BI- DIRECTIONAL READ W/RUN/STOP	X	X	×	X		x	X		X	x		×	1	1		x >	4	T	T	T	Τ	Γ	Γ	Γ	Γ	T	Π	Γ	×			X	T	T	7
K2 W/D2	BI-DIRECTIONAL READ W/FWD/STOP			П		X								7,	4	T	T	T	T	T	T	T	T	T		Ţ	T	Γ	Γ						T	7
HI, JI	-/Z LEVELS	X	×	×	×	X	×	×	×	×	×	×	×	×	×	×	۷,	ζ,	4,	4×		T		T	T	T	T	×		T	x	x		7	x	7
H2 70 H9 W/DI	POSITIVE LEVELS W/RUN/STOP	Γ										٦				T	T	T	1	T	T	X	×	×	×	×		T	x	×			×	T	\top	7
12 70 JIS W/D2	POSITIVE LEVELS W/ FWD / STOP	Γ	Γ													T	T	T	T	T	×				T	T	×	Τ	T					×	T	7
12	ECHO & RATE	×	X	×	x	×	×	x	×	x	×	x	×	×	K	×	۷,	4>	١,	· ×	×	×	×	×	×	×	×	×	×	×	×	x	×	X	x	1
۷3	VERTICAL PARITY CHECK	X	X	X	×	x	x	X	x	X	×	x	x	×	x	×,	7	٨,	١,	×	×	X	×	×	×	×	. ×	×	×	×	×	×	×	X	x	7
<i>L4</i>	VERTICAL PARITY GEN. 7 CH	Г	×	П			X	X	×				x	×	×	×	T	T	×		T	T			x			T	x				T	7	T	1
24	VERTICAL PARITY GEN. 9 CH			×						X					1	T	,	4	Ī	T	T	T	×	Γ	Γ	Ī	×	X	Γ		X	X	×	T	T	T
45	LONGITUDINAL PARITY GEN.	Γ		П			X	٦			X	1	M		1	×.	××	٦,	()	×	T	T	X	×	×	T	×	Γ	×		X	X	X	×	T	7
16	LONGITUDINAL PARITY CHECK		Γ		X			X		X.	X	X	x	X	_	_	T	1,	4	1		T	×	Γ	Γ	×	×	Ţ	X			X	X	T	T	T

* ONLY ONE REQUIRED IF 7 CHANNEL NO OFTIONS OR 7 CHANNEL AND OPTION LA OR LE CR BOTH AND NO OTHER OPTIONS.

NOTE: FOR TRI DENSITY SUBSTITUTE DUE OF THE FOLLOWING STROSE GENERATORS. 75 IPS 3114897-10, 112-5 OR 120 IPS 3115626-10, 150 IPS 3118278-01, AND ADD DENSITY CONTROL 3115632-10 IN B21 . FOR DATA C.C. SEE DWG. 3115770

		DO NOT SCALE DRAWING UNLESS OTHERWISE SPECIFIED DIMENSIONS ARE IN INCHES DECIMALS TOLERANCES ANGLES	THE INFORMATION HEREON IS THE PRO AMPEX COMPUTER PRODUCTS DIVISION. I EUCTION OR UNAUTHORIZED USE IN P 1HOLE SHAL. BE MADE WITHOUT WRIT SENT OF AMPEX COMPUTER PRODUC	NO REPAIL ART OR IN TTEN COM	AMPEX	COMPUTER PRODUCTS DIVISION P.O. BOX 329, CULVER CITY, CALIF.
		XX± XXX± ± BREAK ALL SHARP EDGES APPROX. 010. C BORE AND SPOTTACE CORNER RADII APPROX. 010. ROUGHNESS OF ALL MACHINED SURFACES — PER MIL-STD-10 MATERIAL	ENGR Sulutson		STD. TM.II	PART SELECTOR 07,1109,11211,11291 207,1209,1211,12191
			9.		SIZE CODE IDENT. NO.	
		FINISH			(1) 09150	<i>312474</i> 6
NEXT ASSY.	151 USED ON					
APPLICA	TION				SCALE	SHET

		·	
READ	AMPLIFIER (TRACK 1)	REAL	DESKEW (TRACKI)
RA	(TRACKS 2 {3})	RD.	(TRACK 2)
R A	(TRACKS 4 &S)	RD	(TRACK 3)
R A	(TRACKS 6 £ 1)	RD	(TRACK 4)
READ A	AMPLIFIER (TRACKS 8 \$9)	RD	(TRACK S)
SELE C	T LOGIC	RD	(TRACK 6)
STROB	E GENERATOR	RD	(TRACK 7)
O EXCLO	ISIVE OR	READ	DESKEW (TRACK 8)
M EXCLU	SIVE OR	D* READ	DESKEW (TRACK 9)
M *EXCLO	ISIVE OR	" EXC	USIVE OR
ERRO.	R CHECK	" EXC	LUSIVE OR
OUT PU	T DRIVER	D LONG	PARITY GENERATE
OUTPU	T DRIVER	NRITE	AMPLIFIER (TRACK 1)
À INPUT	BUFFER	UM	(TRACKZ)
à INPUT	BUFFER	AM	(TRACK 3)
T FLIP	FLOP	EM.	(TRACK 4)
T*FLIP F	LOP	UM	(TRACK S)
CONG. F	PARITY REGISTER	KW.	(TRACK 6)
ELPC T.	IMING	E/M	(TRACK 1)
DENS	TY CONTROL	*WRITE	AMPLIFIER (TRACK 8)
à DINPUT	BUFFER	S*WRITE	AMPLIFIER (TRACK 9)
° OUT PU	T DRIVER		
		NRI:	TE POWER GATE

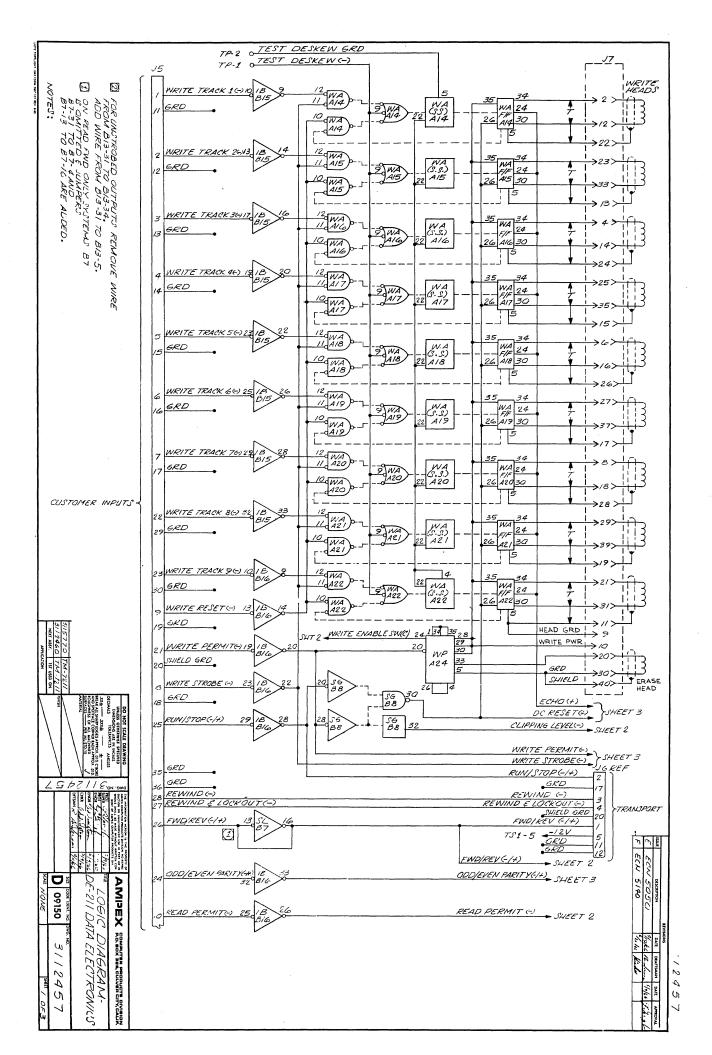
FINESH			WATERIAL	ROUGHNESS OF ALL MACHINED	BREAK ALL SHARP EDGES APPROX. 010. C	WATER TAXABLE	ESS OTHERWISE SPI MENSIONS ARE IN IN TOLERANCES	DO NOT SCALE DRAWING	
		DFTSMN	CHOO	1 BNOR S Weston 4/13/18	Box Childrengton	SUPER	DUCTION OR UNAUTHORIZED USE IN PART OR IN WHOLE SHALL BE MADE WITHOUT WRITTEN CON- SERT OF AMPEX COMPUTEN PRODUCTS DAY.	THE INFORMATION HEREON IS THE PROPERTY OF AMPEX COMPUTER PRODUCTS DIVISION. NO REPRO-	
C 09150 3/24747	SUZE CODE IDENT. NO. DWG. NO.	עב־כוו, עב־כאו	DC_211 DC_201	DATA ELECTRONICS	724/28 CHRD LOCHIIDIN CHITAI	TODO 10/07/01/ /1/007	ANDEX RO. BOX 3RB, CULVER CITY, CALIF.	_	

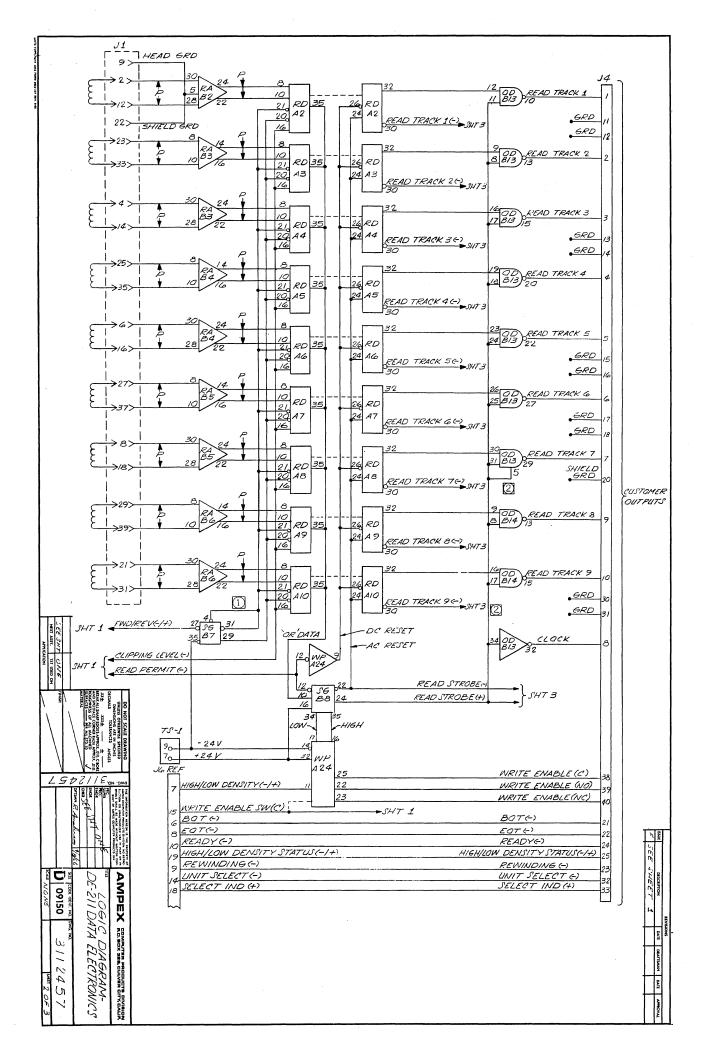
1ST USED ON

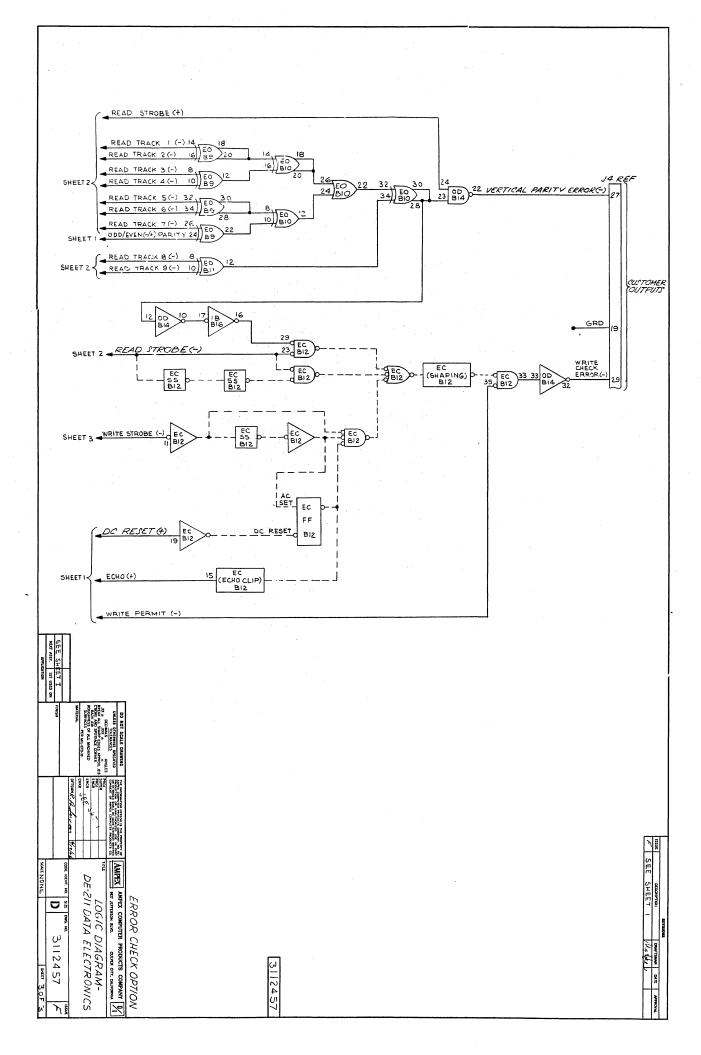
* ADDITIONAL LOCATIONS FOR
9 TRACK QUANTITIES
+ VERTICAL PARITY GENERATE OPTION
• VERTICAL PARITY. CHECK OPTION
• LOCATION OF ADDITIONAL PCBA
REQD WITH POSITIVE LOGIC LEVELS

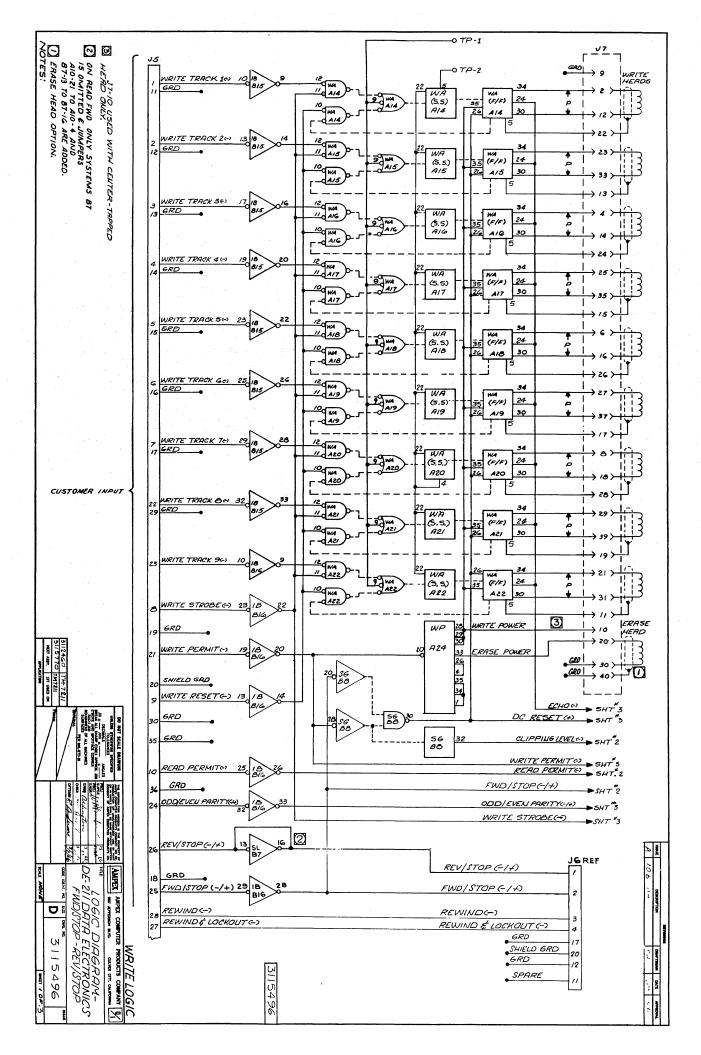
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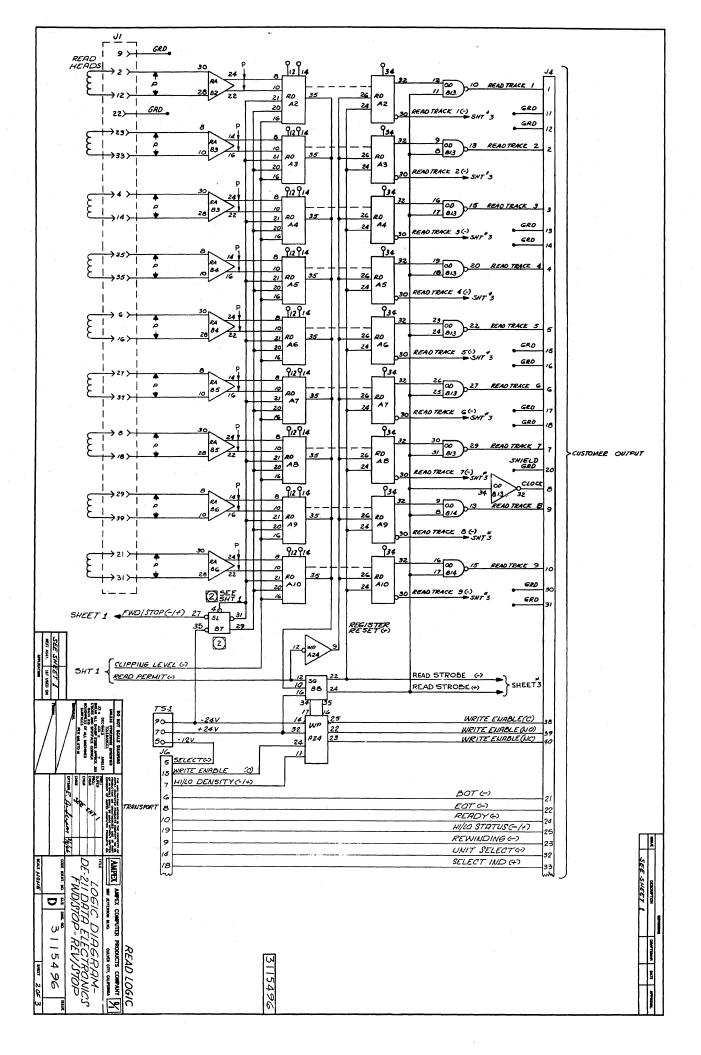
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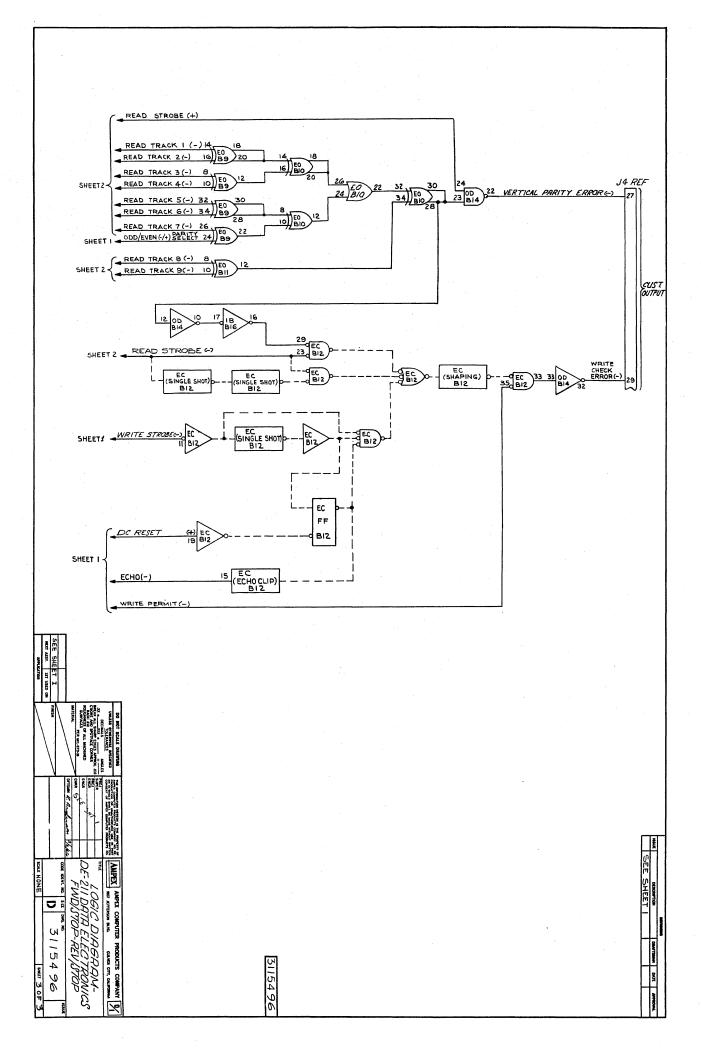












SECTION VIII SPECIAL FEATURES

8-1. INTRODUCTION.

This section documents the changes made in the data electronics to provide the special features listed in Table 8-1. The special feature descriptions are in alphanumeric sequence by the codes listed in Table 8-1. Schematic diagrams and assembly drawings of the PCB assemblies listed in the special feature descriptions are located in Section VII. The logic diagrams applicable to each special feature are located with the special feature description.

TABLE 8-1
DATA ELECTRONICS SPECIAL FEATURES

CODE	DESCRIPTION
SF1	Special Positive Input/Output Levels (Dual Density)
SF2	Vertical Parity Generate (7 Track)
SF3	Vertical Parity Generate (9 Track)
SF4	Longitudinal Parity Check
SF5	Longitudinal Check Character Generate

SPECIAL FEATURE (SF1) SPECIAL POSITIVE INPUT/OUTPUT LEVELS (DUAL DENSITY)

INTRODUCTION.

The standard Input Buffer and Output Driver printed circuit board (PCB) assemblies in the data electronics are replaced with special PCB assemblies in systems which require positive input/output levels. The data electronics assembly is wired as shown in the applicable data electronics logic diagram (3118315 for run/stop logic, 3118325 for forward/stop logic).

GENERAL DESCRIPTION.

The signal levels for the input buffers and the output drivers are selected to meet the system requirements. Table 1 lists typical IBT input buffers used at the various input levels. Table 2 lists typical output drivers used at the various output levels. The ODL and ODM output driver PCB assemblies are used for both 0 volt FALSE and 0 volt TRUE system outputs. When the system output is 0 volts FALSE, ODL output driver PCB assemblies are used in locations B13 and B14 of the data electronics and an ODM output driver PCB is used in location B23. When the system output is 0 volts TRUE, ODM output driver PCB assemblies are used in locations B13 and B14 and an ODL output driver PCB is used in location B23.

DRAWINGS.

The schematic diagrams and assembly drawings of the PCB assemblies are located in Section VII. The logic diagrams are located at the end of this special feature description.

APPLICABLE PRINTED CIRCUIT BOARD DRAWINGS

$\underline{\text{CODE}}$	DESCRIPTION	SCHEMATIC	ASSY DWG
IBT ODL ODM	Input Buffer Output Driver Output Driver	3118175 3118184 3118166	3118174 3118183 3118165
		DIAGRAM	
	DE-211 Data Electron	ics, Positive Levels	
	Run/Stop		3118315
	Forward/Stop		3118325

The logic diagrams are intended for use with systems using either a positive TRUE level and a negative or ground FALSE level or a positive FALSE level and a negative or ground TRUE level. For this reason, state indicators have been omitted from the input buffer inputs and the output driver outputs. State indicators for all other signal levels are as shown in the logic diagram.

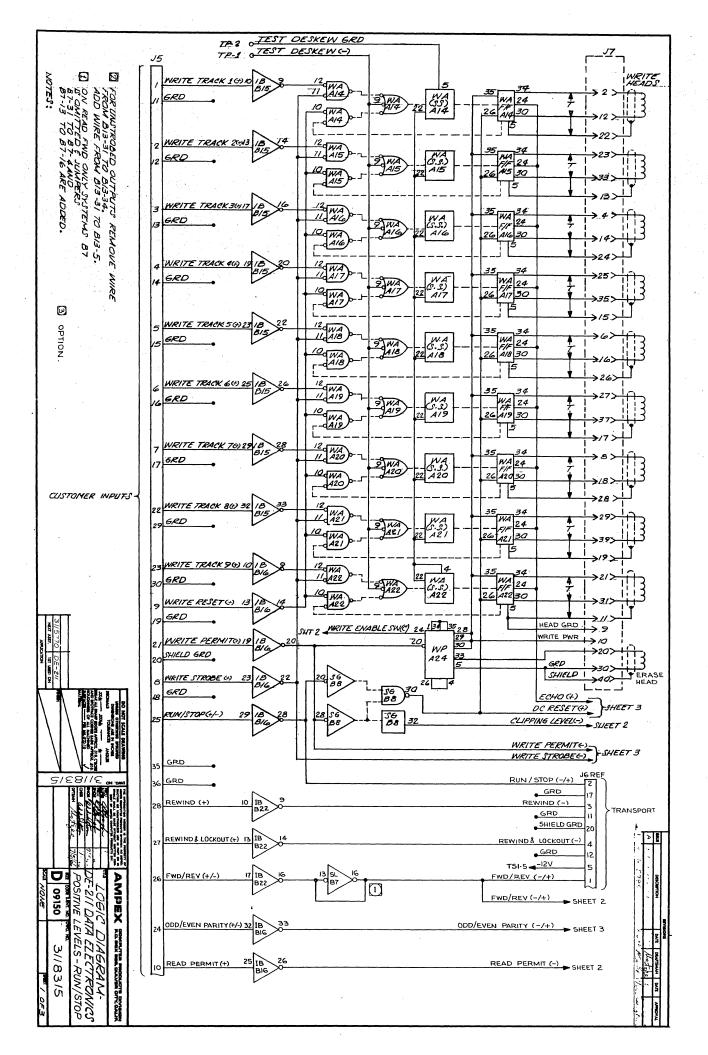
TABLE 1
POSITIVE LEVEL INPUT BUFFERS

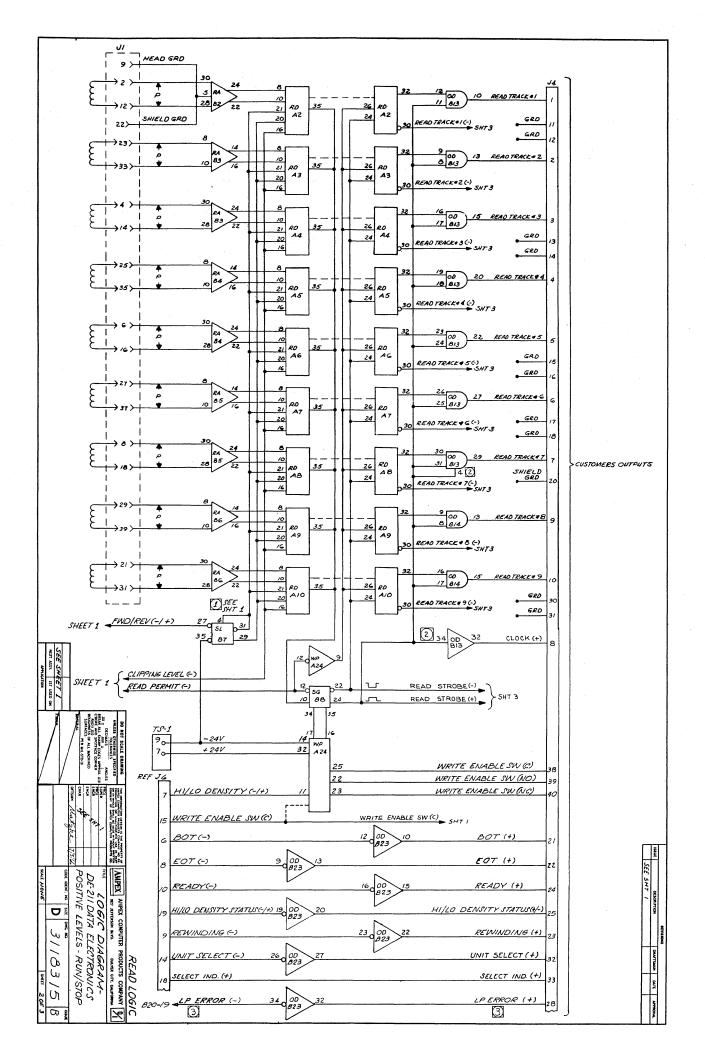
CODE	LEVEL TRUE	(VOLTS) FALSE	PART NO.	SCHEMATIC	ASSY DWG
IBT IBT	+3 +6 +9 +12 0 0 0	0 0 0 0 +3 +6 +9 +12	3118170-01 3118171-01 3118172-01 3118173-01 3118227-01 3118228-01 3118229-01 3118230-01	3118175	3118174

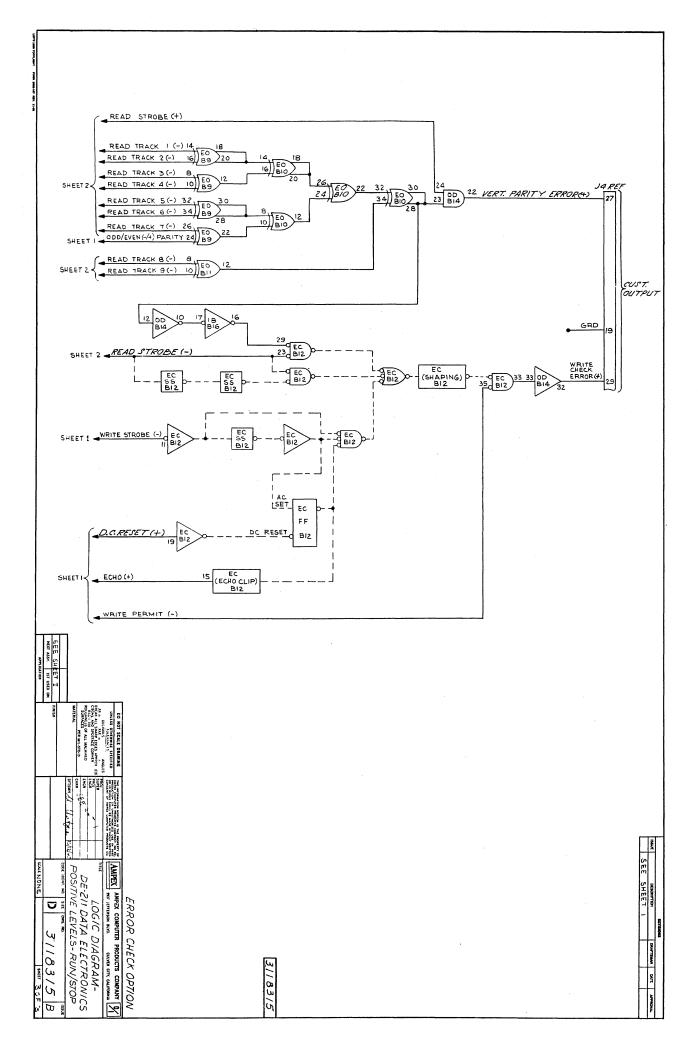
TABLE 2
POSITIVE LEVEL OUTPUT DRIVERS

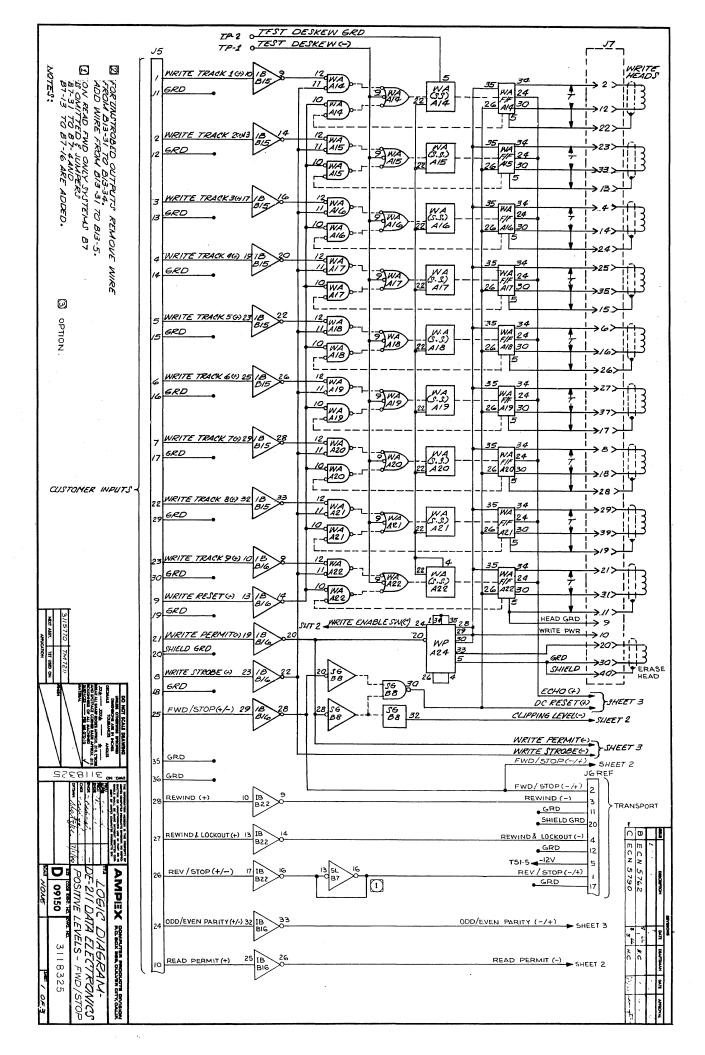
CODE	LEVEL TRUE*	(VOLTS) FALSE*	PART NO.	SCHEMATIC	ASSY DWG
ODL ODM	+3	0	3118179-01 3118161-01	3118184 3118166	3118183 3118165
ODL ODM	+4	0	3118292-01 3118293-01	3118184 3118166	3118183 3118165
ODL ODM	+5	0	3119588-01 3119589-01	3118184 3118166	3118183 3118165
ODL ODM	+6	0	3118180-01 3118162-01	3118184 3118166	3118183 3118165
ODL ODM	+8	0	3119498-01 3119497-01	3118184 3118166	3118183 3118165
ODL ODM	+9	0	3118181-01 3118163-01	3118184 3118166	3118183 3118165
ODL ODM	+12	0	3118182-01 3118164-01	3118184 3118166	3118183 3118165

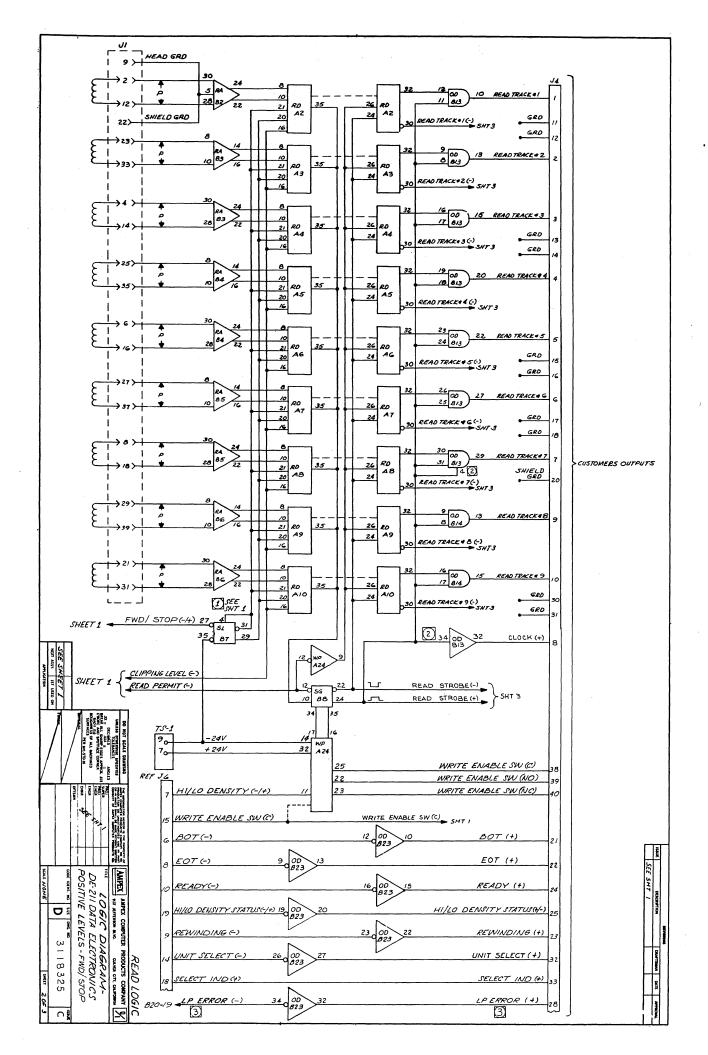
^{*}The same PCB assemblies are also used for 0 volt TRUE and positive voltage FALSE output levels.

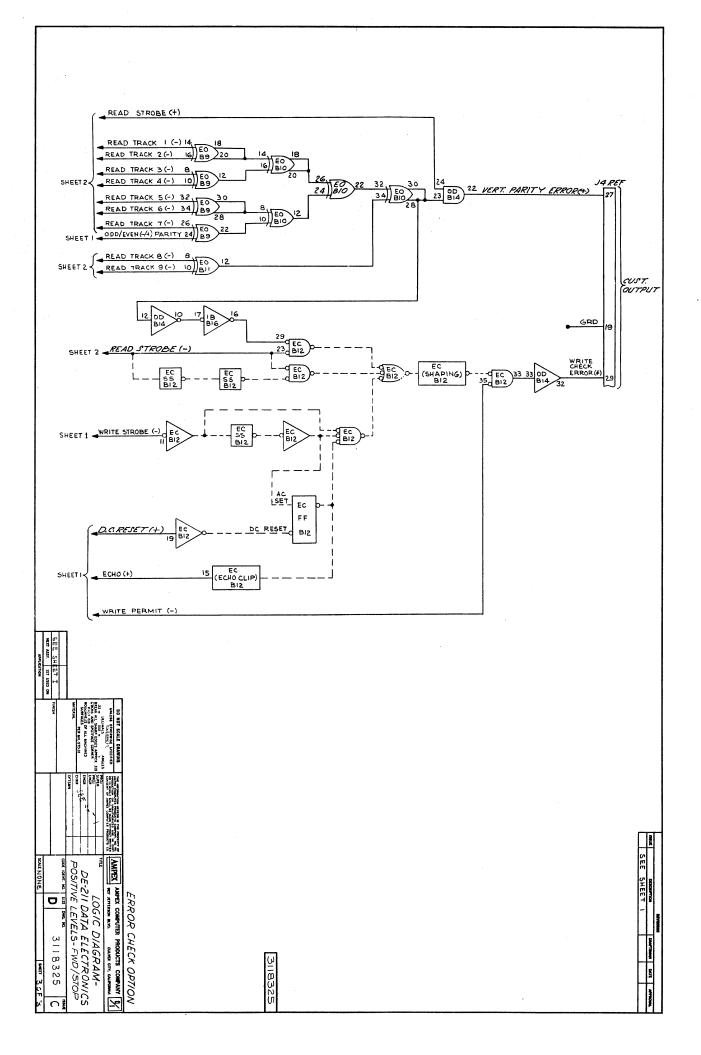












SPECIAL FEATURE (SF2) VERTICAL PARITY GENERATE (7 TRACK)

INTRODUCTION.

The vertical parity generate special feature provides a vertical parity bit (Write Data 7) to write track 7 of the data electronics. Odd or even parity is selected by the Odd/ Even Parity select line.

GENERAL DESCRIPTION.

Exclusive-OR printed circuit board (PCB) assemblies (3107274-10) are inserted into locations A11 and A12 of the data electronics assembly. Four exclusive-OR circuits are provided on each of the PCB assemblies. The data electronics assembly is wired, and the logic elements operate, as shown in vertical parity generate logic diagram 3114921.

OPERATION.

The level of the Odd/Even Parity select line determines whether the parity bit supplied to write track 7 will generate odd or even parity. The parity bit is derived in the same manner as the vertical parity error output. Refer to the description of the vertical parity check circuit and the exclusive-OR circuit description for more details of circuit operation.

DRAWINGS.

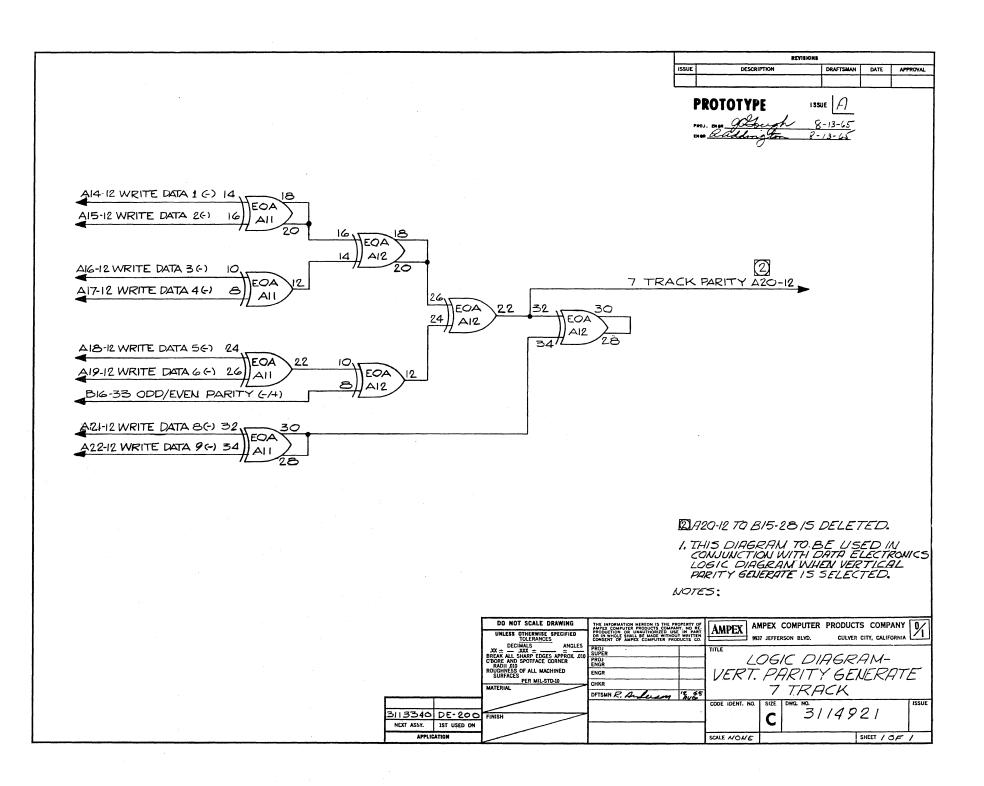
The schematic diagram and assembly drawing of the Exclusive-OR PCB are located in Section VII. The logic diagram is located at the end of this special feature description.

APPLICABLE PRINTED CIRCUIT BOARD DRAWING

CODE	DESCRIPTION	PART NO.	SCHEMATIC	ASSY DWG
ECC	Exclusive-OR	3107274-10	3104453	3107274

LOGIC DIAGRAM

Vertical Parity Generate (7 Track) 3114921



SPECIAL FEATURE (SF3) VERTICAL PARITY GENERATE (9 TRACK)

INTRODUCTION.

The vertical parity generate special feature provides a vertical parity bit (Write Data 4) to write track 4 of the data electronics. Odd or even parity is selected by the Odd/ Even Parity select line.

GENERAL DESCRIPTION.

Exclusive-OR printed circuit board (PCB) assemblies (3107274-10) are inserted into locations A11 and A12 of the data electronics assembly. Four exclusive-OR circuits are provided on each of the PCB assemblies. The data electronics assembly is wired, and the logic elements operate, as shown in vertical parity generate logic diagram 3115766.

OPERATION.

The level of the Odd/Even Parity select line determines whether the parity bit supplied to write track 4 will generate odd or even parity. The parity bit is derived in the same manner as the vertical parity error output. Refer to the description of the vertical parity check circuit and the exclusive-OR circuit description for more details of circuit operation.

DRAWINGS.

The schematic diagrams and assembly drawings of the Exclusive-OR PCB are located in Section VII. The logic diagram is located at the end of this special feature description.

APPLICABLE PRINTED CIRCUIT BOARD DRAWING

CODE	DESCRIPTION	PART NO.	SCHEMATIC	ASSY DWG
ECC	Exclusive-OR	3107274-10	3104453	3107274

LOGIC DIAGRAM

Vertical Parity Generate (9 Track) 3115766

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				•		
					•	
A14-12 WRITE DATA 16) 14, 18						
TEOA						
A15-12 WRITE DATA 26) 16 A11 /						
7_20.	16, - 18					
<u> </u>	HEOA					
	14 AIZ					
AIC-10 WIDTE DATA 3CL IO	120					
AIG-12 WRITE DATA 3(-) 10						
A20-12 WRITE DATA 76) B						
ALU-12 VVICITE DAIM /EI UH AII	26,					
11	EOA		30	2		
	<u>24]</u>] AI	2 EOA) 9 TRACK P	ARITY AIT-12		
	/	- HAIZ	28			
A18-12 WRITE DATA 5(-) 24,		34/2	20			
	10 / EQA 12					
A19-12 WRITE DATA GC) 26 A11	a) A12)					
BIG-33 ODD/EVEN PARITY (-/+)						
-						
A21-12 WRITE DATA OG) 32, 30	•					
TEQA		-				
A22-12 WRITE DATA 9(-) 34 AII						
128						
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	T 14 23	77		CODE IDENT. NO. SIZE DWG. NO		ISSUE
	FINAL ASSY TM-72	// FINISH		C 3	311 576	0611
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SPECIAL FEATURE (SF4) LONGITUDINAL PARITY CHECK

INTRODUCTION.

The longitudinal parity check feature is added to the data electronics by the addition of special printed circuit board (PCB) assemblies and wiring, as shown in the longitudinal parity check logic diagram.

GENERAL DESCRIPTION.

A flip-flop circuit is provided for each read track. Four flip-flops are provided on the Flip-Flop (FF) PCB at data electronics card cage location B17. Three flip-flops are provided on the Longitudinal Parity Register (PR) PCB at B19. Two additional flip-flops are provided on the Flip-Flop (FF) PCB at B18 for tracks 8 and 9. A gap detector circuit, adjusted to six character frame periods (at the lowest character rate) is also provided on the Longitudinal Parity Register PCB. The remaining circuitry required for longitudinal parity check is provided on the LPC Timing (LP) PCB at B20.

OPERATION.

While data is being read, the gap detector on PR at B19 is held on by the read strobe pulse train. The flip-flops (at B17, B19, and B18) are toggled by each read data bit and act as a read register. When longitudinal parity exists in a block of data, all of the flip-flops will be in the reset state following the LPC character and no LP error pulse is generated. When a longitudinal parity error occurs in a block of data, one of the flip-flops will be in the set state following the LPC character and a negative level is applied to the nine-input OR gate on LP at B20. The negative level output from the OR gate enables the LP error NAND gate on LP. The gap detector times out approximately six character frame periods after the LPC character is read and produces a positive-going output transition. The gap detector output is differentiated on LP to produce a negative-going LPC strobe pulse. The LPC strobe pulse is NANDed with the negative-level error output from the OR gate and produces a negative-going LP Error pulse output from the system. The positive-going trailing edge of the LP strobe pulse causes a negative-going LPC Register Reset pulse to be generated on LP and the flip-flops are reset to enable the longitudinal parity check circuit for the next block of data.

ADJUSTMENT.

To check or adjust for the six character frame period, an oscilloscope must be used to measure the timing delay between the leading edge of the last read strobe pulse and the positive-going trailing edge of the gap detector output pulse (at pin 25 of B19); adjust potentiometer R9 to obtain the time delay period listed in Table 1 for the applicable density/speed combination.

TABLE 1 LPC TIMING DELAY (SIX CHARACTER PERIOD)

DENSITY	36 IPS	45 IPS	75 IPS	112.5 IPS	120 IPS	150 IPS
200 cpi	833 µsec	667 µsec	400 μsec	267 μsec	250 μsec	200 μsec
556 cpi	300 μsec	240 μsec	144 μsec	96 μsec	90 μsec	72 μsec
800 cpi	208 μsec	167 μsec	100 μsec	67 μsec	63 μsec	50 μsec

DRAWINGS.

The schematic diagrams and assembly drawings of the PCB assemblies are located in Section VII. The logic diagram is located at the end of this special feature.

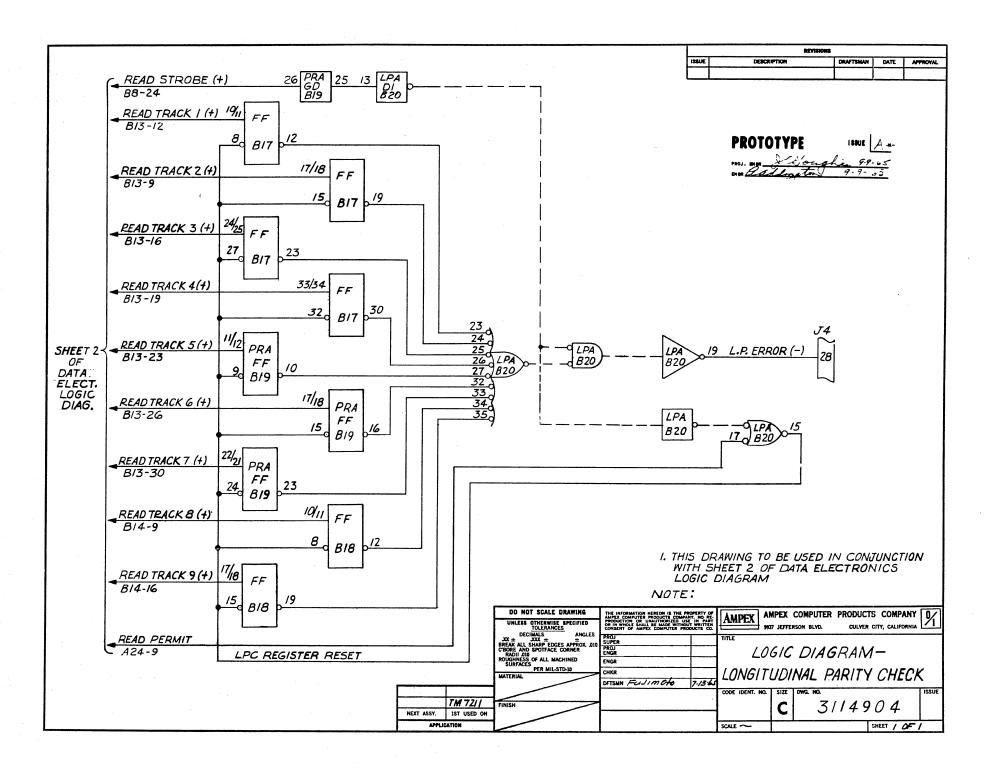
APPLICABLE PRINTED CIRCUIT BOARD DRAWINGS

CODE	DESCRIPTION	PART NO.	SCHEMATIC	ASSY DWG	LOCATION
FFB	Flip-Flop	3107275-10	3104541	3107275	B17,B18*
LPB	LPC Timing -B	3116087-10	3116088	3116087	B20
PRB	Long. Parity Reg -B		3116083	3116100	B19
	36/45 Ips	3116082-10			
	75 Ips	3116161-10			
	112.5/120/150 Ips	3116162-10			

LOGIC DIAGRAM

Longitudinal Parity Check 3114904

^{*}Not required in 7-track systems.



SPECIAL FEATURE (SF5) LONGITUDINAL CHECK CHARACTER GENERATE

INTRODUCTION.

The longitudinal check character generate special feature provides an internally generated Write Reset signal which causes a longitudinal check character (LCC) to be written. Changes to the data electronics for this special feature includes the addition of an LCC Generator (LG) printed circuit board (PCB) assembly at location A13 in the data electronics card cage and additional wiring as shown in the LCC Generate logic diagram.

GENERAL DESCRIPTION.

The absence of a Write Strobe input for the equivalent of four character frame periods is interpreted as the end of a block of data. A Write Reset pulse is generated at this time by the LCC generate circuit and the write registers of the data electronics are reset, causing the LCC to be written on the tape. Two adjustments are provided; one for low density LCC generate timing, the other for high density LCC generate timing. The delay time is selected by the level of the Hi/Low Density select signal.

OPERATION.

The Write Strobe pulse input to the gap detector circuit causes timing capacitor C9 to be charged on receipt of the first Write Strobe pulse and with each succeeding pulse. When no Write Strobe pulses occur for approximately four character frame periods at the selected density/speed combination, timing capacitor C9 discharges and the gap detector produces a positive-going output transition. The gap detector output is differentiated on LG to produce a negative-going Write Reset pulse which resets the write register flip-flops on tracks which have had an ODD number of ONEs written. The LCC is written on the tape when the flip-flops are reset.

Two delay times are preset for the gap detector. When the Hi/Low Density select input to LG is at 0 volts (low density select), Q3 is biased on by the fixed -6 volt level applied at pin 32 of LG. When Q3 conducts, Q1 and Q5 are held cut off by the -7 volt level established at the common emitters by current flow through Q3 (the bases of Q1 and Q5 are at 0 volts, thus the base-to-emitter voltages are positive and establish the cut off condition). When Q1 and Q5 are cut off, Q2 and Q6 are also cut off, effectively removing delay adjustment potentiometers R5 and R15 from the gap detector timing circuit. Transistor Q4 is biased on by Q3 and provides a return to -12 volts (through delay adjustment potentiometer R10) for timing capacitor C9. Potentiometer R10 is adjusted to provide a delay of approximately four character frame periods at the low-density/speed rate. When the Hi/Low Density select input to LG is at -12 volts (high density select), Q5 is biased on. When Q5 conducts, Q1 and Q3 are cut off by the -7 volt level established at the common emitters by current flow through Q5 (the bases of Q1 and Q3 are at 0 volts and -6 volts, respectively, thus the base-to-emitter voltages are

positive and establish the cut off condition). When Q1 and Q3 are cut off, Q2 and Q4 are also cut off, effectively removing delay adjustment potentiometers R5 and R10 from the gap detector timing circuit. Transistor Q6 is biased on by Q5 and provides a return to -12 volts (through delay adjustment potentiometer R15) for timing capacitor C9. Potentiometer R15 is adjusted to provide a delay of approximately four character frame periods at the high-density/speed rate.

ADJUSTMENT.

To check or adjust for the four character frame period, an oscilloscope must be used to measure the timing delay between the leading edge of the last Write Strobe pulse and the leading edge of the Write Reset pulse at pin 16 of A13. For low density, adjust potentiometer R10 to obtain the time delay period listed in Table 1 for the applicable low-density/speed combination; for high density, adjust potentiometer R15 to obtain the time delay listed for the applicable high-density/speed combination.

TABLE 1 LCC GENERATE DELAY (FOUR CHARACTER PERIOD)

DENSITY	36 IPS	45 IPS	75 IPS	112.5 IPS	120 IPS	150 IPS
200 cpi	556 μsec	444 μsec	267 μsec	178 µsec	167 μsec	133 µsec
556 cpi	200 μsec	160 μsec	96 μsec	64 μsec	60 µsec	50 μsec
800 cpi	139 µsec	111 µsec	67 μsec	44 μsec	42 μsec	33 μsec

DRAWINGS.

The schematic diagram and assembly drawing of the PCB are located in Section VII. The logic diagram is located at the end of this special feature.

APPLICABLE PRINTED CIRCUIT BOARD DRAWINGS

CODE	DESCRIPTION	PART NO.	SCHEMATIC	ASSY DWG
LGB	LCC Generator -B		3116076	3116075
A Company of A Company	36/45 Ips	3116072-10		
	75 Ips	3116142-10		
	112.5/120/150 Ips	3116073-10		

LOGIC DIAGRAM

LCC Generate (Dual Density) 3115776

